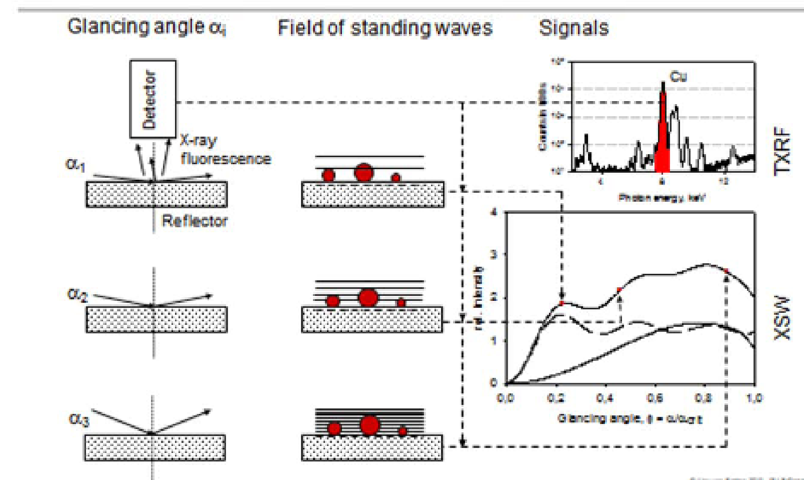
Literatur TXRF

Gesammelt von Dr. Alex von Bohlen und Maria Becker

zwischen 1985 und 2013.

Wir erheben keinen Anspruch auf Vollständigkeit.



Autoren	Titel	Zeitschrift	Vol	Seiten	Jahr	Keywords	Gruppe
Israilova, L.; Borovskii, I.B.	Theoretical studies on X-ray total reflection	in: (Eds) Shinoda, Gunji. Univ.Tokyo Press ; Proc.Int.Conf.X-ray		47-52	1971	TXRF; Calculations	Principles and Instrumentation
Yoneda, Y.; Horiuchi, T.	Optical Flats for Use in X-Ray Spectrochemical Microanalysis	Rev. Sci. Instrum.	42	1069-1070	1971	TXRF	Principles and Instrumentation
Aiginger, H.; Wobrauschek, P.	A Method for quantitative X-Ray Fluorescence Analysis in the Nanogram Region	Nucl. Instr. Methods	114	157-158	1974		Principles and Instrumentation
Wobrauschek, P.; Aiginger, H.	Total-Reflection X-Ray Fluorescence Spectrometric Determination of Elements in Nanogram Amounts	Anal. Chem.	47	852-855	1975		Principles and Instrumentation
Knoth, J.; Schwenke, H.; Marten, R.; Glauer, J.	Total-Reflection X-Ray Fluorescence Spectrometric Determination of Elements in Nanogram Amounts	J. Clin. Chem. Clin. Biochem.	15	557-560	1977		Chemical Analysis
Knoth, J.; Schwenke, H.	An X-Ray Fluorescence Spectrometer with totally Reflecting Sample Support for Trace Analysis at the ppb Level	Fresenius' Z. Anal. Chem.	291	200-204	1978		Principles and Instrumentation
Knoth, J.; Schwenke, H.	Trace Element Enrichment on a Quartz Glass Surface Used as a Sample Support of an X-Ray Spectrometer for the Subnanogram Range	Fresenius' Z. Anal. Chem.	294	273-274	1979		Chemical Analysis
Wobrauschek, P.; Aiginger, H	Totalreflexions-Röntgenfluoreszenzanalyse	X-Ray Spectrom.	8	57-62	1979		Principles and Instrumentation
Wobrauschek, B.; Aiginger, H.	X-Ray Total Reflection Fluorescence Analysis	in: Trace Element Analytical Chemistry in Medicine and Biology, Walter de		297-306	1980		Principles and Instrumentation
Knöchel, A.; Prange, A.	Analysis of Trace Elements in Sea water. Part II - Determination of Heavy Metal Traces in Seawater by X-Ray Fluorescence Analysis with Totally Reflecting Sample Holders	Mikrochim. Acta	(II)	395-408	1980		Chemical Analysis

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Schwenke, H.; Knoth, J.	High-Sensitivity Multielement Trace Analysis using EDXRF Spectrometry with multiple Total Reflection at the exciting Beam	in: Trace Element Analytical Chemistry in Medicine and Biology, Walter de		307-317	1980		Principles and Instrumentation
Wobrauschek, P.; Aiginger, H.	X-Ray Fluorescence Analysis in the ng Region using Total Reflection of the Primary Beam	Spectrochim. Acta Part B	35	607-614	1980		Principles and Instrumentation
Knoth, J.; Schwenke, H.	A New Totally Reflecting X-Ray Fluorescence Spectrometer with Detection Limits below 10-11 g	Fresenius' Z. Anal. Chem.	301	7-9	1980		Principles and Instrumentation
Knöchel, A.; Prange, A.	Analytik von Elementspuren in Meerwasser I - Tracerstudien zur Entwicklung von spurenanalytischen Verfahren für die Multielementbestimmung von Schwermtallen in	Fresenius' Z. Anal. Chem.	306	252-258	1981		Chemical Analysis
Bartels, B.; Freitag, K.; Rath, R.	Staubimmission Hamburgs untersucht durch Röntgenfluoreszenz mit totalreflektierendem Probenträger	Forum Städtehygiene	32	220-224	1981		Chemical Analysis
Ahlf, W.; Weber, A.	A simple Monitoring Technique to Determine the Heavy Metal Load of Algae in Aquatic Ecosystem	Environ. Techn. Lett.	2	317-322	1981		Chemical Analysis
Price, B.	Identification and the analysis of alloys with the combined x-ray fluorescence spectrometer (TXRF)	Spektrometertagung	13th	403-414	1981	alloy analysis; x-ray fluorescence; spectrometer	Chemical Analysis
Greim, L.	Schadstoffe im Wasser, Sediment und in Organismen (Muscheln) des Wattenmeeres	in: AGF (Hrsg.), Schadstoffe in Nahrungsketten	Bonn -Bad Godesberg	48-53	1982		Chemical Analysis
Schwenke, H.; Knoth, J.	A Highly Sensitive Energy-Dispersive X-Ray Spectrometer with Multiple Total Reflection of the Exciting Beam	Nucl. Instr. Methods	193	239-243	1982		Principles and Instrumentation
Junge, W.; Knoth, J.; Rath, R.	Chemische und optische Untersuchungen von komplexen Titan-Niob-Tantalaten (Betafiten)	N. Jb. Miner. 2Abh.	147	169-183	1983		Chemical Analysis

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Knöchel, A.; Petersen, W.;	Ergebnisse einer Ringanalyse von Elbwasser auf Schwermetalle	Fresenius' Z. Anal. Chem.	314	105-113	1983		Chemical Analysis
Batsford, S.; Rohrbach, R.; Knoth, J.; Vogt, A.; Kluthe, R.;	Diätetische Versuche bei einem definierten Immunmodell (New Zeeland black/white mouse): Der Einfluß erhöhter Zinkzufuhr	Akt. Ernähr.	8	250-252	1983		Chemical Analysis
Ketelsen, P.; Knöchel, A.	Multielementanalyse von Aerosolen mit Hilfe der Röntgenfluoreszenzanalyse mit totalreflektierendem Probenträger (TRFA)	Fresenius' Z. Anal. Chem.	317	333-342	1984	element detection; aerosol; x-ray fluorescence analysis; High-	Chemical Analysis
Schneider, B.; Weiler, K.	A Quick Grain Size Correction Procedure for Trace Metal Contents of Sediments	Env. Techn. Lett.	5	245-256	1984		Chemical Analysis
Pets, L.I.; Vaganov, P.A.; Knoth, J.; Haldna, Ü.L.; Schwenke, H.; Schnier, C.; Juga, R.G.	Microelements in Oil-Shale Ash of the Baltic Thermoelectric Power Plant	Oil Shale		379-390	1985		Chemical Analysis
Michaelis, W.; Knoth, J.; Prange, A.; Schwenke, H.	Trace Analytical Capabilities of Total-Reflection X-Ray Fluorescence Analysis	Adv. X-Ray Anal.	28	75-83	1985		Review
Ketelsen, P.; Knöchel, A.	Multielementanalyse von größenklassierten Luftstaubproben	Staub Reinhaltung der Luft	45	175-178	1985	airborne particulate; element composition; Hamburg	Chemical Analysis
Prange, A.; Knöchel, A.; Michaelis, W.	Multielement Determination of Dissolved Heavy Metal Traces in Sea Water by Total-Reflection X-Ray Fluorescence Spectrometry	Anal. Chim. Acta	172	79-100	1985		Chemical Analysis
Leyden, D.E.	Total reflection X-ray spectrometry	Trends in Analytical Chemistry	4	VIII	1985		Principles and Instrumentation
Freitag, K.	Energy Dispersive X-Ray Fluorescence Analysis with Multiple Total Reflection - An Improvement of Detection Limits	in: Sansoni, B. (Ed.) Instrumentelle Multielement-Analyse, VCH		257-268	1985		Principles and Instrumentation

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Michaelis, W.; Fanger, H.-U.; Niedergesäß, R.; Schwenke, H.	Intercomparison of the Multielement Analytical Methods TXRF, NAA and ICP with Regard to Trace Element Determinations in Environmental Samples	in: Sansoni, B. (Ed.) Instrumentelle MultielementAnalyse	VCH Verla gsge sellsc	693-710	1985		Chemical Analysis
Stößel, R.-P.; Prange, A.	Determination of Trace Elements in Rainwater by Total Reflection X-Ray Fluorescence	Anal. Chem.	57	2880-2885	1985	rainwater; trace element detection; x-ray fluorescence; freeze drying	Chemical Analysis
Hentschke, U.; Junge, W.; Rath, R.;	Chemical and Optical Properties of Columbites	N. Jb. Miner. Abh.	152	113-121	1985		Chemical Analysis
Michaelis, W.; Prange, A.; Knoth, J.	Recent Applications of Total Reflection X-Ray Fluorescence Analysis in Multielement Analysis	in: Sansoni, B. (Ed.) Instrumentelle Multielement-Analyse	VCH Verla gsge sellsc	269-289	1985		Chemical Analysis
Aiginger, H.; Wobrauschek, P.	Total Reflectance X-Ray Spectrometry	Adv. X-Ray Anal.	28	1-10	1985		Review
Prange, A.; Kremling, K.	Distribution of Dissolved Molybdenum, Uranium and Vanadium in Baltic Sea Waters	Mar. Chem.	16	259-274	1985	seawater; molybdenum; uranium; vanadium; dissolved;	Chemical Analysis
Michaelis, W.	Multielement Analysis of Environmental Samples by Total-Reflection X-Ray Fluorescence Spectrometry, Neutron Activation Analysis and Inductively Coupled Plasma Optical	Fresenius' Z. Anal. Chem.	324	662-671	1986		Chemical Analysis
Wobrauschek, P.; Aiginger, H.	Analytical application of total reflection and polarized X-rays	Fresenius' Z. Anal. Chem.	324	865-874	1986		Principles and Instrumentation
Michaelis, W.	Naß- und Trockendeposition von Schwermetallen	Technische Mitteilungen	79	266-271	1986		Chemical Analysis
Iida, A.; Sakurai, K.; Yoshinaga, A.; Gohshi, Y.	Grazing incidence X-ray fluorescence analysis	Nucl. Instr. Methods	A246	736-738	1986		Principles and Instrumentation

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Iida, A.; Yoshinaga, A.; Sakurai, K.; Gohshi, Y.	Synchrotron radiation excited X-ray fluorescence analysis using total reflection of X-rays	Anal. Chem.	58	394-397	1986		Principles and Instrumentation
Bilbrey, D.; Leland,D.; Leyden, D.; Wobrauschek, P.; Aiginger, H.	Determination of metals in oil using total reflection X-ray fluorescence spectrometry	X-Ray Spectrom.	16	161-165	1987		Chemical Analysis
Prange, A.; Knoth, J.; Stößel, R.-P.; Böddeker, H.; Kramer, K.	Determination of Trace Elements in the Water Cycle by Total-Reflection X-Ray Fluorescence Spectrometry	Anal. Chim. Acta	195	275-287	1987		Chemical Analysis
Gerwinski, W.; Goetz, D.; Koelling, S.; Kunze, J.	Multielement-Analyse von Müllverbrennungs-Schlacke mit der Totalreflexions-Röntgenfluoreszenz (TRFA)	Fresenius' Z. Anal. Chem.	327	293-296	1987	incineration ash; x-ray fluorescence; trace element detection; leachate	Chemical Analysis
Prange, A.	Totalreflexions-Röntgenfluoreszenzanalyse	GIT Fachz. Lab.	31	513-526	1987	total reflection x-ray analysis; fluorescence x-ray	Review
Leland, D.J.; Bilbrey, D.B.; Leyden, D.E.; Wobrauschek, P.; Aiginger, H.; Puxbaum, H.	Analysis of Aerosols Using Total Reflection X-ray Spectrometry	Anal. Chem.	59	1911-1914	1987	aerosol analysis; x-ray spectrometry; sulphur, chlorine, potassium, calcium	Chemical Analysis
Klockenkämper, R.	X-ray spectral analysis - new aspects	Fresenius' Z. Anal. Chem.	327	6-7	1987		Review
Eller, R.; Weber, G.	Bestimmung der durch Flavonoide komplexierten Metalle in Zwiebeln mit Totalreflexions-Röntgen-fluoreszenzanalyse (TRFA)	Fresenius' Z. Anal. Chem.	328	492-494	1987	Food; TXRF; Onions	Chemical Analysis
Gerwinski, W.; Goetz, D.	Multielement analysis of standard reference materials with total reflection X-ray Fluorescence (TXRF)	Fresenius' Z. Anal. Chem.	327	690-693	1987	standard analysis; total reflection x-ray fluorescence; soil	Chemical Analysis
von Bohlen, A.; Eller, R.; Klockenkämper, R.; Tölg, G.;	Microanalysis of Solid Samples by Total-Reflection X-ray Fluorescence Spectrometry	Anal. Chem.	59	2551-2555	1987	Solid samples; Microanalysis; TXRF	Chemical Analysis

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von Bohlen, A.; Klockenkämper, R.; Otto, H.; Tölg, G.; Wiecken, B.	Qualitative survey analysis of thin layers of tissue samples - Heavy metal traces in human lung tissue	Int. Arch. Occup. Environ. Health	59	403-411	1987	TXRF; Lung tissue; Metals	Chemical Analysis
Schmitt, M.; Hoffmann, P.; Lieser, K.-H.	Perspex as sample carrier in TXRF	Fresenius' Z. Anal. Chem.	328	594-595	1987	Perspex; sample carrier; x-ray analysis; total reflection x-ray	Principles and Instrumentation
Hegedüs, F.; Winkler, P.; Wobrauschek, P.; Streli, Christina	Low level iodine detection by TXRF in a reactor safety simulation experiment	Adv. X-Ray Anal.	30	85-88	1987	iodine detection; total reflectance XRF; reactor safety; simulation	Chemical Analysis
Iida, A.; Sakurai, K.; Gohshi, Y.	Near surface analysis of semiconductor using grazing incidence X-ray fluorescence	Adv. X-Ray Anal.	31	487-494	1988		Surfaces and Layers
Huber, A.; Rath, H.; Eichinger, P.; Bauer, T.; Kotz, L.; Staudigl, R.	Sub-ppb monitoring of transition metal contamination of silicon wafer surfaces by VPD-TXRF	Proc. Electrochem. Soc.	88-20	109-112	1988	transition metal detection silicon surface; total reflection x-ray	Surfaces and Layers
Hockett, R.S.; Baumann, S.M.; Schemmel, E.	An evaluation of ultra-surface (<3 nm), trace (E11/cm2) impurity analysis of silicon using a new X-ray technique	Proc. Electrochem. Soc.	88-20	113-130	1988		Surfaces and Layers
Yap, C.T.	X-ray Total Reflection Fluorescence Analysis of Iron, Copper, Zinc, and Bromine in Human Serum	Appl. Spectros.	42	1250-1253	1988		Chemical Analysis
Michaelis, W.; Prange, A.	Trace analysis of geological and environmental samples by total-reflection x-ray fluorescence spectrometry	Nucl. Geophys.	2	231-245	1988	total reflection x-ray fluorescence analysis; geological analysis; trace	Chemical Analysis
von Bohlen, A.; Klockenkämper, R.; Tölg, G.; Wiecken, B.	Microtome sections of biomaterials for trace analyses by TXRF	Fresenius' Z. Anal. Chem.	331	454-458	1988	TXRF; Tissue; Food; Microtome	Chemical Analysis
Burba, P.; Willmer, P.G.; Klockenkämper, R.	Elementspuren-Bestimmungen (AAS, ICP-OES, TRFA) in natürlichen Wässern nach Voranreicherung: ein Vergleich	Vom Wasser	71	179-194	1988	AAS; ICP-OES; TXRF; Water	Chemical Analysis

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Yap, C.T.; Ayala, R.E.; Wobrauschek, P.	Quantitative trace element determination in thin film samples by TXRF using the scattered radiation method	X-Ray Spectrom.	17	171-174	1988		Principles and Instrumentation
Prange, A.; Schwenke, H.	Sample treatment for TXRF - requirements and prospects	Adv. X-Ray Anal.	32	211-220	1989	sample preparation; reflection x-ray fluorescence	Chemical Analysis
Knoth, J.; Schwenke, H.; Weisbrod, U.	Total reflection X-ray fluorescence spectrometry for surface analysis	Spectrochim. Acta Part B	44	477-482	1989		Surfaces and Layers
Hockett, R. S.; Katz, W.	Comparison of wafer cleaning processes using total reflection x-ray fluorescence (TXRF)	J. Electrochem. Soc.	136	3481-3486	1989	reflection x-ray fluorescence; wafer cleaning; copper, iron, zinc, bromine,	Surfaces and Layers
Prange, A.; Böddeker, H.; Michaelis, W.	Multielement determination of trace elements in whole blood and blood serum by TXRF	Fresenius' Z. Anal. Chem.	335	914-918	1989	total reflection x-ray fluorescence; trace element detection; blood serum	Chemical Analysis
Hockett, R. S.	The correlation between quantitative surface metallic contamination and RTP-induced surface defects	Mater. Res. Soc. Symp. Proc.	146	377-383	1989	metallic contamination; correlation; surface defect; silicon wafer	Surfaces and Layers
Mueller, K. H.; Rupertus, V.; Oechsner, H.; Scheuer, V.; Tschudi, T.	Analysis of sputter deposited and evaporated tantalum oxide layers on silica by SNMS, XPS, TDS and TRFA	Fresenius' Z. Anal. Chem.	333	498-501	1989	tantalum oxide film analysis; silica substrate; secondary neutral mass	Surfaces and Layers
Yap, C. T.; Gunawardena, K. V. R.	TXRF - spectrometric analysis of major elements in mineral sands	Appl. Spectrosc.	43	702-704	1989	mineral; sand; major element detection; total reflection x-ray fluorescence; rutile	Chemical Analysis
Yap, C. T.; Gunawardena, K. V. R.	Analysis of trace elements in soft drinks using total reflection X-ray fluorescence spectrometry	Int. J. Environ. Stud.	32	297-302	1989	trace element detection; soft drink; carbonated beverage;	Chemical Analysis
Graule, T.; von Bohlen, A.; Broekaert, J.A.C.; Grallath, E.; Klockenkämper, R.; Tschöpel, P.; Tölg, G.	Atomic emission and atomic absorption spectrometric analysis of high-purity powders for the production of ceramics	Fresenius´ Z. Anal. Chem.	335	637-642	1989	high-purity; ceramic powders; AAS;	Chemical Analysis

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Saisho, H.	X-ray fluorescence analysis using synchrotron radiation	Trends Anal. Chem.	8	209-212	1989		Surfaces and Layers
Hockett, R.S.	Process development and control using total reflection X-ray fluorescence (TXRF) for surface analysis	Proc. SPIE-Int. Soc. Opt. Eng.	1186	10-21	1989		Surfaces and Layers
Hockett, R.S.	Analysis of trace impurities on wafers from cleaning	Proc. Electrochem. Soc.	90-9	227-242	1989		Surfaces and Layers
Nishihagi, K.; Kawabata, A.; Taniguchi, T.; Ikeda, S.	Impurity analysis on silicon wafer by monochromatic TRXRF	Proc. Electrochem. Soc.	90-9	243-250	1989		Surfaces and Layers
Nomura, S.; Nishihagi, K.; Taniguchi, K.	Impurity analysis of silicon wafers by total reflection X-ray fluorescence analysis	Adv. X-Ray Anal.	32	205-210	1989		Surfaces and Layers
Eichinger, P.; Rath, H.J.; Schwenke, H.	Application of total reflection X-ray fluorescence analysis for metallic trace impurities on silicon wafer surfaces	ASTM Spec.Tech.Publ.	990	305-313	1989		Surfaces and Layers
Burba, P.; Willmer, P.-G.; Becker, M.; Klockenkämper, R.	Determination of trace elements in high-purity aluminium by total reflection X-ray fluorescence after their separation on cellulose loaded with hexamethylenedithiocarba-mates	Spectrochim. Acta Part B	44	525-532	1989	TXRF; Al; Matrix separation; trace element preconcentration	Chemical Analysis
Haarich, M.; Knöchel, A.; Salow, H.	Einsatz der Totalreflexions-Röntgenfluoreszenzanalyse in der Analytik von nuklearen Wiederaufarbeitungsanlagen	Spectrochim. Acta Part B	44	543-549	1989	TXRF; Nuclear waste	Chemical Analysis
Niemann, A.; von Bohlen, A.; Klockenkämper, R.; Keck, E.	Quantifizierung der Biomineralisation - Gewebekultur und Mikroanalyse	in :H.-G.Willert, F.H.W.Heuck (Hrsg.) Neuere Ergebnisse in der	Springer-Verlag,	195-202	1989	Bone; Mineralization; TXRF	Chemical Analysis
Bethel, U.; Hamm, V.; Knöchel, A.	Untersuchungen zur Bestimmung von Spurenelementen in Blutserum mit Hilfe der Totalreflexions - Röntgenfluoreszezanalyse	Fresenius' Z. Anal. Chem.	335	855-859	1989	Blood; TXRF	Chemical Analysis

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Schneider, B.	The determination of atmospheric trace metal concentrations by collection of aerosol particles on sample holders for total-reflection X-ray fluorescence	Spectrochim. Acta Part B	44	519-524	1989	Impactor; Airborne particulate matter; TXRF	Chemical Analysis
Freimann, P.; Schmidt, D.	Application of total reflection X-ray fluorescence analysis for the determination of trace metals in the North Sea	Spectrochim. Acta Part B	44	505-511	1989	Water; Sea; TXRF	Chemical Analysis
Niomiya, T.; Nomura, S.; Taniguchi, K.; Ikeda, S.	Quantitative analysis of arsenic element in a trace of water using total reflection X-ray fluorescence spectrometry	Adv. X-Ray Anal.	32	197-204	1989	As; Water; TXRF	Chemical Analysis
Hockett, R. S.; Katz, W.	Comparison of water cleaning processes using total reflection X-ray fluorescence (TXRF)	J. Electrochem. Soc.	136	3481-3486	1989		Surfaces and Layers
Reus, U.	Total reflection X-ray fluorescence spectrometry: matrix removal procedures for trace analysis of high-purity silicon, quartz and sulphuric acid	Spectrochim. Acta Part B	44	533-542	1989	total reflection x-ray fluorescence analysis; silicon analysis; quartz;	Chemical Analysis
Hoffmann, P.; Lieser, K.H.; Hein, M.; Flakowski, M.	Analysis of thin layers by total-reflection X-ray fluorescence spectrometry	Spectrochim. Acta Part B	44	471-476	1989		Surfaces and Layers
Penka, V.; Hub, W.	Application of total reflection X-ray fluorescence in semiconductor surface analysis	Spectrochim. Acta Part B	44	483-490	1989	silicon; surface analysis; x-ray fluorescence; semiconductor	Surfaces and Layers
Eller, R.; Alt, F.; Tölg, G.; Tobschall, H.J.	An efficient combined procedure for the extreme trace determination of gold, platinum, palladium and rhodium with the aid of graphite furnace atomic absorption spectrometry and total-	Fresenius' Z. Anal. Chem.	334	723-739	1989	TXRF; Nobel metals; Ores	Chemical Analysis
Kolbesen, B. O.; Palmer, W.	Surface and thin film analysis in silicon technology: actual and future problems and demands	Fresenius' Z. Anal. Chem.	333	561-568	1989		Chemical Analysis
Berneike, W.; Knoth, J.; Schwenke, H.; Weisbrod, U.	Surface analysis for Si-Wafers using total reflection X-ray fluorescence analysis	Fresenius' Z. Anal. Chem.	333	524-526	1989		Surfaces and Layers

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Penka, V.; Hub, W.	Detection of metallic trace impurities on Si (100) surfaces with total reflection X-ray fluorescence (TXRF)	Fresenius' Z. Anal. Chem.	333	586-589	1989	silicon surface analysis; transition metal trace detection; total	Surfaces and Layers
Klockenkämper, R.; von Bohlen, A.; Wiecken, B.	Quantification in total reflection X-ray fluorescence analysis of microtome sections	Spectrochim. Acta Part B	44	511-518	1989	Lung tissue; TXRF; Quantification	Chemical Analysis
Hegedüs, F.; Winkler, P.	Low level iodine detection by TXRF spectrometry	Adv. X-Ray Anal.	32	251-253	1989	iodine detection; gas analysis; reflection x-ray; water analysis	Chemical Analysis
Reus, U.; Freitag, K.; Haase, A.; Alexandre, J.F.	Total-reflection X-ray fluorescence spectrometry. Application methods	Spectra 2000 [Deux Mille]	143	42-46	1989		Review
Klockenkämper, R.; von Bohlen, A.	Determination of the critical thickness and the sensitivity of thin-film analysis by total reflection X-ray fluorescence spectrometry	Spectrochim. Acta Part B	44	461-470	1989		Principles and Instrumentation
Wobrauschek, P.; Kregsamer, P.	Total reflection X-ray fluorescence analysis with polarized X-rays, a compact attachment unit, and high energy X-rays	Spectrochim. Acta Part B	44	453-460	1989	total reflection x-ray fluorescence analysis; polarized x-ray	Principles and Instrumentation
Streli, C.; Aiginger, H.; Wobrauschek, P.	Total reflection X-ray fluorescence analysis of low-Z elements	Spectrochim. Acta Part B	44	491-498	1989		Principles and Instrumentation
Tada, Y.; Sako, Y.; Iwamoto, K.; Gonsui, S.; Arai, T.	Instrumentation and application for total-reflection X-ray fluorescence spectrometry	Adv. X-Ray Anal.	32	131-139	1989		Review
Prange, A.	Total reflection X-ray spectrometry: method and applications	Spectrochim. Acta Part B	44	437-452	1989	total reflection x-ray analysis; trace element detection; environmental	Review
Freitag, K.; Reus, U.; Fleischhauer, J.	Extension of the analytical range of total reflection X-ray fluorescence spectrometry to lighter elements (11 < Z < 16) and increase in sensitivity by excitation with tungsten La radiation	Spectrochim. Acta Part B	44	499-504	1989		Principles and Instrumentation

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Schwenke, H.; Berneike, W.; Knoth, J.; Weisbrod, U.	How to use the features of total reflection of X-rays for energy dispersive XRF	Adv. X-Ray Anal.	32	105-114	1989		Surfaces and Layers
Klockenkämper, R.	Totalreflexions-Röntgenfluoreszenz - Prinzip und Anwendungen	GIT Fachz. Lab.	33	441-447	1989		Review
Hockett, R.S.; Knowles, J.	Characterization of heavy metal contamination in diamond films using SIMS, TXRF and RBS	Mater. Res. Soc. Symp. Proc.	162	261-266	1990	diamond film analysis; heavy trace metal detection; secondary ion mass	Chemical Analysis
Niemann, A.; von Bohlen, A.; Klockenkämper, R.; Keck, E.	Quantification of biomineralisation : An in-vitro tissue culture system and microanalysis of calcium, phosphorus and trace elements by total reflection X-ray fluorescence	Biochem. Biophys. Res. Commun.	170	1216-1222	1990	TXRF; Bone; Mineralization	Chemical Analysis
Stanglmeier, F.	Bestimmung der dispersiven Korrektur f'(E) zum Atomformfaktor aus der Totalreflexion von Röntgenstrahlen	Forschungszentrum Jülich : Bericht, ISBN 0366-0885	Nr. 2346		1990		Principles and Instrumentation
Chen, J.S.; Berndt, H.; Klockenkämper, R.; Tölg, G.	Trace analysis of high-purity iron by total reflection X-ray fluorescence spectrometry	Fresenius' J. Anal. Chem.	338	891-894	1990	TXRF; Fe; Matrix separation	Chemical Analysis
Günther, K.; von Bohlen, A.	Simultaneous multielement determination in vegetable foodstuffs and their respective cell fractions by total-reflection X-ray fluorescence (TXRF)	Z Lebensm Unters Forsch A	190	331-335	1990	TXRF; Food; Vegetables	Chemical Analysis
Eichinger, P.	Total reflection X-ray fluorescence analysis (TXRF) for contamination monitoring	Proc. Electrochem. Soc.	90-11	227-237	1990	x-ray fluorescence; reflection; contamination; monitoring; silicon	Surfaces and Layers
Hoffmann, P.; Hein, M.; Scheuer, V.; Lieser, K.H.	Application of total-reflection X-ray fluorescence spectrometry in material analysis	Mikrochim. Acta	2	305-313	1990		Chemical Analysis
Hockett, R.S.; Wilson, R.G.	Quantitative measurement of surface, trace metal contamination on SOI using total reflection X-ray fluorescence (TXRF)	Proc. Electrochem. Soc.	90-6	154-160	1990		Surfaces and Layers

Autoren	Titel	Zeitschrift	Vol	Seiten	Jahr	Keywords	Gruppe
Hockett, R.S.; Norberg, J.C.	The practical use of polyencapsulation/SIMS for quantitative surface analysis of silicon substrates	Second. Ion Mass Spectrom.	Ed. A. Benningho		1990		Surfaces and Layers
Hockett, R.S.	Control of semiconductor surface, trace metal contamination by total reflection X-ray fluorescence (TXRF)	in: Sumino, Koji (Ed); Amsterdam; Detect Control Semiconduct.	2	1547-1552	1990		Surfaces and Layers
Hegedüs, F.; Winkler, P.; Wobrauschek, P.; Streli, C.	TXRF Spectrometer for trace element detection	Adv. X-Ray Anal.	33	581-583	1990		Chemical Analysis
Kim, Yun Ok; Kim, Yung Sang	TXRF (total-reflection x-ray fluorescence): Its principles and analytical performances	Anal. Sci. Technol.	3	131-139	1990	total reflection x-ray fluorescence; x-ray fluorescence spectrochemical	Review
Hockett, R. S.	Relative surface stoichiometry of high-Tc materials by total reflection x-ray fluorescence	Proc. SPIE-Int. Soc. Opt. Eng.	1287	54-65	1990	total reflection x-ray fluorescence analysis; superconductor	Surfaces and Layers
Klockenkämper, R.	Total-Reflection X-ray Fluorescence Spectrometry : Principles and Applications	Spectroscopy International	2	26-37	1990		Review
Knöchel, A.	TXRF, PIXE, SYXRF; principles, critical comparison and applications	Fresenius' J. Anal. Chem.	337	614-621	1990	x-ray fluorescence analysis; particle induced x-ray emission;	Review
Hockett. R. S.; Wilson, R. G.	Quantitative measurement of surface, trace metal contamination on SOI using total reflection x-ray fluorescence (TXRF)	Proc. - Electrochem. Soc.	90-6	154-60	1990	semiconductor; surface analysis; heavy metal; TXRF; trace metal;	Surfaces and Layers
Hockett, R. S.	Process development and control using total reflection x-ray fluorescence (TXRF) for surface analysis	Proc. SPIE-Int. Soc. Opt. Eng.	1186	10-21	1990	surface analysis; reflection x-ray fluorescence	Surfaces and Layers
Klockenkämper, R.	Total-reflection x-ray fluorescence spectrometry: principles and applications	Spectroscopy	5(6)	26-32	1990	TXRF	Review

Autoren	Titel	Zeitschrift	Vol	Seiten	Jahr	Keywords	Gruppe
Hockett, R. S.	Analysis of trace impurities on wafers from cleaning	Proc. - Electrochem. Soc.	90-9	227-242	1990	trace impurity detection; cleaned wafer; SIMS; mass spectra; x-ray;	Surfaces and Layers
Hockett, R.S.	Quantitative analysis for surface trace metal contamination on substrates and films by TXRF	NIST Spec. Publ.	801	239-253	1990		Surfaces and Layers
Hockett, R. S.; Herman, M. H.; Mu, X. C.; Ma, Li Jia	Investigations of residual chlorine on etched aluminum-copper metal lines by total reflection x-ray fluorescence (TXRF)	Mater. Res. Soc. Symp. Proc.	225	329-333	1991	aluminum; copper; interconnect; residual chlorine	Surfaces and Layers
Reus, U.	Determination of trace elements in oils and greases with total reflection X-ray fluorescence: sample preparation methods	Spectrochim. Acta Part B	46	1403-1411	1991	TXRF; Oils; Greases	Chemical Analysis
Muia, L.M.; Razafindramisa, F.L.; Van Grieken, R.E.	Total reflection X-ray fluorescence analysis using an extended focus tube for the determination of dissolved elements in rain water	Spectrochim. Acta Part B	46	1421-1427	1991	TXRF; Water; Rain	Chemical Analysis
Dixkens, J.; Fissan, H.	Electrostatic particle sampler for total reflection X-ray fluorescence analysis	J. Aerosol. Sci.	22	S375-S378	1991	TXRF; Airborne particulate matter	Chemical Analysis
Günther, K.; von Bohlen, A.	Multielement speciation in vegetable foodstuffs by gel permeation chromatography (GPC) and total-reflection X-ray fluorescence (TXRF)	Spectrochim. Acta Part B	46	1413-1419	1991	TXRF; GPC; Food; Vegetables; Species	Chemical Analysis
Hashimoto, H.; Iida, Y.; Saisho, H.; Nishioji, H.	Quantitative analysis of liquid samples using total reflection X-ray fluorescence	Anal. Sci.	7	5770-5780	1991	-	Chemical Analysis
Iwamoto, K.; Kojima, S.; Sako, Y.; Utaka, T.; Arai, T.	Instrumentation and applications of total reflection fluorescence spectroscopy	Anal. Sci.	7	499-502	1991	-	Chemical Analysis
Bubert, H.; Burba, P.; Klockenkämper, R.; Schönborn, A.; Wielunski, M.	Dose determination of nickel implantations in silicon wafers	Fresenius' J. Anal. Chem.	341	245-247	1991	TXRF; Implantation; Dose	Chemical Analysis

Autoren	Titel	Zeitschrift	Vol	Seiten	Jahr	Keywords	Gruppe
Koopmann, C.; Prange, A.	Multielement determination in sediments from the German Wadden Sea - investigations on sample preparation techniques	Spectrochim. Acta Part B	46	1395-1402	1991	TXRF; Sediments; Wadden Sea	Chemical Analysis
Hegedüs, F.; Winkler, P.	Niobium concentration measurement in steel samples with TXRF	Adv. X-Ray Anal.	34	239-241	1991	niobium detection; steel; TXRF	Chemical Analysis
de Boer, D.K.G.	Glancing incidence X-ray fluorescence of layered materials	Phys. Rev. B	44	498-511	1991	-	Surfaces and Layers
de Boer, D.K.G.; Van den Hoogenhof, W.W.	Total-reflection x-ray fluorescence of thin layers on and in solids	Adv. X-Ray Anal.	34	35-40	1991	interference fringe; TXRF; depth profiling; thin layer analysis; angle	Surfaces and Layers
Wobrauschek, P.; Kregsamer, P.; Streli, C.; Aiginger, H.	Recent developments and results in total reflection x-ray fluorescence analysis	Adv. X-Ray Anal.	34	1-12	1991	total reflection x-ray fluorescence;	Review
Muia, L.; Van Grieken, R.	Determination of rare earth elements in geological materials by total reflection x-ray fluorescence	Anal. Chim. Acta	251	177-181	1991	total reflection x-ray fluorescence; geological material; rare earth; rock	Chemical Analysis
Hashiguchi, Yoshihiro; Hayashi, Shunichi	Analysis of surface cleanliness on silicon wafers using total reflection XRF excited by synchrotron radiation	Tetsu to Hagane	77	2007-2013	1991	silicon surface analysis; synchrotron x-ray source; TXRF;	Surfaces and Layers
Zhukovskii D.A.; Prokofiev, M.A.	Use of total reflection X-ray fluorescence analysis to study atmospheric aerosols	Tr. Gl. Geofiz. Obs. Im. A.I. Voeikova	534	124-136	1991		Review
Streli, C.; Wobrauschek, P.; Aiginger, H.	A new X-ray tube for efficient excitation of low-Z-elements with total reflection X-ray fluorescence analysis	Spectrochim. Acta Part B	46	1351-1359	1991	windowless x-ray tube; total reflection x-ray fluorescence; detection limit; low Z	Principles and Instrumentation
Noburo, Y.	Surface analysis of wafers by total reflection energy dispersion X-ray analysis	Denshi Zairyo	30	32-36	1991		Review

Autoren	Titel	Zeitschrift	Vol	Seiten	Jahr	Keywords	Gruppe
Hockett, R.S.	Surface analysis of trace metals on gallium arsenide by total reflection X-ray fluorescence	Proc. Electrochem. Soc.	91-1	183-190	1991	surface contamination; heavy metal; silicon; reflection x-ray	Surfaces and Layers
Aiginger, H.	Historical development and principles of total reflection X-ray fluorescence analysis (TXRF)	Spectrochim. Acta Part B	46	1313-1321	1991	total reflection x-ray fluorescence	Review
Klockenkämper, R.	Totalreflexions-Röntgenfluoreszenzanalyse	in: Günzler, H. et al. (Hrsg.) Analytiker Taschenbuch Bd.10 (1991)	Bd.10	111-152	1991	-	Review
Nishihagi, K.; Yamashita, N.; Fujino, N.; Taniguchi, K.; Ikeda, S.	Impurity analysis on silicon wafer using Monochro-TREX	Adv. X-Ray Anal.	34	81-89	1991	-	Surfaces and Layers
Schwenke, H.; Knoth, J.; Weisbrod, U.	Current Work on Total Reflection X-Ray Fluorescence Spectrometry at the GKSS Research Centre	X-Ray Spectrom.	20	277-281	1991	surface analysis; reflection x-ray fluorescence; trace analysis	Surfaces and Layers
Hockett, R.S.	TXRF for surface contamination defect control	Proc. Electrochem. Soc.	91-9	57-64	1991	surface contamination; heavy metal; silicon; reflection x-ray	Surfaces and Layers
Neumann, C.; Eichinger, P.	Ultra-trace analysis of metallic contaminations on silicon-wafer surfaces by vapour phase decomposition/total reflection X-ray fluorescence analysis	Spectrochim. Acta Part B	46	1369-1377	1991	metal detection; silicon surface; VPD; TXRF; vapor phase decomposition;	Surfaces and Layers
de Boer, D.K.G.; van den Hoogenhof, W.W.	Total reflection X-ray fluorescence of single and multiple thin-layer samples	Spectrochim. Acta Part B	46	1323-1331	1991	single; multiple layer; film analysis; angular dependence; TXRF;	Surfaces and Layers
Schuster, M.	Grazing incidence X-ray fluorescence analysis with monochromatic radiation	Adv. X-Ray Anal.	34	71-80	1991	grazing incidence; monochromatic radiation; x-ray fluorescence	Principles and Instrumentation
Ayala, R.E.; Alvarez, E.M.; Wobrauschek, P.	Direct determination of lead in whole human blood by total reflection X-ray fluorescence spectrometry	Spectrochim. Acta Part B	46	1429-1432	1991	TXRF; Water; Soil	Chemical Analysis

Autoren	Titel	Zeitschrift	Vol	Seiten	Jahr	Keywords	Gruppe
Kregsamer, P.; Wobrauschek, P.	Total reflection X-ray fluorescence analysis of the rare earth elements by K-shell excitation	Spectrochim. Acta Part B	46	1361-1367	1991	collimator; reflector; rare earth detection; TXRF; K- excitation	Principles and Instrumentation
Dixkens, J.; Fissan, H.	Electrostatic particle sampler for total-reflection x-ray fluorescence analysis	J. Aerosol Sci.	22(Suppl. 1)	S375-S378	1991	electrostatic; particle sampler design; x-ray fluorescence	Principles and Instrumentation
Niemann, A.; von Bohlen, A.; Klockenkämper, R.; Clahsen, H.; Keck, E.	Hemmung der Zink-Aufnahme durch Ethylen-1-hydroxy-1,1-diphosphonat (EHDP) während der Biomineralisation in vitro	in: Werner , Matthiaß (Hrsg) Osteologie - Interdiszipliär.	Springer Verlag	300-304	1991	TXRF; tissue	Chemical Analysis
Prange, A.; Kramer, K.; Reus, U.	Determination of trace element impurities in ultrapure reagents by total reflection X-ray spectrometry	Spectrochim. Acta Part B	46	1385-1393	1991	TXRF; Ultrapure; Reagents; Acids	Chemical Analysis
Klockenkämper, R.; Becker, M.; Bubert, H.	Determination of the heavy-metal ion-dose after implantation in silicon-wafers by total-reflection X-ray fluorescence analysis	Spectrochim. Acta Part B	46	1379-1383	1991	TXRF; Wafer; Implantation; Dose	Chemical Analysis
Mukhtar, S.; Haswell, S.J.	Suitability of total reflection X-ray fluorescence spectrometry for elemental speciation studies	J. Anal. At. Spectrom.	6	339-341	1991	oxidation state detection; elemental speciation; total reflection XRF;	Chemical Analysis
de Boer, D.K.G.	X-ray standing waves and the critical sample thickness for total-reflection X-ray fluorescence analysis	Spectrochim. Acta Part B	46	1433-1436	1991	x-ray standing wave; TXRF analysis; critical sample; thickness	Principles and Instrumentation
Matsushita, Y.	Total reflection X-ray fluorescence analysis (TRXRF)	Oyo Butsuri	60	1141-1142	1991		Review
Schwenke, H.; Knoth, J.; Weisbrod, U.	Analysis of particles on surfaces by total reflection x-ray fluorescence spectrometry	Part. Surf.	3	131-141	1991	surface particle analysis; total reflection XRF; ray fluorescence surface	Surfaces and Layers
Weisbrod, U.; Gutschke, R.; Knoth, J.; Schwenke, H.	X-ray induced fluorescence at grazing incidence for quantitative surface analysis	Fresenius' J. Anal. Chem.	341	83-86	1991	grazing incidence; total reflection XRF analysis; surface analysis; layer	Surfaces and Layers

Autoren	Titel	Zeitschrift	Vol	Seiten	Jahr	Keywords	Gruppe
Wobrauschek, P.; Kregsamer, P.; Streli, C.; Aiginger, H.	Instrumental developments in total reflection X-ray fluorescence analysis for K-lines from oxygen to the rare earth elements	X-Ray Spectrom.	20	23-28	1991	total reflection x-ray fluorescence; instrumentation	Principles and Instrumentation
Kregsamer, P.	Fundamentals of total reflection X-ray fluorescence	Spectrochim. Acta Part B	46	1333-1340	1991	quartz reflector; total reflection XRF; molybdenum K excitation radiation	Principles and Instrumentation
Schuster, M.	A total reflection X-ray fluorescence spectrometer with monochromatic excitation	Spectrochim. Acta Part B	46	1341-1349	1991	excitation; semiconductor; wafer analysis; trace element detection;	Principles and Instrumentation
Weisbrod, U.; Gutschke, R.; Knoth, J.; Schwenke, H.	Total reflection X-ray fluorescence spectrometry for quantitative surface and layer analysis	Appl. Phys. A	53	449-456	1991	total reflection XRF; surface layer analysis; surface analysis	Surfaces and Layers
Mukhtar, S.; Haswell, S.J.; Ellis, A.T.; Hawke, D.T.	Application of total-reflection X-ray fluorescence spectrometry to elemental determinations in water, soil and sewage sludge samples	Analyst (London)	116	333-338	1991	soil; sewage; sludge; water analysis; total reflection x-ray fluorescence	Chemical Analysis
Hockett, R. S.	TXRF - measurement of substrate backside contamination	Proc. - Electrochem. Soc.	92-12	350-357	1992	TXRF; analysis; backside contamination	Review
Kudo, M.	Detection of microconstituents on the surface of solids	Shinsozai	3	24-29	1992		Review
Schwenke, H.; Gutschke, R.; Knoth, J.	Characterization of near surface layer by means of total reflection X-ray fluorescence spectrometry	Adv. X-Ray Anal.	35	941-946	1992	near surface layer; total reflection XRF	Surfaces and Layers
Hein, M.; Hoffmann, P.; Lieser, K. H.; Ortner, H. M.	Application of x-ray fluorescence analysis with total-reflection (TXRF) in material science	Fresenius' J. Anal. Chem.	343	760-764	1992	low atomic number element detection; TXRF	Chemical Analysis
Shibaya, H.; Kondo, H.; Tomizawa, K.	Surface contamination level of gallium arsenide wafers treated with solutions of organic base measured by total reflection x-ray fluorescence (TXRF)	Mater. Res. Soc. Symp. Proc.	259	329-334	1992	gallium arsenide; surface contamination detection; TXRF;	Surfaces and Layers

Autoren	Titel	Zeitschrift	Vol	Seiten	Jahr	Keywords	Gruppe
Wobrauschek, P.; Streli, C.; Görgl, R.; Ladisich, W.	Total reflection x ray fluorescence analysis and its versatile applicability to environmental samples	Appl. Isot. Radiat. Conserv. Environ., Proc. Int. Symp.		397-410	1992	total reflection XRF environmental analysis; x-ray fluorescence; water	Chemical Analysis
Hockett, R. S.; Hymes, Diane	TXRF - characterization of trace metal contamination in thin gate oxides	Mater. Res. Soc. Symp. Proc.	259	173-178	1992	metal contamination; gate oxide semiconductor; silicon	Surfaces and Layers
Dogan, M.	Determination of mineral spring water trace elements content in central Turkey by TXRF spectrometry	Kim. Kim. Muhendisligi Semp.,	8th, Volume 1	265-270	1992	trace element detection; spring water; total reflection x-ray fluorescence	Chemical Analysis
Streli, C.; Wobrauschek, P.; Aiginger, H.	Light element analysis with TXRF	Adv. X-Ray Anal.	35B	947-952	1992	light element detection; total reflection XRF	Principles and Instrumentation
Hegedüs, F.; Winkler, P.	Uranium concentration measurement in water samples with XRF	Adv. X-Ray Anal.	35B	965-967	1992	uranium detection; x-ray fluorescence; water; total reflection x-ray fluorescence	Chemical Analysis
Hegedüs, F.	Total reflection x-ray fluorescence (TXRF) spectrometer for measurement of ultratrace elements	Chimia	46	477-479	1992	total reflection x-ray fluorescence spectrometer; ultratrace element	Chemical Analysis
Hegedüs, F.; Szaloki, I.	On the track of trace elements. Supersensitive x-ray spectrometer	Termeszet Vilaga	123	318-320	1992	total reflection x-ray fluorescence analysis; spectrometer; trace	Review
Hockett, R. S.; Mu, X. C.; Ma, Li Jia	TXRF evaluation of residual chlorine on etched aluminum-copper metal lines	Proc. - Electrochem. Soc.	92-12	358-365	1992	chlorine RIE; copper; aluminum line; sputter etching; analysis	Surfaces and Layers
Streckfuss, N.; Frey, L.; Zielonka, G.; Kroninger, F.; Ryzlewicz, C.; Ryssel, H.	Analysis for trace metals on silicon surfaces	Fresenius' J. Anal. Chem.	343	765-768	1992	trace metal detection; silicon surface analysis; vapor phase	Surfaces and Layers
Kudo, Masahiro	Detection of microconstituents on the surface of solids	Shinsozai	3(6)	24-29	1992	semiconductor surface analysis; spectrochemical method	Review

Autoren	Titel	Zeitschrift	Vol	Seiten	Jahr	Keywords	Gruppe
Hockett, R. S.	TXRF - detection of subsurface metals in silicon substrates	Proc. - Electrochem. Soc.	92-2	132-139	1992	total reflection x-ray fluorescence; metal detection; subsurface; silicon	Surfaces and Layers
Anttila, O. J.; Tilli, M. V.	Metal contamination removal on silicon wafers using dilute acidic solutions	J. Electrochem. Soc.	139	1751-1756	1992	acid wash; decontamination; silicon; metal	Surfaces and Layers
Yakushiji, K.; Ohakawa, S.; Yoshinaga, A.; Harada, J.	Main peak profiles of total reflection X-ray fluorescence analysis of silicon(001) wafers excited by monochromatic X-Ray beam WLß1	Jpn. J. Appl. Phys., Part 1	31	2872-2876	1992	silicon wafer analysis; TXRF; crystal orientation	Surfaces and Layers
Hockett, R. S.; Ikeda, S.; Taniguchi, T.	TXRF round robin results	Proc. - Electrochem. Soc.	92-12	324-337	1992	review total reflection x-ray fluorescence	Review
Frey, L.; Kroninger, F.; Streckfuss, N.; Ryssel, H.; Margail, J.	Characterization of metal impurities in silicon-on-insulator material	Mater. Sci. Eng. B,	12	195-198	1992	silicon on insulator; metal impurity detection; total reflection XRF;	Surfaces and Layers
Günther, K.; von Bohlen, A.; Paprott, G.; Klockenkämper, R.	Multielement analysis of biological reference materials by total-reflection x-ray fluorescence and inductively coupled plasma mass spectrometry in the semiquant mode	Fresenius' J. Anal. Chem.	342	444-448	1992	biol element detection; total reflection x-ray fluorescence	Chemical Analysis
Hein, M.; Hoffmann, P.; Lieser, K. H.; Ortner, H. M.	Measurement of low-Z elements by TXRF	Fresenius' J. Anal. Chem.	342	191	1992	low Z element detection; TXRF; solid; sodium hydrogen carbonate	Chemical Analysis
Utaka, T.; Arai, T.	Instrumentation for total reflection X-ray spectrometry	Adv. X-Ray Anal.	35	933-940	1992	-	Review
Yakushiji, Kenji; Ohkawa, Shinji; Yoshinaga, Atsushi; Harada, Jimpei	Main peak profiles of total reflection x-ray fluorescence analysis of silicon(001) wafers excited by monochromatic x-ray beam W-L beta. (I)	Jpn. J. Appl. Phys., Part 1	31(9 A)	2872-2876	1992	silicon wafer analysis; TXRF; crystal orientation	Principles and Instrumentation
Taniguchi, K.; Nishihagi, K.	Total reflection X-ray fluorescence	Kagaku Kogyo	43	149-154	1992		Review

Autoren	Titel	Zeitschrift	Vol	Seiten	Jahr	Keywords	Gruppe
Klockenkämper, R.; Knoth, J.; Prange, A.; Schwenke, H.	Total reflection X-ray fluorescence	Anal. Chem.	64	1115A-1123A	1992	-	Principles and Instrumentation
Nomura, S.; Ninomiya, T.; Taniguchi, K.; Ikeda, S.	Application of total reflection X-ray fluorescence spectrometry of drug analysis	Adv. X-Ray Anal.	35	969-974	1992	-	Chemical Analysis
Hegedüs, F.; Winkler, P.	Uranium concentration measurement in water samples with TXRF	Adv. X-Ray Anal.	35	965-967	1992	uranium detection; water; total reflection x-ray fluorescence	Chemical Analysis
Egorov, A.; Kabina, L.; Kondurov, I.; Korotkikh, E.; Martynov, V.; Shchebetov, A.; Sushkov, P.	Determination of heavy metals in environmental water by total reflection X-ray fluorescence method using optimized Röntgen optics cut-off filter	Adv. X-Ray Anal.	35	959-963	1992	-	Chemical Analysis
Michaelis, W.; Pepelnik, R.; Prange, A.	Application of TXRF in environmental research	Adv. X-Ray Anal.	35	953-958	1992	environmental pollution elemental analysis; total reflection x-ray	Review
Hein, M.; Hoffmann, P.; Lieser, K.H.; Ortner, H.M.	Application of X-ray fluorescence analysis with total-reflection (TXRF) in material science	Fresenius' J. Anal. Chem.	343	760-764	1992	low atomic number element detection; TXRF	Chemical Analysis
Kojima, S.	Analysis of surface contamination in subhalfmicron range. Microanalysis of impurities by TRXRF	Kurin Tekunoroji	2	20-25	1992		Review
Sansoni, B.	Nuclear and nuclear related analytical techniques: an overview and their current applicability in environmental research and monitoring	Appl. Isot. Radiat. Conserv. Environ.	Proc. Int.Symp.	17-41	1992		Review
Klockenkämper, R.; von Bohlen, A.	Total reflection X-ray fluorescence - An efficient method for micro-, trace- and surface-layer-analysis	J. Anal. At. Spectrom.	7	273-279	1992	total reflection x-ray fluorescence; trace analysis; surface analysis; water;	Review
Prange, A.; Schwenke, H.	Trace element analysis using total-reflection X-ray fluorescence spectrometry	Adv. X-Ray Anal.	35	899-923	1992	total x-ray fluorescence; trace element detection; TXRF	Review

Autoren	Titel	Zeitschrift	Vol	Seiten	Jahr	Keywords	Gruppe
NN c/o Rigaku	Instrumentation and application of total reflection fluorescence X-ray spectrometry	The Rigaku Journal	9	29-36	1992	-	Surfaces and Layers
Kondo, H.; Rylta, J.; Morita, E.; Yoshimi, T.; Shimanuki, Y.	Quantitative analysis of surface contaminations on silicon wafers by total reflection X-ray fluorescence	Jpn. J. Appl. Phys., Part 2	31	L11-L13	1992	-	Surfaces and Layers
Kawai, J.; Takami, M.; Fujinami, M.; Hashiguchi, Y.; Hayakawa, S.; Gohshi, Y.	A numerical simulation of total reflection X-ray photoelectron spectroscopy (TRXPS)	Spectrochim. Acta Part B	47	983-991	1992	-	Principles and Instrumentation
Streckfuss, N.; Frey, L.; Kroninger, F.; Ryzlewicz, C.; Ryssel, H.	Analysis for trace metals on silicon surfaces	Fresenius' J. Anal. Chem.	343	765-768	1992	trace metal detection; vapor phase decomposition;	Surfaces and Layers
Kubota, A.; Tsuchiya, N.; Norihiko, S.; Matsushita, Y.; Kageyama, M.	System for analyzing metal impurity on the surface of a single-crystal semiconductor using total reflection of X-ray fluorescence	Eur. Pat. Appl.		15pp	1992	-	Surfaces and Layers
Hoffmann, P.; Jährling, R.; Minh Tu, N.T.; Bowitz, R.; Kübler, A.; Hein, M.; Stingl, U.; Lieser, K.H.	Examination of steel samples, provided as reference materials, by instrumental analyses	Fresenius' J. Anal. Chem.	342	312- 317	1992		Chemical Analysis
Wobrauschek, P.; Kregsamer, P.; Streli, C.; Rieder, R.; Aiginger, H.	TXRF with various excitation sources	Adv. X-Ray Anal.	35	925-931	1992	-	Review
Usui, T.	Handy and convenient X-ray chemical analysis method for superconducting thin films	ISTEC J.	5	13-15	1992	-	Review
Schwenke, H.; Gutschke, R.; Knoth, J.; Kock, M.	Treatment of Roughness and Concentration Gradients in Total Reflection X-Ray Fluorescence Analysis of Surfaces	Appl. Phys. A	54	460-465	1992	modelling calculations; interfaces; grazing incidence; roughness	Surfaces and Layers
Streli, C.; Aiginger, H.; Wobrauschek, P.	Light element determination with a new spectrometer for total-reflection x-ray fluorescence	Spectrochim. Acta Part B	48	163-170	1993	light element detection; TXRF spectrometer	Principles and Instrumentation

Autoren	Titel	Zeitschrift	Vol	Seiten	Jahr	Keywords	Gruppe
Knoth, J.; Bormann, R.; Gutschke, R.; Michaelsen, C.; Schwenke, H.	Examination of layered structures by total-reflection x-ray fluorescence analysis	Spectrochim. Acta Part B	48	285-292	1993	total reflection XRF analysis; layered structure; x-ray fluorescence analysis	Surfaces and Layers
Ojeda, N.; Greaves, E. D.; Alvarado, J.; Sajo-Bohus, L.	Determination of vanadium, iron, nickel and sulphur in petroleum crude oil by total-reflection x-ray fluorescence	Spectrochim. Acta Part B	48	247-253	1993	petroleum; vanadium, iron, nickel, sulphur detection; x-ray	Chemical Analysis
Klockenkämper, R.; von Bohlen, A.; Moens, L.; Devos, W.	Analytical characterization of artists' pigments used in old and modern paintings by total-reflection x-ray fluorescence	Spectrochim. Acta Part B	48	239-246	1993	artist pigment characterization; oil painting; reflection x-ray fluorescence	Chemical Analysis
Schirmacher, M.; Freimann, P.; Schmidt, D.; Dahlmann, G.	Trace metal determination by total-reflection x-ray fluorescence (TXRF) for the differentiation between pure fuel oil (bunker oil) and waste oil (sludge) in maritime shipping legal cases	Spectrochim. Acta Part B	48	199-205	1993	diesel fuel; marine sludge identification; trace metal; water pollution; sludge	Chemical Analysis
Prange, A.; Böddeker, H.; Kramer, K.	Determination of trace elements in river-water using total-reflection x-ray fluorescence	Spectrochim. Acta Part B	48	207-215	1993	river water analysis; x-ray fluorescence	Chemical Analysis
Tölg, G.; Klockenkämper, R.	The role of total-reflection x-ray fluorescence in atomic spectroscopy	Spectrochim. Acta Part B	48	111-127	1993	total reflection x-ray fluorescence	Review
Schwenke, H.; Bormann, R.; Knoth, J.; Prange, A.	Some potential developments for trace element and surface analysis using a grazing incident x-ray beam	Spectrochim. Acta Part B	48	293-299	1993	TXRF; trace element; surface analysis; total reflection x-ray	Related Methods
Van den Hoogenhof, W.W.; de Boer, D.K.G.	Glancing-incidence x-ray analysis	Spectrochim. Acta Part B	48	277-284	1993	glancing incidence x-ray analysis	Related Methods
Horiuchi, T.	Initial idea to use optical flats for x-ray fluorescence analysis and recent applications to diffraction studies	Spectrochim. Acta Part B	48	129-136	1993	optical flat; x-ray fluorescence analysis; total reflection x-ray	Review
Kroninger, F.; Streckfuss, N.; Frey, L.; Falter, T.; Ryzlewicz, C.; Pfitzner, L.; Ryssel, H.	Application of advanced contamination analysis for qualification of wafer handling systems and chucks	Appl. Surf. Sci.	63	93-98	1993	semiconductor; wafer handling system; qualification; chuck	Surfaces and Layers

Autoren	Titel	Zeitschrift	Vol	Seiten	Jahr	Keywords	Gruppe
Günther, K.; von Bohlen, A.; Waldner, H.	Solubility behaviour of metals in ordinary vegetables after cell breakdown	Fresenius' J. Anal. Chem.	345	533-536	1993	metal; vegetable; mechanical cell breakdown; TXRF	Chemical Analysis
Sugihara, Kohei; Hata, Yoshifumi; Fujii, Shinji; Harada, Yoshikazu	Measurement of metallic impurities in SiO2 and at the interface using TXRF	X-sen Bunseki no Shinpo	25	255-268	1993	metallic impurity detection TXRF; interface analysis; silicon dioxide	Surfaces and Layers
Yakushiji, Kenji; Ohkawa, Shinji; Yoshinaga, Atsushi; Harada, Jimpei	Spurious peaks appeared in trace analysis of silicon wafers by total reflection x-ray fluorescence	X-sen Bunseki no Shinpo	25	213-234	1993	silicon analysis; trace impurity; x-ray fluorescence	Surfaces and Layers
Madden, M.C.; Wherry, D.C.; Pianetta, P.; Brennan, S.	Synchrotron radiation for measurement of contaminants on silicon surfaces	Mater. Res. Soc. Symp. Proc.	307	125-130	1993	silicon; surface analysis; synchrotron radiation;	Surfaces and Layers
Reus, U.; Markert, B.; Hoffmeister, C.; Spott, D.; Guhr, H.	Determination of trace metals in river water and suspended solids by TXRF spectrometry. A methodical study on analytical performance and sample homogeneity	Fresenius' J. Anal. Chem.	347	430-435	1993	river water; trace metal detection; total reflection x-ray fluorescence	Chemical Analysis
Streli, C.; Wobrauschek, P.; Unfried, E.; Aiginger, H.	A new spectrometer for total reflection x-ray fluorescence analysis of light elements	Nucl. Instrum. Methods Phys. Res., Sect. A	334	425-429	1993	total reflection x-ray fluorescence spectrometer; light element detection	Principles and Instrumentation
Yakushiji, Kenji; Ohkawa, Shinji; Yoshinaga, Atsushi	The fundamental consideration for the droplet analysis on the wafer by the total reflection X-ray fluorescence	X-sen Bunseki no Shinpo	24	87-95	1993	reflection x-ray fluorescence analysis; droplet	Chemical Analysis
Hegde, Rama I.; Tobin, Philip J.; Fiordalice, Robert W.; Travis, Edward O.	Nucleation and growth of chemical vapor deposition titanium mononitride films on silicon (100) as studied by total reflection x-ray fluorescence, atomic force microscopy, and	J. Vac. Sci. Technol., A	11(4, Pt. 2)	1692-1695	1993	titanium nitride film; nucleation growth; surface morphol titanium nitride	Surfaces and Layers
Yakushiji, Kenji; Ohkawa, Shinji	Reliable data of trace impurity contents on silicon wafers with use of total reflection x-ray fluorescence analysis	X-sen Bunseki no Shinpo	24	97-111	1993	trace impurity; x-ray fluorescence; silicon wafer analysis; total reflection x-ray	Review
Ladisich, W.; Rieder, R.; Wobrauschek, P.; Aiginger, H.	Total reflection x-ray fluorescence analysis with monoenergetic excitation and full spectrum excitation using rotating anode x-ray tubes	Nucl. Instrum. Methods Phys. Res., Sect. A	A330	501-506	1993	total reflection x-ray fluorescence analysis; rotating anode x-ray tube;	Principles and Instrumentation

Autoren	Titel	Zeitschrift	Vol	Seiten	Jahr	Keywords	Gruppe
Freiburg, C.; Krumpen, W.; Troppenz, U.	Determinations of cerium, europium and terbium in the electroluminescent materials gadolinium oxysulfide (Gd2O2S) and lanthanum oxysulfide (La2O2S) by total-reflection x-ray spectrometry	Spectrochim. Acta Part B	48	263-267	1993	rare earth detection; electroluminescent material; x-ray fluorescence;	Chemical Analysis
Fan, Q. M.; Liu, Y. W.; Li, L.; Wei, C. L.	Determination of depth profiling of metal trace impurities on silicon surface using total-reflection x-ray fluorescence	Fresenius' J. Anal. Chem.	345	518-520	1993	silicon analysis; metal profile; x-ray fluorescence; silicon impurity profiling;	Surfaces and Layers
Prange, A.; Kramer, K.; Reus, U.	Boron nitride sample carriers for total-reflection x-ray fluorescence	Spectrochim. Acta Part B	48	153-161	1993	boron nitride sample carrier; TXRF	Principles and Instrumentation
Yakushiji, Kenji; Ohkawa, Shinji; Yoshinaga, Atsushi; Harada, Jimpei	Main peak profiles of total reflection x-ray fluorescence analysis of silicon(001) wafers excited by monochromatic x-ray beam tungsten-L beta (II)	Jpn. J. Appl. Phys., Part 1	32(3 A)	1191-1196	1993	silicon; wafer analysis; total reflection XRF; tungsten	Principles and Instrumentation
Kunii, Yasuo	Measurement of germanium/silicon ratio of silicon-germanium-layer on Si substrate using total-reflection x-ray fluorescence	Jpn. J. Appl. Phys., Part 1	32(3 A)	1279-1284	1993	silicon detection; depth profile; reflection XRF; germanium	Surfaces and Layers
Ryssel, H.; Frey, L.; Streckfuss, N.; Schork, R.; Kroninger, F.; Falter, T.	Contamination control and ultrasensitive chemical analysis	Appl. Surf. Sci.	63	79-87	1993		Review
Horiuchi, Toshihisa; Matsushige, Kazumi	Total-reflection x-ray diffractometry and its applications to evaporated organic thin films	Spectrochim. Acta Part B	48	137-142	1993	total reflection x-ray diffraction; film	Related Methods
Freimann, P.; Schmidt, D.; Neubauer-Ziebarth, A.	Reference materials for quality assurance in sea-water analysis: performance of total-reflection x-ray fluorescence in the intercomparison and certification stages	Spectrochim. Acta Part B	48	193-198	1993	seawater analysis; reference material; certification	Chemical Analysis
Schmidt, D.; Gerwinski, W.; Radke, I.	Trace metal determinations by total-reflection x-ray fluorescence analysis in the open Atlantic Ocean	Spectrochim. Acta Part B	48	171-181	1993	heavy metal detection; x-ray fluorescence spectrometry;	Chemical Analysis
Diebold, A.C.; Bruce, D.	A survey of non-destructive surface characterization methods used to insure reliable gate oxide fabrication for silicon IC devices	Surf. Interface Anal.	20	127-139	1993		Review

Autoren	Titel	Zeitschrift	Vol	Seiten	Jahr	Keywords	Gruppe
Berneike, W.	Basic features of total-reflection x-ray fluorescence analysis on silicon wafers	Spectrochim. Acta Part B	48	269-275	1993	reflection x-ray fluorescence analysis; silicon; total reflection XRF	Surfaces and Layers
Dixkens, J.; Fissan, H.; Dose, T.	A new particle sampling technique for direct analysis using total-reflection x-ray fluorescence spectrometry	Spectrochim. Acta Part B	48	231-238	1993	particle sampling; total reflection XRF analysis; x-ray fluorescence analysis	Chemical Analysis
Rieder, R.; Ladisich, W.; Wobrauschek, P.; Streli, C.; Kregsamer, P.	A multifunctional vacuum chamber for total reflection x-ray fluorescence analysis in various excitation and detection geometries for detection limits in the femtogram range	Nucl. Instrum. Methods Phys. Res., Sect. A	A327	594-599	1993	total reflection XRF; multifunctional vacuum chamber	Principles and Instrumentation
Schwenke, H.; Knoth, J.	Total reflection XRF	in: Handbook on X-Ray Spectrometry, Practical Spectroscopy	14	453-	1993		Review
Fabry, L.; Pahlke, S.; Kotz, L.; Schemmel, E.; Berneike, W.	TXRF in the daily routine	Proc. - Electrochem. Soc.	93-15	232-239	1993	total refection x-ray fluorescence analysis	Surfaces and Layers
Dogan, P.; Dogan, M.; Klockenkämper, R.	Determination of trace elements in blood serum of patients with Behcet disease by total reflection X-ray fluorescence analysis	Clin. Chem.	39	1037-1041	1993	blood serum; iron, copper, zinc, selenium. Rubidium, Behcet	Chemical Analysis
Hockett, R. S.	High sensitivity characterization of contamination on silicon surfaces using TXRF	Proc. - Inst. Environ. Sci.	39TH (VOL. 1)	432-459	1993	TXRF; characterization contamination; silicon surface	Layers and Surfaces
Reus, U.; Prange, A.	An analyst´s approach to total reflection XRF: Features and applications	Spectroscopy Europe	5	25-33	1993		Review
Wobrauschek, P.; Kregsamer, P.; Ladisich, W.; Rieder, R.; Streli, C.	Total-reflection X-ray fluorescence analysis using special X-ray sources	Spectrochim. Acta Part B	48	143-151	1993	double-plate reflector; multilayer structure; synchrotron radiation	Principles and Instrumentation
Streckfuss, N.; Frey, L.; Pichler, P.; Kgel, M.; Zielonka, G.; Ryssel, H.	Trace analysis of silicon surfaces using angle-dependent total-reflection X-ray fluorescence	Proc. - Electrochem. Soc.	93-15	222-231	1993	trace analysis; silicon surface; ADTXRF; angle dependent TXRF	Surfaces and Layers

Autoren	Titel	Zeitschrift	Vol	Seiten	Jahr	Keywords	Gruppe
Tölg, G.	Problems and trends in extreme trace analysis for the elements	Anal. Chim. Acta	283	3-18	1993		Review
Eichinger, P.; Hage, J.; Huber, D.; Falster, R.	Characterization of metallic impurities in large diameter CZ Si wafers in high volume production environment	Proc. - Electrochem. Soc.	93-15	240-251	1993	metallic impurity characterization silicon wafer	Surfaces and Layers
Taniguchi, K.	Total reflection X-ray fluorescence spectrometry	SR Kagaku Gijutsu Joho	3	2-6	1993		Review
Haarich, M., Schmidt, D., Freimann, P., Jakobsen, A.	North Sea research projects ZISCH and PRISMA: application of total reflection X-ray fluorescence in sea-water analysis	Spectrochim. Acta Part B	48	183-192	1993	Sea water; trace elements;	Chemical Analysis
Losev, N.F.; Krasnolutskii, V.P.; Losev, V.N.	X-ray spectral fluorescence analysis using total external reflection of primary radiation. Review	Zavod. Lab.	59	20-29	1993		Review
Zecca, L.; Swartz, H.M.	Total and paramagnetic metals in human substantia nigra and its neuromelanin	J. Neural. Transm. [P-D Sect]	5	203-213	1993	Free radicals - trace elements - cytotoxicity - EPR - Parkinson's	Chemical Analysis
Prange, A.; Böddeker, H.; Kramer, K.	Determination of trace elements in river-water using total-reflection X-ray fluorescence	Spectrochim. Acta Part B	48	207-215	1993		Chemical Analysis
Ohsugi, Tetsuya; Kyoto, Michihisa	Environmental analysis in clean rooms using total reflection x-ray fluorescence technique	X-sen Bunseki no Shinpo	25	247-254	1993	environmental analysis; clean room; x-ray fluorescence analysis	Chemical Analysis
Battiston, G.A.; Gerbasi, R.; Degetto, S.; Sbrignadello, S.	Heavy metal speciation in coastal sediments using fluorescence spectrometry	Spectrochim. Acta Part B	48	217-221	1993		Chemical Analysis
Prange, A.	Total reflection X-ray fluorescence analysis	Nachr. Chem., Tech. Lab.	41	40-45	1993		Review

Autoren	Titel	Zeitschrift	Vol	Seiten	Jahr	Keywords	Gruppe
Hahn, J.U.; Jaschke, M.	Determination of metals in cooling lubricants by use of total-reflection X-ray fluorescence analysis	Staub-Reinhalt. Luft	53	109-113	1993	Cooling lubricants; Metal contamination; Preparation techniques	Chemical Analysis
Jin, L.	Total reflection X-ray fluorescence analysis introduction of a new highly sensitive method	Yejin Fenxi	13	31-34	1993		Review
Utaka, Tadashi; Sako, Yukio; Kohno, Hiroshi; Shoji, Takashi; Shimizu, Kazuaki; Miyazaki, Kunihiro; Shimazaki, Ayako	High sensitivity x-ray analyzer for total x-ray fluorescence analysis	X-sen Bunseki no Shinpo	25	203-212	1993	x-ray fluorescence analysis analyzer	Principles and Instrumentation
Boumans, P.	Developments and trends in plasma spectrometry - a view	J. Anal. At. Spectrom.	8	767-780	1993		Review
Fan, Q.; Gohshi, Y.	Enhancement of total reflection X-ray fluorescence spectroscopy with electrochemical deposition	Appl. Spectrosc.	47	1739-1956	1993	Concentration technique; Electrodeposition	Chemical Analysis
Salva, A.; von Bohlen, A.; Klockenkämper, R.; Klockow, D.	Multielement analysis of airborne particulate matter by total reflection X-ray fluorescence	Quim. Anal. (Barcelona)	12	57-62	1993	airborne particulate; analysis; x-ray fluorescence	Chemical Analysis
Jacobson, D. C.; Poate, J. M.; Higashi, G. S.; Boone, T.; Eaglesham, D. J.; Hockett, Richard	Ion implanted calibration standards for silicon surface contamination detection by total reflection x-ray fluorescence (TXRF)	Mater. Res. Soc. Symp. Proc.	315	347-351	1993	ion implantation silicon surface contamination detection	Surfaces and Layers
Streli, C., Aiginger, H., and Wobrauschek, P.	A new spectrometer for total reflection X-ray fluorescence analysis of light elements	Nucl. Instr. Meth. A	334	425-429	1993		Principles and Instrumentation
Pepelnik, R.; Erbslöh, B.; Michaelis, W.; Prange, A.	Determination of trace element deposition into a forest ecosystem using total-reflection X-ray fluorescence	Spectrochim. Acta Part B	48	223–229	1993		Chemical Analysis
Verhaverbeke, S.; Werkhoven, C.; Meuris, M.; Schmidt, H. F.; Dillenbeck, K.; Mertens, P.; Heyns, M.; Philipossian, A.	Investigation of sources of metallic contamination by TXRF	Proc. - Inst. Environ. Sci.	39TH (VOL. 1)	423-431	1993	metallic contamination source; TXRF; investigation	Chemical Analysis

Autoren	Titel	Zeitschrift	Vol	Seiten	Jahr	Keywords	Gruppe
Schwenke, H.; Knoth, J.	Total reflexion XRF	Pract. Spectrosc.	14	453-489	1993		Review
Taniguchi, K.	Total reflection X-ray analysis	Bunseki	(3)	168-174	1993		Review
Hockett, R. S	Ultratrace impurity analysis of silicon surfaces by SIMS and TXRF methods	Handb. Semicond. Wafer Clean. Technol.		537-592	1993	silicon; impurity detection; SIMS; TXRF	Review
Gupta, P.; Tan, S.H.; Pourmotamed, Z.; Cristobal, F.; Oshiro, N.; McDonald, B.	Novel methods for trace metal analysis in process chemicals and deionized water and on silicon surfaces	Proc. - Electrochem. Soc.	94-9	200-221	1994	process chem; deionized water trace metal analysis; silicon surface trace	Surfaces and Layers
Wobrauschek, P.	Use of total reflection x-ray fluorescence [TXRF] analysis in the life sciences	Biol. Trace Elem. Res.	43-45	65-71	1994	total reflection XRF; x-ray fluorescence; life science	Review
Hockett, R. S.; Metz, J. M.	Characterization of inorganic contamination in liquid crystal display materials using total reflection x-ray fluorescence (TXRF)	Mater. Res. Soc. Symp. Proc.	345	223-234	1994	inorg contamination; reflection x-ray fluorescence; liquid crystal display	Chemical Analysis
Lieser, K. H.; Flakowski, M.; Hoffmann, P.	Determination of trace elements in small water samples by total reflexion X-ray fluorescence (TXRF) and by neutron activation analysis (NAA)	Fresenius' J. Anal. Chem.	350	135-138	1994	neutron activation analysis water; x-ray fluorescence water analysis	Chemical Analysis
Brennan, S.; Tompkins, W.; Takaura, N.; Pianetta, P.; Laderman, S. S.; Fischer-Colbrie, A.; Kortright, J. B.; Madden, M. C.; Wherry, D. C.	Wide band-pass approaches to total-reflection X-ray fluorescence using synchrotron radiation	Nucl. Instrum. Methods Phys. Res., Sect. A	347	417-421	1994	total reflection x-ray fluorescence analysis; synchrotron	Instrumentation
Taniguchi, K.	Total-reflection fluorescent x-ray analysis	Kinzoku	64(10)	13-17	1994	reflection fluorescent x-ray analysis	Review
Hockett, R. S.	TXRF semiconductors applications	Adv. X-Ray Anal.	37	565-575	1994	X-ray fluorescence semiconductor	Review

Autoren	Titel	Zeitschrift	Vol	Seiten	Jahr	Keywords	Gruppe
Markert, B.; Reus, U.; Herpin, U.	The application of TXRF in instrumental multielement analysis of plants, demonstrated with species of moss	Sci. Total Environ.	152	213-220	1994	moss; x-ray fluorescence; metal; air pollution; monitoring	Chemical Analysis
Streli, C.; Wobrauschek, P.; Aiginger, H.; Ladisich, W.; Rieder, R.	Total reflection XRF of light elements using various excitation sources	Adv. X-Ray Anal.	37	577-583	1994	total reflection XRF; light element detection	Principles and Instrumentation
Utaka, T.; Shoji, T.; Shimizu, K.; Arai, T.	TXRF- high sensitivity X-ray analyzer with multi-layer monochromator	Adv. X-Ray Anal.	37	599-605	1994	high sensitivity; TXRF; multilayer monochromator; x-ray fluorescence	Principles and Instrumentation
Metz, J. M.; Radicati, F.; Craig, A. Y.; Hockett, R. S.	Comparison of wafer cassette contamination using multi-techniques	Proc. - Electrochem. Soc.	94-3	132-142	1994	wafer cassette; contamination; interion surface multitechnique;	Surfaces and Layers
Törok, S.B.; Van Grieken, R.E.	X-Ray Spectrometry	Anal. Chem.	66	186R-206R	1994		Review
Krumpen, W.	Application of total reflection X-ray fluorescence analysis in trace analysis	Ber. Forschungszent. Jülich	JUEL-2867	111-122	1994		Review
Liang, M. K.; Ling, Y. C.	Application of TXRF in sub-micron VLSI	Cailiao Kexue	26(1)	73-76	1994	total reflection X-ray fluorescence spectroscopy; VLSI; silicon wafer	Surfaces and Layers
Wobrauschek, P.	Use of total Reflection X-ray Fluorescence Analysis in the life sciences	Biological Trace Element Research	43-45	65-71	1994	X-ray fluorescence analysis (XRF); energy-dispersive XRF (EDXRF); total	Chemical Analysis
Stoev, K.N.	Study on journal distribution of publications in the field of X-ray fluorescence analysis	X-Ray Spectrom.	23	229-35	1994		Review
Fabry, L.; Pahlke, S.; Kotz, L.; Tölg, G.	Trace-analytical methods for monitoring contaminations in semiconductor-grade Si manufacturing	Fresenius' J. Anal. Chem.	349	260-270	1994	semiconductor; trace-analytical methods; VPD	Review

Autoren	Titel	Zeitschrift	Vol	Seiten	Jahr	Keywords	Gruppe
Chen, Y.	Principles and applications of total reflection X-ray fluorescence spectrometry	Fenxi Huaxue	22	406-414	1994		Review
Baumann, S. M.; Hitzman, C. J.; Ivanov, I. C.; Craig, A. Y.; Lindley, P. M.	Multi-technique characterization of WSix films	Mater. Res. Soc. Symp. Proc.		675-683	1994	characterization technique; tungsten silicide film	Surfaces and Layers
Moens, L.; Devos, W.; Klockenkämper, R.; von Bohlen, A.	Total reflection X-ray fluorescence in the ultramicro analysis of artists´pigments	TrAC, Trends Anal. Chem.	13	198-205	1994		Review
von Bohlen, A.; Rechmann, P.; Tourmann, J.L.; Klockenkämper, R.	Ultramicroanalysis of dental plaque films by total reflection X-ray fluorescence	J. Trace Eelm. Electrolytes Health Dis.	8	37-42	1994	Plaque analysis; Amalgam fillings; Mercury	Chemical Analysis
Knoth, J., Schneider, H., Schwenke, H.	Tunable Exciting Energies for Total Reflection X-Ray Fluorescence Spectrometry Using a Tungsten Anode and Bandpass Filtering	X-Ray Spectrom	23	261-266	1994	crystal monochromators; multilayer; excitation energies	Principles and Instrumentation
Torcheux, L.; Degraeve, B.; Mayeux, A.; Delamar, M.	Calibration procedure for quantitative surface analysis by total reflection x-ray fluorescence	Surf. Interface Anal.	21	192-198	1994	surface analysis; TXRF calibration; total reflection XRF	Surfaces and Layers
Streli, C.; Wobrauschek, P.; Ladisich, W.; Rieder, R.; Aiginger, H.; Ryon, R. W.; Pianetta, P	Total reflection X-ray fluorescence analysis of light elements using synchrotron radiation	Nucl. Instrum. Methods Phys. Res., Sect. A	345	399-403	1994	light element detection; x-ray fluorescence; synchrotron	Principles and Instrumentation
Fisch, E. E.; Gaylord, R. H.; Estes, S. A.	Metal contamination monitoring in a semiconductor manufacturing environment	Proc. - Electrochem. Soc.	94-7	514-521	1994	metal contamination monitoring; semiconductor device fabrication	Surfaces and Layers
Holynska, B.; Ostachowicz, B.; Ostachowicz, J.; Ostrowski, A.; Ptasinski, J.; Wegrzynek, D.	Multifunctional system for energy dispersive x-ray fluorescence analysis	J. Trace Microprobe Tech.	13	163-175	1995	multifunctional system EDXRF; energy dispersive x-ray fluorescence;	Chemical Analysis
Tsuji, Kouichi; Yamada, Takashi; Utaka, Tadashi; Hirokawa, Kichinosuke	The effects of surface roughness on the angle-dependent total-reflection x-ray fluorescence of ultrathin films	J. Appl. Phys.	78	969-973	1995	surface roughness; x-ray fluorescence; film; silicon gold grating x-ray	Surfaces and Layers

Autoren	Titel	Zeitschrift	Vol	Seiten	Jahr	Keywords	Gruppe
Aiginger, H.; Wobrauschek, P.; Streli, C.	Principles and development of total reflection x-ray fluorescence analysis	Anal. Sci.	11	471-476	1995	total reflection XRF; x-ray fluorescence analysis; grazing incidence x-ray	Review
Hockett, R.S.	A review of standardization issues for total reflection x-ray fluorescence and vapor phase decomposition/total reflection x-ray fluorescence	Anal. Sci.	11	511-513	1995	standardization; VPD; TXRF; surface metal detection; silicon; total	Review
Schwenke, H.; Knoth, J.	Discrimination between particulate and film type contamination on surfaces by means of total reflection x-ray fluorescence spectrometry	Part. Surf. [Proc. Symp.]	4th		1995	particulate type contamination; TXRF; film type contamination;	Surfaces and Layers
Streli, C.; Wobrauschek, P.; Randolf, G.; Rieder, R.; Ladisich, W.; Aiginger, H.	Theoretical considerations about total reflection x-ray fluorescence for light element analysis at various excitation energies and experimental results	Anal. Sci.	11	477-481	1995	TXRF; light element detection; energy dispersive; scattering reflector;	Principles and Instrumentation
Pettersson, R. P.; Wobrauschek, P.	Total-reflection x-ray fluorescence analysis with an 18 kW rotating anode source - first results	Nucl. Instrum. Methods Phys. Res., Sect. A	355	665-667	1995	total reflection x-ray fluorescence; source; rotating anode	Principles and Instrumentation
Yakushiji, Kenji; Ohkawa, Shinji; Yoshinaga, Atsushi; Harada, Jimpei	Spurious peaks in total reflection x-ray fluorescence analysis	Anal. Sci.	11	505-510	1995	spurious peak; total reflection XRF analysis; silicon analysis	Surfaces and Layers
Laderman, Stephen S.; Fischer-Colbrie, Alice; Shimazaki, Ayako; Miyazaki, Kunihiro; Brennan, Sean; Takakura, Noritaka; Pianetta, Piero;	High-sensitivity total reflection x-ray fluorescence spectroscopy of silicon wafers using synchrotron radiation	Anal. Sci.	11	515-518	1995	total reflection XRF; silicon wafer	Principles and Instrumentation
Streli, C.; Wobrauschek, P.; Ladisich, W.; Rieder, R.; Aiginger, H.	Total reflection x-ray fluorescence analysis for light elements under various excitation conditions	X-Ray Spectrom.	24	137-142	1995	total reflection XRF detection light element	Principles and Instrumentation
Wobrauschek, P.; Kregsamer, P.; Ladisich, W.; Streli, C.; Pahlke, S.; Fabry, L.; Garbe, S.; Haller, M.; Knöchel, A.; et al.	TXRF with synchrotron radiation. analysis for Ni on Si-wafer surfaces	Nucl. Instrum. Methods Phys. Res., Sect. A	363	619-620	1995	synchrotron radiation; TXRF; nickel detection silicon	Principles and Instrumentation
Mori, Yoshihiro; Shimanoe, Kengo; Sakon, Tadashi	A standard sample preparation method for the determination of metal impurities on a silicon wafer by total reflection x-ray fluorescence spectrometry	Anal. Sci.	11	499-504	1995	std sample preparation; silicon wafer analysis; calibration std	Chemical Analysis

Autoren	Titel	Zeitschrift	Vol	Seiten	Jahr	Keywords	Gruppe
Frank, W.; Thomas, H.-J.; Schindler, A.	Depth profiling by means of the combination of glancing incidence x-ray fluorescence spectrometry with low energy ion beam etching technique	Spectrochim. Acta Part B	50	265-270	1995	x-ray fluorescence spectrometry; depth profiling; ion beam etching	Related Methods
Bayer, H.; von Bohlen, A.; Klockenkämper, R. Klockow, D.	Choice of a suitable material for construction of a Battelle type impactor to minimize systematic errors in sampling of airborne dust	Mikrochim. Acta	119	167-176	1995	airborne dust; sampling; cascade impactor; TXRF	Chemical Analysis
Klockenkämper, R.; Bayer, H.; von Bohlen, A.; Schmeling, M.; Klockow, D.	Collection of airborne particulate matter for a subsequent analysis by total reflection x-ray fluorescence	Anal. Sci.	11	495-498	1995	filtration; collection; airborne particulate matter; impa-ction; cellulose nitrate	Chemical Analysis
Günther, K.; von Bohlen, A.; Strompen, C.	Element determination by total-reflection X-ray fluorescence spectrometry at the initial step of element speciation in biological matrixes	Anal. Chim. Acta	309	327-332	1995	mineral trace element detection; biological matrix	Chemical Analysis
Sees, J.A.; Hall, L.H.	TXRF analysis of SC-1 treated silicon wafers	J. Electrochem. Soc.	142	1238-1241	1995	cleaned silicon wafer analysis; TXRF	Surfaces and Layers
Rieder, R.; Wobrauschek, P.; Ladisich, W.; Streli, C.; Aiginger, H.; Garbe, S.; Gaul, G.; Knöchel, A.; Lechtenberg, F.	Total reflection X-ray fluorescence analysis with synchrotron radiation monochromatized by multilayer structures	Nucl. Instrum. Methods Phys. Res., Sect. A	355	648-653	1995	total reflection x-ray fluorescence analysis; synchrotron	Principles and Instrumentation
Wiener, G.; Michaelsen, C.; Knoth, J.; Schwenke, H.; Bormann, R.	Concentration-depth profiling using total-reflection x-ray fluorescence spectrometry in combination with ion-beam microsectioning techniques	Rev. Sci. Instrum.	66(1, Pt. 1)	20-23	1995	depth profiling; total reflection XRF; ion beam microsectioning;	Layers and Surfaces
Schwenke, H.; Knoth, J.	Depth Profiling in Surfaces Using Total Reflection X-Ray Fluorescence	Anal. Sci.	11	533-537	1995	Glancing incidence X-ray fluorescence spectroscopy; calibration; thin film	Surfaces and Layers
Devos, W.; Moens, L.; von Bohlen, A.; Klockenkämper, R.	Ultra-microanalysis of inorganic pigments on painted objects by total reflection X-ray fluorescence analysis	Studies in Conservation	40	153-162	1995	inorganic pigments; ultra-microsampling; TXRF;	Chemical Analysis
Braziewicz, J.	External total reflection of X-rays: new applications	Postepy Fiz.	46	453-478	1995		Review

Autoren	Titel	Zeitschrift	Vol	Seiten	Jahr	Keywords	Gruppe
Huang, T.C.; Lee, W.Y.	X-ray fluorescence and reflectivity analysis of multiple layer thin films	Anal. Sci.	11	529-532	1995		Review
Kawai, J.; Hayakawa, S.; Kitajima, Y.; Gohshi, Y.	X-ray absorption and photoelectron spectroscopies using total reflection X-rays	Anal. Sci.	11	519-524	1995		Review
Ohsugi, T.; Kyoto, M.	Trace analysis using the total reflection X-ray fluorescence (TXRF) technique	Sumitomo Denki	147	153-157	1995		Review
Prange, A.; Reus, U.; Böddeker, H.; Fischer, R.; Adolf, F.-P.	Microanalysis in forensic science: characterization of single textile fibers by total reflection x-ray fluorescence	Anal. Sci.	11	483-487	1995	forensic; textile fiber; x-ray fluorescence	Chemical Analysis
Yamada, T.; Shoji, T.; Funahashi, M.; Utaka, T.; Arai, T.; Wilson, R.	Tungsten analysis with a total reflection X-ray fluorescence spectrometer using a three crystal changer	Adv. X-Ray Chem. Anal. Jpn.	26s	53-56	1995		Surfaces and Layers
Streli, C.	Light element trace analysis by means of TXRF using Synchrotron radiation	J. Trace and Microprobe Techniques	13	109-117	1995	EDXRF; TXRF; Synchrotron radiation; Low-Z elements; Light	Principles and Instrumentation
Moens, L.; Devos, W.; Klockenkämper, R.; von Bohlen, A.	Application of TXRF for the ultra micro analysis of artists´ pigments	J. Trace and Microprobe Techniques	13	119-139	1995	TXRF; Pigments; Artifacts; Inorganic analysis	Chemical Analysis
Yoshihiro Mori, Y.; Uemura, K.; Shimanoe, K.; Sakon, T.	Adsorption Species of Transition Metal Ions on Silicon Wafer in SC-1 Solution	J. Electrochem. Soc.	142	3104-3109	1995		Surfaces and Layers
Hockett, R.S.	A review of standardization issues for TXRF and VPD/TXRF	Adv. X-Ray Chem. Anal. Jpn.	26s	79-84	1995		Surfaces and Layers
Yakushui, K.; Ohkawa, S.; Yoshinaga, A.; Harada, J.	Trace determination of metallic impurities on Si-wafers using a commercially available TXRF analyzer	Adv. X-Ray Chem. Anal. Jpn.	26s	73-78	1995		Surfaces and Layers

Autoren	Titel	Zeitschrift	Vol	Seiten	Jahr	Keywords	Gruppe
Mori, Y.; Shimanoe, K.; Sakon, T.	Standard sample preparation for quantitative TXRF analysis	Adv. X-Ray Chem. Anal. Jpn.	26s	69-72	1995		Chemical Analysis
Streli, C.; Wobrauschek, P.; Randolf, C.; Rieder, R.; Ladisich, W.; Aiginger, H.	Light element analysis with TXRF at different excitation energies: theory and experiment	Adv. X-Ray Chem. Anal. Jpn.	26s	63-68	1995		Principles and Instrumentation
von Bohlen, A.; Klockenkämper, R.; Garbe, S.; Gaul, G.; Knöchel, A.; Lechtenberg, F.; Palmetshofer, L.	Application of a synchrotron microprobe to the analytical characterization of ion-implanted material	Spectrochim. Acta Part B	50	1769-1777	1995	Synchrotron; Capillary optics; Wafer implantation	Related Methods
Klockenkämper, R.; von Bohlen, A.; Radtke, M.; Garbe, S.; Haller, M.; Knöchel, A.; Palmetshofer, L.	Analytical characterization of ion-implanted conductors in Si-wafers by a synchrotron microprobe	HASYLAB/DESY Jahresbericht	II	967-968	1995	Synchrotron; Capillary optics; Wafer implantation	Related Methods
Sasaki, Y.C.	Fluorescent X-ray interference from a metal monolayer and metal-labeled proteins	Adv. X-Ray Chem. Anal. Jpn.	26s	193-198	1995		Surfaces and Layers
Greaves, E.D.; Meitin, J.; Sajo-Bohus, L.; Castelli, C; Liendo, J.; Borgerg,C. M.D	Trace element determination in amniotic fluid by total reflection X-ray fluorescence	Adv. X-Ray Chem. Anal. Jpn.	26s	47-52	1995		Chemical Analysis
Klockenkämper, R.; Bayer, H.; von Bohlen, A.	Total reflection X-ray fluorescence analysis of airborne particulate matter	Adv. X-Ray Chem. Anal. Jpn.	26s	41-46	1995	TXRF; Airborne particulate matter; Battelle impactor; Berner impactor	Chemical Analysis
Gambino, V.; Moccia, G.; Girolami, E.; Alfonsetti, R.	Study of metal contamination induced by ion implantation process using TRXRF and SIMS techniques	Adv. X-Ray Chem. Anal. Jpn.	26s	35-40	1995		Principles and Instrumentation
Yamada, T.; Arai, T.	X-ray spectra detected with a Lithium drifted silicon detector in total reflection fluorescence analysis	Adv. X-Ray Chem. Anal. Jpn.	26s	29-34	1995		Principles and Instrumentation
Ayala, R.E.; Pérez, J.F.	Empirical versus theoretical calibration of a total reflection X-ray fluorescence spectrometer	Adv. X-Ray Chem. Anal. Jpn.	26s	25-28	1995		Chemical Analysis

Autoren	Titel	Zeitschrift	Vol	Seiten	Jahr	Keywords	Gruppe
Tsuchiya, N.; Matsushita, Y.	Impurity distribution correction for full wafer mapping by TXRF	Adv. X-Ray Chem. Anal. Jpn.	26s	85-90	1995		Surfaces and Layers
Fabry, L.; Pahlke, S.; Kotz, L.; Adachi, Y.; Furukawa, S.	Standardization of TXRF using microdroplet samples. Particulate or film type?	Adv. X-Ray Chem. Anal. Jpn.	26s	19-24	1995		Surfaces and Layers
Mainka, G.; Metz, S.; Martin, A.; Fester, A.; Rostam-Khani, P.; Schemmel, E.; Berneike, W.; Kolbesen, B.O.	Adsorption studies of Co-57, Ni-63 and U-238 on silicon wafers - a comparison of TXRF and radiochemical analysis	Adv. X-Ray Chem. Anal. Jpn.	26s	57-62	1995		Chemical Analysis
Alfonsetti, R.; De Tommasis, R.; Famà, F.; Moccia, G.; Santucci, S.; Passacantando, M.	Characterization of Sio2/Si3N4/SiO2 stacked films by XPS, AFM, I-Vand C-V techniques	Adv. X-Ray Chem. Anal. Jpn.	26s	145-150	1995		Surfaces and Layers
Laderman, S.S.; Fischer-Colbrie, A.; Shimazaki, A.; Miyazaki, K.; Brennan, S.; Takaura, N.; Pianetta, P.; Kortright, J.B.	High sensitivity total reflection X-ray fluorescence spectroscopy of silicon wafers using Synchrotron radiation	Adv. X-Ray Chem. Anal. Jpn.	26s	91-96	1995	Synchrotron	Surfaces and Layers
Kawai, J.;. Hayakawa, S.; Kitajima, Y.; Gohshi, Y.	Total reflection X-ray absorption and photoelectron spectroscopy	Adv. X-Ray Chem. Anal. Jpn.	26s	97-102	1995		Related Methods
Zhan, X.C.; Hayakawa, S.; Zheng, S.; Gohshi, Y.	Trace element detection utilizing sample current jump around X-ray absorption edge	Adv. X-Ray Chem. Anal. Jpn.	26s	103-106	1995		Related Methods
Liu, K.Y.; Kojima, S.; Kudo, Y.; Kawada, S.; Iida, A.	Sr-TXRF analysis of metallic impurities on silicon surface	Adv. X-Ray Chem. Anal. Jpn.	26s	107-112	1995	Synchrotron	Surfaces asnd Layers
Takaura, N.; Brennan, S.; Pianetta, P.; Laderman, S.S.; Fischer-Colbrie, A.; Kortright, J.B.; Wherry, D.C.; Miyazaki, K.; Shimazaki, A.	Quantitative consideration of background contributions to TXRF spectra for the case of a Synchrotron radiation X-ray source	Adv. X-Ray Chem. Anal. Jpn.	26s	113-118	1995	Synchrotron	Principles and Instrumentation
de Boer, D.K.G.; Leenaers, A.J.G.	X-ray scattering from samples with rough interfaces	Adv. X-Ray Chem. Anal. Jpn.	26s	119-124	1995		Surfaces and Layers

Autoren	Titel	Zeitschrift	Vol	Seiten	Jahr	Keywords	Gruppe
Hayashi, K.; Horiuchi, T.; Matsushige, K.	The estimation on molecular orientations in copper-Phthalocyanine thin films by total reflection in-plane diffractometer	Adv. X-Ray Chem. Anal. Jpn.	26s	125-128	1995		Chemical Analysis
Wobrauschek, P.	Total reflection X-ray fluorescence analysis with polarized radiation	J. Trace and Microprobe Techniques	13	83-96	1995	EDXRF; TXRF; Linear polarized X-rays; Synchrotron radiation; Lower	Principles and Instrumentation
Schwenke, H.; Knoth, J.	Depth profiling in surfaces using TXRF	Adv. X-Ray Chem. Anal. Jpn.	26s	137-144	1995		Surfaces and Layers
de Bokx, P.K.; Urbach, H.P.	Calculation of fluorescence intensities in grazing-emission X-ray fluorescence spectrometry	Adv. X-Ray Chem. Anal. Jpn.	26s	199-204	1995		Related Methods
Tsuji, K.; Sato, S.; Hirokawa, K.	X-ray fluorescence analysis of thin films at glancing-incident and -takeoff angles	Adv. X-Ray Chem. Anal. Jpn.	26s	151-156	1995		Surfaces and Layers
Ishida, K.; Horiuchi, T.; Matsushige, K.	Epitaxial growth of organometallic thin films studied by total reflection X-ray diffraction	Adv. X-Ray Chem. Anal. Jpn.	26s	157-162	1995		Surfaces and Layers
Watanabe, I.; Tanida, H.	XAFS spectra of solution surfaces by total reflection total-electron yield method	Adv. X-Ray Chem. Anal. Jpn.	26s	163-168	1995		Surfaces and Layers
Kamakura, T.; Sugamoto, H.; Tsuchiya, N.; Matsushita, Y.	The application of TXRF for the adsorbed impurities on the GaAs wafers	Adv. X-Ray Chem. Anal. Jpn.	26s	169-174	1995		Surfaces and Layers
Kohzuki, H.; Motoyama, M.; Shin, S.; Agui, A.; Kato, H.; Muramatsu, Y.; Kawai, J.; Adachi, A?	Soft X-ray spectrochemical analysis of boron nitride thin film structure	Adv. X-Ray Chem. Anal. Jpn.	26s	175-180	1995		Surfaces and Layers
Zheludeva, S.I.; Kovalchuk, M.V.; Novikava, N.N.; Sospenov, A.N.	The role of film thickness in the realization of X-ray waveguide effects at total reflection	Adv. X-Ray Chem. Anal. Jpn.	26s	181-186	1995		Surfaces and Layers

Autoren	Titel	Zeitschrift	Vol	Seiten	Jahr	Keywords	Gruppe
Ino, S.	Study of epitaxy by RHEED-TRAXS (Total Reflection Angle X-ray Spectroscopy)	Adv. X-Ray Chem. Anal. Jpn.	26s	187-192	1995		Surfaces and Layers
Ninomiya, T.; Nomura, S.; Taniguchi, K.; Ikeda, S.	Application of GIXF to forensic samples	Adv. X-Ray Chem. Anal. Jpn.	26s	9-18	1995		Related Methods
Huang, T.C.; Lee, W.Y.	Characterization of multiple-layer thin films by X-ray fluorescence and reflectivity techniques	Adv. X-Ray Chem. Anal. Jpn.	26s	129-136	1995		Surfaces and Layers
Devos, W.; Moens, L.; von Bohlen, A.; Klockenkämper, R.	Ultra-microanalysis of inorganic pigments on painted objects by total reflection x-ray fluorescence analysis	Stud. Conserv.	40	153-162	1995	x-ray fluorescence analysis pigment paint	Chemical Analysis
Hockett, R. S.	Trace analysis by TXRF	Adv. X-Ray Anal.	38	687-690	1995	x-ray fluorescence analysis; synchrotron radiation;	Review
Injuk, J.; Van Grieken, R.	Optimization of total-reflection x-ray fluorescence for aerosol analysis	Spectrochim. Acta Part B	50	1787-1803	1995	optimization total reflection XRF; aerosol analysis; x-ray fluorescence	Chemical Analysis
Yamada, T.; Shoji, T.; Funahashi, M.; Utaka, T.; Arai, T.; Wilson, R.	Development of a high sensitivity TXRF with a novel monochromator having three selectable crystals	Adv. X-Ray Anal.	38	313-317	1995	TXRF; monochromator; three selectable crystal	Principles and Instrumentation
Hayashi, Kouichi; Horiuchi, Toshihisa; Matsushige, Kazumi	Simultaneous analysis of total reflection x-ray diffraction and fluorescence from copper-phthalocyanine thin films during evaporation process	Jpn. J. Appl. Phys., Part 1	34(12A)	6478-6482	1995	x-ray diffraction; fluorescence; copper phthalocyanine	Chemical Analysis
Hockett, R. S.	Total reflection x-ray fluorescence (TXRF)	Mater. Res. Soc. Symp. Proc.	354	377-388	1995	total reflection XRF; silicon processing; TXRF	Review
Ohsugi, Tetsuya; Kyoto, Michihisa	Trace analysis using the total reflection x-ray fluorescence (TXRF) technique	Sumitomo Denki	147	153-157	1995	trace analysis; x-ray fluorescence; total reflection x-ray fluorescence	Review

Autoren	Titel	Zeitschrift	Vol	Seiten	Jahr	Keywords	Gruppe
Torboli, A.	Total reflection x-ray fluorescence (TXRF) spectrometer TX 2000	Lab. 2000	9(7)	48-51	1995	x-ray reflection fluorescence spectrometer	Principles and Instrumentation
Jeon, Hyeongtag; Choi, Hyungbok; Cho, Y. S.; Ryoo, K. K.; Jung, S. D.	Effects of UV/O3 and SC1 steps for the HF last silicon wafer cleaning	Mater. Res. Soc. Symp. Proc.	386	297-302	1995	ULSI circuit; ozone; silicon wafer; cleaning	Surfaces and Layers
Abadeer, W. W.; LeBlanc, A.; Kluwe, A.; Schulz, P.; Vollertsen, R.; Penka, V.; Nadahara, S.; Antreasyan, A.; Cote, D.; et al.	Advanced technology processing and state-of-the-art solutions to cleaning, contamination control, and integration problems	Mater. Res. Soc. Symp. Proc.	386	261-26	1995	ULSI processing; advanced technol; cleaning ULSI technol;	Review
Fester, A.; Metz, S.; Mainka, G.; Angelkort, C.; Martin, A. R.; Hermann, H.; Kolbesen, B. O.	TXRF and radiochemical analysis. A comparison of two analytical tools for determination of metal impurities on silicon	Proc. - Electrochem. Soc.	95-30	228-235	1995	silicon; metal impurity detection; TXRF; radiochem; XRF reflection	Surfaces and Layers
Fabry, L.; Pahlke, S.; Kotz, L.	Application of TXRF in silicon wafer manufacturing	Proc. - Electrochem. Soc.	95-30	217-227	1995	TXRF; silicon wafer manuf; reflection XRF analysis; water analysis	Surfaces and Layers
Shibaya, Hiroshi	Behaviour of Cu and Zn impurities on GaAs wafer surfaces	Jpn. J. Appl. Phys., Part 2	34(8A)	L962-L964	1995	surface impurity copper zinc gallium arsenide	Surfaces and Layers
Prange, A.; Reus, U.; Böddeker, H.; Fischer, R.; Adolf, F.-P.	Microanalysis in forensic science: Characterization of single textile fibers by TXRF	Adv. X-Ray Chem. Anal. Jpn.	26s	1-8	1995		Chemical Analysis
Tian, Yuhong; Tan, Jilian; Zheng, Suhua; Wang, Ruiguang; Liu, Kai; Pan, Xiaowen	Study of the total reflection x-ray fluorescence technique	He Dianzixue Yu Tance Jishu	15	265-269	1995	total reflection x-ray fluorescence spectrometry; copper;	Chemical Analysis
Bredendiek-Kämper, S.; von Bohlen, A.; Klockenkämper, R.; Quentmeier, A.; Klockow, D.	Microanalysis of Solid Samples by Laser-Ablation and Total-Reflection Fluorescence	J. Anal. At. Spectrom.	11	537-541	1996	Laser-ablation; TXRF; Solids	Principles and Instrumentation
Yakushiji, Kenji; Mutoh, Arihiro	Total-reflection X-ray fluorescence associated with chemical concentration and its accuracy	X-sen Bunseki no Shinpo	28	195-206	1996	total reflection x-ray fluorescence analysis	Chemical Analysis

Autoren	Titel	Zeitschrift	Vol	Seiten	Jahr	Keywords	Gruppe
Kawai, Kenichi	Current status of TXRF	Hyomen Kagaku	17	592-598	1996	TXRF; x-ray fluorescence spectroscopy	Review
Carvalho, M. L.; Barreiros, M. A.; Costa, M. M.; Ramos, M. T.; Marques, M. I.	Study of heavy metals in Madeira wine by total reflection x-ray fluorescence analysis	X-Ray Spectrom.	25	29-32	1996	Madeira wine; heavy metal	Chemical Analysis
Chang, C. H.; Koo, Y. M.; Padmore, H.	Total reflection x-ray fluorescence spectroscopy using synchrotron radiation for trace impurity analysis of silicon wafer surfaces	Met. Mater. (Seoul)	2	23-29	1996	silicon; surface contamination; x-ray fluorescence	Surfaces and Layers
Mori, Yoshihiro; Sakon, Tadashi; Shimanoe, Kengo	Consideration of some standard samples for total reflection x-ray fluorescence spectrometry	X-sen Bunseki no Shinpo	27	59-70	1996	total reflection x-ray fluorescence	Review
Mori, Yoshihiro; Shimanoe, Kengo	Standard sample preparation for the analysis for several metals on silicon wafer	Anal. Sci.	12	141-143	1996	std; sample preparation; metal detection; silicon; TXRF	Surfaces and Layers
Fabry, L.; Pahlke, S.; Kotz, L.	Accurate calibration of TXRF using microdroplet samples	Fresenius' J. Anal. Chem.	354	266-270	1996	calibration; TXRF; microdroplet sample; oxide layer; silicon analysis	Surfaces and Layers
Wobrauschek, P; Streli, C.; Kregsamer, P.; Ladisich, W.; Rieder, R.	Recent developments in TXRF with various excitation sources	J. Trace Microprobe Tech.	14	103-117	1996	review; TXRF; excitation source; x-ray fluorescence	Review
Cheburkin, A.K.; Shoryk, W.	Double-plate sample carrier for a simple total reflection x-ray fluorescence analyzer	X-Ray Spectrom.	25	175-178	1996	double plate sample carrier; TXRF spectrometer	Principles and Instrumentation
Wagner, M.; Rostam-Khani, P.; Wittershagen, A.; Rittmeyer, C.; Hoffmann, H.; Kolbesen, B. O.	Application of total reflection x-ray fluorescence spectrometry (TXRF) to trace element determination in pharmaceutical substances. Part 1	Pharmazie	51	865-868	1996	x-ray fluorescence total reflection pharmaceutical; trace metal drug x-	Chemical Analysis
Härtel, R.; Vehlow, J.; Schneider, J.	Pretreatment of special samples from waste incineration for analysis by total reflection x-ray fluorescence	Spectrochim. Acta Part B	51	1647-1653	1996	incineration waste analysis sample pretreatment	Chemical Analysis

Autoren	Titel	Zeitschrift	Vol	Seiten	Jahr	Keywords	Gruppe
Torboli, A.; Zanetti, C.	Applications of total x-ray reflection fluorescence (TXRF)	Lab. 2000	10(2)	24-27	1996	review x-ray reflection fluorescence	Review
Jin, Liyun; Huang, Qingliang; Li, Yun; Yuan, Hui; Gao, Hong	Development of total-reflection x-ray fluorescence analysis equipment with detection limits of subnanogram level	He Huaxue Yu Fangshe Huaxue	18	152-157	1996	total reflection x-ray fluorescence analyzer	Principles and Instrumentation
Viksna, A.; Selin, E.	Intercomparison between energy dispersive and total reflection x-ray fluorescence in whole blood analysis	J. Trace Microprobe Tech.	14	763-774	1996	energy dispersive reflection; x-ray fluorescence; blood analysis	Chemical Analysis
Ebert, Martin; Dahmen, Joachim; Ortner, Hugo M.; Hoffmann, Peter	Determination of the chemical composition of clean room particles by total reflection x-ray fluorescence analysis (TXRF) and electron probe microanalysis (EPMA)	GIT Fachz. Lab.	40(10)	982-986	1996	aerosol; clean room; electron probe microanalysis; x-ray fluorescence aerosol	Chemical Analysis
Klockenkämper, R.; von Bohlen, A.	Elemental Analysis of Environmental Samples by Total Reflection X-Ray Fluorescence: a Review	X-Ray Spectrom.	25	156-162	1996	TXRF; Environmental samples; Biological materials	Review
Carney, G. F.; Briehl, B.; Lu, S.; Anderson, T. A.; Evans, K. L.	Process tool qualification and problem solving using SIMS, TXRF and ICP-MS	Proc. - Inst. Environ. Sci.	42nd	152-159	1996	semiconductor device; manuf contaminant analysis; SIMS; x-	Surfaces and Layers
Lahatra Razafindramisa, F.; Andriambololona, R.; Brunel, M.; Van Grieken, R.	Analysis of medicinal herbs by total reflection x-ray fluorescence	J. Phys. IV	6	C4/833-C4/842	1996	analysis medicinal herb; reflection x-ray fluorescence	Chemical Analysis
Pasti, F.; Torboli, A.; Zanetti, C.; Marchi, M.	A new method for the determination of S, V, Fe, Ni, Pb and other elements in some distilled fractions of crude petroleum by TXRF	J. Phys. IV	6	C4/627-C4/633	1996	trace element detection; petroleum product; gasoline; TXRF; diesel fuel;	Chemical Analysis
Fabry, L.; Pahlke, S.; Kotz, L.	Application of TXRF in silicon wafer manufacturing	X-sen Bunseki no Shinpo	27	345-353	1996	review; silicon wafer manufg spectrochem analysis; x-ray	Review
Schwenke, H.; Knoth, J.; Guenther, R.; Wiener, G.; Bormann, R.	A new technique for depth profiling on a nanometer scale	Mater. Res. Soc. Symp. Proc.	405	407-412	1996	depth profiling nanometer scale; ion beam sputtering; x-ray fluorescence	Principles and Instrumentation

Autoren	Titel	Zeitschrift	Vol	Seiten	Jahr	Keywords	Gruppe
Mori, Yoshihiro; Shimanoe, Kengo	Study of depth distribution shift of copper on silicon wafer surface using total reflection x-ray fluorescence spectrometry	Anal. Sci.	12	277-279	1996	depth distribution shift; copper; silicon wafer	Surfaces and Layers
Diebold, A.C.	Calibration issues for total reflection x-ray fluorescence analysis of surface metallic contamination on silicon	J. Vac. Sci. Technol., A	14(3, Pt. 2)	1919-1923	1996	calibration issue; reflection x-ray fluorescence; surface metallic	Surfaces and Layers
Günther, K.; Xie, M.Y.; Ma, Y.H.; von Bohlen, A.; Messerschmidt, J.	Selen-Tees: Eine Möglichkeit zur praktischen Selen-Versorgung der Bevölkerung in Mangelregionen dieser Erde	Lebensmittelchemie	50	10-11	1996	TXRF; Chinese tea	Chemical Analysis
Devos, W.; Moens, L.; von Bohlen, A.; Klockenkämper, R.	Q-tips and old masters, ultra-micro analysis of artists´ pigments by total reflection X-ray fluorescence analysis	in: Archaeometry 94 (Ankara)		243-251	1996	TXRF; Pigments; Microanalysis	Chemical Analysis
Van Kan, J. A.; Vis, R. D.	Trace element analysis in an optimized set-up for total reflection PIXE (TPIXE)	Int. J. PIXE	6	89-96	1996	trace element detection optimized setup TPIXE; surface analysis	Related Methods
Lavoie, M. A.; Adams, E. D.; Miles, G. L.	Total reflection x-ray fluorescence analysis of planarized semiconductor product wafers	J. Vac. Sci. Technol., A	14(3, Pt. 2)	1924-1926	1996	x-ray fluorescence; planarized semiconductor; wafer	Surfaces and Layers
Kump, P.; Necemer, M.; Snajder, J.	Determination of trace elements in bee honey, pollen and tissue by total reflection and radioisotope x-ray fluorescence spectrometry	Spectrochim. Acta Part B	51	499-507	1996	trace element detection; bee honey; pollen; fluorescence	Chemical Analysis
Leenaers, A.J.G.; de Boer, D.K.G.		Spectroscopy	8	14-20	1996		Review
Pettersson, R. P.; Boman, J.	A total-reflection x-ray fluorescence spectrometer using a rotating anode	Nucl. Instrum. Methods Phys. Res., Sect. A	371	553-559	1996	x-ray fluorescence spectrometer; biochem analysis; plankton analysis;	Principles and Instrumentation
Günther, R.; Wiener, G.; Knoth, J.; Schwenke, H.; Bormann, R.	Determination of concentration depth profiles using total-reflection X-ray fluorescence spectrometry in combination with ion-beam etching	Rev. Sci. Instrum.	67	2332-2336	1996	Depth profiling; Sputter-etching	Surfaces and Layers

Autoren	Titel	Zeitschrift	Vol	Seiten	Jahr	Keywords	Gruppe
Török, S.B.; Labar, J.; Injuk, J.; Van Grieken, R.E.	X-ray spectrometry	Anal. Chem.	68	467R-485R	1996		Review
Hall, L. H.; Sees, J. A.; Schmidt, B. L.	Characterization and application of the vapor phase decomposition technique for trace metal analysis on silicon oxide surfaces	Surf. Interface Anal.	24	511-516	1996	vapor decomposition; trace metal detection; silicon oxide surface	Surfaces and Layers
de Bokx, P.K.; Kok, Chr.; Bailleul, A.; Wiener, G.; Urbach, H.P.	Grazing-emission X-ray fluorescence spectrometry; principles and applications	Spectrochim. Acta Part B	52	829-840	1997	Energy-dispersive detection; GEXRF; Wavelength-dispersive detection	Surfaces and Layers
Tsuji, K.; Wagatsuma, K.; Hirokawa, K.; Yamada, T.; Utaka, T.	Development of glancing-incidence and glancing-take-off X-ray fluorescence apparatus for surface and thin-film analyses	Spectrochim. Acta Part B	52	841-846	1997	Total reflection X-ray fluorescence; Surface analysis; Surface density	Surfaces and Layers
van Kan, J.A.; Vis, R.D.	An optimized set-up for total reflection particle induced X-ray emission	Spectrochim. Acta Part B	52	847-853	1997	Glancing incidence; Large solid angle; Total reflection PIXE; Ultra-trace	Surfaces and Layers
Tsuji, K.; Wagatsuma, K.; Hirokawa, K.	Characteristics of total reflection X-ray excited current detected with the tip of a scanning tunneling microscope	Spectrochim. Acta Part B	52	855-860	1997	Scanning tunneling microscope; Total reflection; X-ray excited current; XRF	Related Methods
Streli, C.; Wobrauschek, P.; Bauer, V.; Kregsamer, P.; Görgl, R.; Pianetta, P.; Ryon, R.; Pahlke, S.; Fabry, L.	Total reflection X-ray fluorescence analysis of light elements with synchrotron radiation and special X-ray tubes	Spectrochim. Acta Part B	52	861-872	1997	TXRF; EDXRF; Synchrotron radiation; Light elements	Surfaces and Layers
Schwenke, H.; Knoth, J.; Fabry, L.; Pahlke, S.; Scholz, R.; Frey, L.	Measurement of Shallow Arsenic Impurity Profiles in Semiconductor Silicon Using Time-of-Flight Secondary Ion Mass Spectrometry and Total Reflection X-Ray Fluorescence	J. Electrochem. Soc.	144	3979-3983	1997	ToF-SIMS; Arsenic implantation; depth profiles	Surfaces and Layers
Brown, D.R.; Qin, K.; Herms, J.W.; Madlung, A.; Manson, J.; Strome, R.; Fraser, P.E.; Kruck, T.; von Bohlen, A.; Schulz-Schaeffer, W.; Giese, A.;	The cellular prion protein binds copper in vivo	Nature	390, 18/35	684-687	1997	prion proteins, copper, TXRF, medicine	Chemical Analysis
Schwenke, H.; Knoth, J.; Günther, R.; Wiener, G.; Bormann, R.	Depth profiling using total reflection X-ray fluorescence spectrometry alone and in combination with ion beam sputtering	Spectrochim. Acta Part B	52	795-803	1997	Depth profiling; Ion beam sputtering; Surface analysis; TXRF	Surfaces and Layers

Autoren	Titel	Zeitschrift	Vol	Seiten	Jahr	Keywords	Gruppe
Krivan, V.; Theimer, K.-H.	Trace characterization of high-purity Mo and W by ET-AAS, ICP-AES; ICP-MS and TXRF involving analyte-matrix separation	Spectrochim. Acta Part B	52	2061-2076	1997	ETAAS; ICP-AES; ICP-MS; Matrix separation; Mo; Trace analysis;	Chemical Analysis
Yao, Z.H.	Total reflection angle X-ray microanalysis of microdroplets in SEM	J. Trace and Microprobe Techniques	15	683-686	1997	microdroplet; total-reflection X-ray microanalysis; scanning electron	Related Methods
Kondo, N.; Ota, N.; Nakai, I.; Sasaki, A.	Synchrotron radiation-induced total-reflection X-ray fluorescence analysis of Cu and Zn in carcinoma tissues obtained by a biopsy	Bunseki Kagaku	46	957-964	1997	synchrotron radiation; TXRF; biopsy; trace elements; clinical	Related Methods
Werho, D.; Gregory, R.; Schauer, S.; Liu, X.; Carney, G.; Banks, J.; Knapp, J.; Doyle, B.; Diebold, A.C.	Calibration of reference materials for total-reflection X-ray fluorescence analysis by heavy ion backscattering spectrometry	Spectrochim. Acta Part B	52	881-886	1997	Ion backscattering (IBS); Reference material; TXRF	Surfaces and Layers
Funahashi, M.; Utaka, T.; Arai, T.	Improvement of Total reflection X-ray fluorescence (TXRF) spectrochemical analysis for silicon wafers	Spectrochim. Acta Part B	52	887-899	1997	TXRF; Surface analysis; Silicon wafers; Contamination of	Surfaces and Layers
Wobrauschek, P.; Görgl, R.; Kregsamer, P.; Streli, C.; Pahlke, S.; Fabry, L.; Haller, M.; Knöchel, A.; Radtke, M.	Analysis of Ni on Si-wafer surfaces using synchrotron radiation excited total reflection X-ray fluorescence analysis	Spectrochim. Acta Part B	52	901-906	1997	Total reflection; XRF; Synchrotron radiation; Wafer analysis	Surfaces and Layers
Kawai, J.; Amano, H.; Hayashi, K.; Horiuchi, T.;. Matsushige, K.; Kitajima, Y.	Total reflection X-ray photoelectron spectroscopy of copper phthalocyanine gold multilayers	Spectrochim. Acta Part B	52	873-879	1997	Surface analysis; Surface layer analysis; X-ray photoelectron	Surfaces and Layers
Schmeling, M.; Klockenkämper, R.; Klockow, D.	Application of total-reflection X-ray fluorescence spectrometry to the analysis of airborne particulate matter	Spectrochim. Acta Part B	52	985-994	1997	Airborne particulate matter; Blank values; Impaction; Memory effects;	Chemical Analysis
Vilhunen, J.K.; von Bohlen, A.; Schmeling, M.; Klockenkämper, R.;. Klockow, D.	Total reflection X-ray fluorescence analyses of samples from oil refining and chemical industries	Spectrochim. Acta Part B	52	953-959	1997	Diesel emission particles; Phenol; TXRF; Urea	Chemical Analysis
Hockett, R.S.		Adv. X-Ray Anal.	39	767-769	1997		Surfaces and Layers

Autoren	Titel	Zeitschrift	Vol	Seiten	Jahr	Keywords	Gruppe
Wobrauschek, P.; Kregsamer, P.; Ladisich, W.; Rieder, R.; Streli, C.; Garbe, S.; Haller, M.; Radtke, M.	TXRF - sources - samples and detectors	Adv. X-Ray Anal.	39	755-763	1997	surface analysis; XRF total reflection;	Principles and Instrumentation
von Bohlen, A.; Meyer, F.	Microanalysis of old violin varnishes by total-reflection X-ray fluorescence	Spectrochim. Acta Part B	52	1053-56	1997	TXRF; Violin varnish; Musical instruments	Chemical Analysis
Holynska, B.; Ptasinski, J.; Maenhaut, W.; Annegarn, H.J.	Energy-dispersive X-ray fluorescence spectrometer with capillary optics for the chemical analysis of atmospheric aerosols with high time resolution	J. Aerosol. Sci.	28	1455-1463	1997	EDXRF; atmospheric aerosols; capillary optics; particulate	not TXRF, Aerosols
Injuk, J.; Van Grieken, R.; Klockenkämper, R.; von Bohlen, A.; Kump, P.	Performance and characteristics of two total-reflection X-ray fluorescence and a particle induced X-ray emission setup for aerosol analysis	Spectrochim. Acta Part B	52	977-984	1997	Aerosol; Detection limit; PIXE; TXRF	Chemical Analysis
Kerminen, V.-M.; Mäkelä, T.E.; Ottoson, C.H.; Hillamo, R.E.; Vilhunen, J.K.; Rantanen, L.; Havers, N.; von Bohlen, A..; Klockow, D.	Characterization of the particulate phase from a Diesel car exhaust	Environ. Sci. Technol.	31	1883-1889	1997	Diesel; Particles; Exhaust; TXRF; Carbon	Chemical Analysis
Klockenkämper, R.	Total-Reflection X-Ray Fluorescence Analysis	Monographie Wiley			1997	TXRF; Principles; Applications	Review
Mori, Y.; Kenichi Uemura; Kengo Shimanoe	A depth profile fitting model for a commercial total reflection X-ray fluorescence spectrometer	Spectrochim. Acta Part B	52	823-828	1997	TXRF; Depth profiling; Surface contamination; Surface analysis;	Surfaces and Layers
Schmeling, M.; Alt, F.; Klockenkämper, R.; Klockow, D.	Multielement analysis by total reflection X-ray fluorescence spectrometry for the certification of lichen research material	Fresenius' J. Anal. Chem.	357	1042-1044	1997	TXRF; Lichen; Reference materials	Chemical Analysis
Pérez, R.E.; Sánchez, H.J.	New spectrometer for grazing exit x-ray fluorescence	Rev. Sci. Instrum.	68	2681-2683	1997	Grazing exit, Surface analysis	Related Methods
Schmeling, M.; Klockow, D.	Sample collection and Preparation for analysis of airborne particulate matter by total reflection X-ray fluorescence spectrometry	Anal. Chim. Acta	346	121-126	1997	Airborne particulate matter; Blank values; Impaction; Memory effects;	Chemical Analysis

Autoren	Titel	Zeitschrift	Vol	Seiten	Jahr	Keywords	Gruppe
Barreiros, M.A.; Carvalho, M.L.; Costa, M.M.; Marques, M.I.; Ramos, M.T.	Application of Total Reflection XRF to Elemental Studies of Drinking Water	X-Ray Spectrom.	26	165-168	1997		Chemical Analysis
Görgl, R.; Wobrauschek, P.; Kregsamer, P.; Streli, C.; Haller, M.; Knöchel, A.; Radtke, M.	Total Reflection X-Ray Fluorescence Analysis Excited by Synchrotron Radiation (SR-TXRF): Variation of Excitation Conditions and Sample Geometries	X-Ray Spectrom.	26	189-194	1997		Principles and Instrumentation
Bernasconi, G.; Dargie, M.; Jaib, M.M.; Tajani, A.	Total Reflection X-Ray Fluorescence Analysis Under Various Experimental Conditions	X-Ray Spectrom.	26	203-210	1997		Principles and Instrumentation
Kump, P.; Necemer, M.; Veber, M.	Determination of Trace Elements in Mineral Water Using Total Reflection X-Ray Fluorescence Spectrometry after Preconcentration with Ammonium	X-Ray Spectrom.	26	232-236	1997		Chemical Analysis
Leenaers, A.J.G.; Vrakking, J.J.A.M.; de Boer, D.K.G.	Glancing incidence X-ray analysis: more than just reflectivity!	Spectrochim. Acta Part B	52	805-812	1997	Depth profiling; Diffuse scattering; Thin layer; X-ray fluorescence; X-ray	Surfaces and Layers
Knoth, J.; Prange, A.; Schneider, H.; Schwenke, H.	Variable X-ray excitation for total reflection X-ray fluorescence spectrometry using an Mo/W alloy anode and a tunable double multilayer monochromator	Spectrochim. Acta Part B	52	907-913	1997	Mo/W alloy anode; Multilayer monochromator; TXRF; Variable	Principles and Instrumentation
Wiener, G.; Günther, R.; Michaelsen, C.; Knoth, J.; Schwenke, H.; Bormann, R.	Ion beam sputtering for high-resolution concentration depth profiling with glancing-incidence X-ray fluorescence spectrometry	Spectrochim. Acta Part B	52	813-821	1997	Depth profiling; Ion beam sputtering; Surface analysis; Thin layer; X-ray	Surfaces and Layers
Messerschmidt, J.; von Bohlen, A.; Alt, F.; Klockenkämper; R.	Determination of Arsenic and Bismuth in Biological Samples by Total-Reflection X-Ray Fluorescence after Separation and Collection of Their Hydrides	J. Anal. At. Spectrom.	12	1251-1254	1997	Arsenic; Bismuth; Hydride generation; TXRF; Biological materials	Chemical Analysis
Bernasconi, G.; Dargie, M.; Jaib, M. M.; Tajani, A.	Total reflection x-ray fluorescence analysis under various experimental conditions	X-Ray Spectrom.	26	203-210	1997	element detection; reflection x-ray fluorescence	Principles and Instrumentation
von Czarnowski, D.; Denkhaus, E.; Lemke, K.	Determination of trace element distribution in cancerous and normal human tissues by total reflection X-ray fluorescence analysis	Spectrochim. Acta Part B	52	1047-1052	1997	Carcinoma; Colon; Rectum; Stomach; Microtome section; TXRF; Trace	Chemical Analysis

Autoren	Titel	Zeitschrift	Vol	Seiten	Jahr	Keywords	Gruppe
Wegstein, M.; Urban, H.; Rostam-Khani, P.; Wittershagen, A.; Kolbesen, B.O.	Total-reflection X-ray fluorescence spectrometry, a powerful tool for semiquantitative analysis of archaeological glass samples	Spectrochim. Acta Part B	52	1057-1061	1997	Archaeological sample; Glass corrosion; Non-destructive	Chemical Analysis
Claes, M.; de Bokx, P.; Willard, N.; Veny, P.; Van Grieken, R.	Optimization of sample preparation for grazing emission X-ray fluorescence in micro- and trace analysis applications	Spectrochim. Acta Part B	52	1063-1070	1997	Grazing emission X-ray fluorescence; Polycarbonate; Sample preparation	Related Methods
Smith, S.P.; Metz, J.	Understanding the correlation of surface SIMS and TXRE measurements of surface metal contamination on silicon wafers	Mater. Res. Soc. Symp. Proc.	477	305-310	1997	SIMS; TXRE; metal contamination detection; silicon	Surfaces and Layers
Tian, Yuhong; Liu, Kai; Zheng, Suhua; Wang, Ruiguang; Zhang, Yuhui	Application of TXRF analysis technique	Hejishu	20	1-5	1997	total reflection x-ray fluorescence	Review
Fischer-Colbrie, A.; Laderman, S. S.; Brennan, S.; Ghosh, S.; Takaura, N.; Pianetta, P.; Shimazaki, A.; Waldhauer, A.; Wherry, D.; Barkan, S	State-of-the-art evaluation of ultra-clean ULSI processes	Mater. Res. Soc. Symp. Proc.	477	403-407	1997	integrated circuit; surface; trace metal analysis	Surfaces and Layers
De Gendt, S.; Kenis, K.; Baeyens, M.; Mertens, P. W.; Heyns, M. M.; Wiener, G.; Kidd, S. J.; Knotter, D. M.; De Bokx, P. K.	Silicon surface metal contamination measurements using grazing-emission XRF spectrometry	Mater. Res. Soc. Symp. Proc.	477	397-402	1997	silicon surface metal contamination; XRF spectrometry; grazing emission	Surfaces and Layers
Beck, S.E.; Gilicinski, A.G.	Avoiding the pitfalls of surface analysis	Solid State Technol.	40(10)	169-170, 172, 174, 176, 178	1997	pitfall; surface spectroscopy analysis	Surfaces and Layers
Weiss, C.A.; Hossain, T.Z.; Zschech, E.; Macdonald, B.J.	Rapid in-fab monitoring of ion implant doses using total reflection	Proc. SPIE-Int. Soc. Opt. Eng.	3215	128-136	1997	ion implantation dose detection; TXRF	Surfaces and Layers
Aiginger, H.; Streli, C.	Total reflection x-ray fluorescence spectrometry (TXRF) for trace element analysis	Spectrosc. Eur.	9	16,18,20-22	1997	total reflection x-ray fluorescence; trace element x-ray fluorescence	Review
Benninghoff, L.; von Czarnowski, D.; Denkhaus, E.; Lemke, K.	Analysis of human tissues by total reflection X-ray fluorescence. Application of chemotrics for diagnostic cancer recognition	Spectrochim. Acta Part B	52	1039-1046	1997	Carcinoma; colon; Cluster analysis; Pressure digestion; Three-way principal	Chemical Analysis

Autoren	Titel	Zeitschrift	Vol	Seiten	Jahr	Keywords	Gruppe
Metz, S.; Kilian, G.; Mainka, G.; Angelkort, C.; Fester, A.; Kolbesen, B.O.	VPD-DSE-studies of metal impurities on silicon: a comparison of TXRF and radiochemical analysis	Proc. - Electrochem. Soc.	97-22	458-467	1997	iron impurity silicon surface TXRF; total reflection XRF metal impurity silicon; x-	Chemical Analysis
Csato, I.; Zaray, Gy.; Gal-Solymos, K.; Hassler, J.	Direct analysis of silicon carbide powder by total reflection x-ray fluorescence spectrometry	Appl. Spectrosc.	51	1067-1072	1997	silicon carbide analysis; x-ray fluorescence	Chemical Analysis
Görgl, R.; Wobrauschek, P.; Kregsamer, P.; Streli, Ch.; Haller, M.; Knöchel, A.; Radtke, M.	Total reflection x-ray fluorescence analysis excited by synchrotron radiation (SR-TXRF): variation of excitation conditions and sample geometries	X-Ray Spectrom.	26	189-194	1997	total reflection x-ray fluorescence analysis	Principles and Instrumentation
Tian, Y. H.; Liu, K.; Wu, X. R.; Wang, R. G.	A small TXRF analyzer and its applications	J. Radioanal. Nucl. Chem.	217	243-245	1997	total reflection x-ray fluorescence spectrometer; tap water total reflection	Chemical Analysis
Kump, P.; Necemer, M.; Veber, M.	Determination of trace elements in mineral water using total reflection x-ray fluorescence spectrometry after preconcentration with ammonium pyrrolidinedithiocarbamate	X-Ray Spectrom.	26	232-236	1997	trace element detection; mineral water; total reflection x-ray fluorescence	Chemical Analysis
Dargie, M.; Markowicz, A.; Tajani, A.; Valkovic, V.	Optimized sample preparation procedures for analysis of solid materials by total-reflection XRF	Fresenius' J. Anal. Chem.	357	589-593	1997	solid total reflection XRF sample preparation; x-ray fluorescence solid	Chemical Analysis
Tsuji, Kouichi; Wagatsuma, Kazuaki; Oku, Takeo	Experimental evaluation of the Mo K-alpha. X-ray probing depth for a GaAs wafer in a total-reflection x-ray fluorescence analysis	Anal. Sci.	13	351-354	1997	probing depth; x-ray fluorescence; gallium arsenide; reflection x-ray	Surfaces and Layers
Streli, C.	Total reflection x-ray fluorescence analysis of light elements	Spectrochim. Acta Part B	52	281-293	1997	total reflection XRF; light element	Review
Simmross, U.; Fischer, R.; Duwel, F.; Muller, U.	Quantitative determination of cadmium in polyethylene using total reflection x-ray fluorescence (TXRF) spectroscopy	Fresenius' J. Anal. Chem.	358	541-545	1997	cadmium; polyethylene; reflection x-ray fluorescence	Chemical Analysis
Gasparics, T.; Csato, I.; Zaray, Gy	Analysis of Antarctic marine sediment by inductively coupled plasma atomic emission and total reflection x-ray fluorescence spectrometry	Microchem. J.	55	56-63	1997	heavy metal detection; sediment; Antarctica	Chemical Analysis

Autoren	Titel	Zeitschrift	Vol	Seiten	Jahr	Keywords	Gruppe
Wobrauschek, P.; Streli, C.	Total reflection x-ray fluorescence analysis with synchrotron radiation and other sources for trace element determination	AIP Conf. Proc.	389	233-247	1997	trace analysis reflection x-ray fluorescence	Principles and Instrumentation
Hoffmann, P.; Karandashev, V. K.; Sinner, T.; Ortner, H. M.	Chemical analysis of rain and snow samples from Chernogolovka/Russia by IC, TXRF, and ICP-MS	Fresenius' J. Anal. Chem.	357	1142-1148	1997	rain; snow; environment pollution; Chernogolovka	Chemical Analysis
Bennun, L.; Gomez, J.	Determination of mercury by total-reflection x-ray fluorescence using amalgamation with gold	Spectrochim. Acta Part B	52	1195-1200	1997	mercury detection; x-ray fluorescence; amalgamation gold	Chemical Analysis
Aster, B.; von Bohlen, A.; Burba, P.	Determination of metals and their species in aquatic humic substances by using total-reflection X-ray fluorescence spectrometry	Spectrochim. Acta Part B	52	1009-1018	1997	Aquatic humic substances; Lability; Metal species; Size fractionation; TXRF	Chemical Analysis
Wagner, M.; Rostam-Khani, P.; Wittershagen, A.; Rittmeyer, C.; Kolbesen, B.O.; Hoffmann, H.	Trace element determination in drugs by total-reflection X-ray fluorescence spectrometry	Spectrochim. Acta Part B	52	961-965	1997	Element fingerprint; Insulin; Pharmaceutics; TXRF; Tryptophan	Chemical Analysis
Wittershagen, A.; Rostam-Khani, P.; Klimmek, O.; Groß, R.; Zickermann, V.; Zickermann, I.; Gemeinhardt, S.; Kröger, A.; Ludwig, B.; Kolbesen, B.O.	Determination of metal-cofactors in enzyme complexes by total-reflection X-ray fluorescence spectrometry	Spectrochim. Acta Part B	52	1033-1038	1997	TXRF; Metal-cofactors; Enzymatic samples	Chemical Analysis
Haffer, E.; Schmidt, D.; Freimann, P.; Gerwinski, W.	Simultaneous determination of germanium, arsenic, tin and antimony with total-reflection X-ray fluorescence spectrometry using the hydride generation technique for matrix separation - first	Spectrochim. Acta Part B	52	935-944	1997	Hydride generation technique; Decomposition of hydrides; Matrix	Chemical Analysis
Stahlschmidt, T.; Schulz, M.; Dannecker, W.	Application of total-reflection X-ray fluorescence for the determination of lead, calcium and zinc in size-fractionated marine aerosols	Spectrochim. Acta Part B	52	995-1001	1997	Atmospheric aerosol; Impactor; Short-time measurement; Size	Chemical Analysis
Greaves, E.D.; Alfonso Sosa, J.; Sajo-Bohus, L.; Alvarez, M.; Wobrauschek, P.; Streli, C.	Trace element determination of mercury by total-reflection X-ray fluorescence	Spectrochim. Acta Part B	52	945-951	1997	Amalgam; Mercury; Trace analysis; TXRF	Chemical Analysis
Greaves, E.D.; Bernasconi, G.; Wobrauschek, P.; Streli, C.	Direct total-reflection X-ray fluorescence trace element analysis of organic matrix materials with a semiempirical standard	Spectrochim. Acta Part B	52	923-933	1997	Organic sample; Semiempirical standard model; TXRF; Trace	Chemical Analysis

Autoren	Titel	Zeitschrift	Vol	Seiten	Jahr	Keywords	Gruppe
Friese, K.; Mages, M.;. Wendt-Potthoff, K.; Neu, T.R.	Determination of heavy metals in biofilms from the River Elbe by total-reflection X-ray fluorescence spectrometry	Spectrochim. Acta Part B	52	1019-1025	1997	Aquatic biofilms; Heavy metals; River water quality; TXRF	Chemical Analysis
Varga, A.; Zaray, Gy.; Fodor, F.; Cseh, E.	Study of interaction of iron and lead during their uptake process in wheat roots by total-reflection X-ray fluorescence spectrometry	Spectrochim. Acta Part B	52	1027-1032	1997	Iron; Lead; Wheat; Uptake	Chemical Analysis
Ebert, M.; Dahmen, J.; Hoffmann, P.; Ortner, H.M.	Examination of clean room aerosol particle composition by total reflection X-ray analysis and electron probe microanalysis	Spectrochim. Acta Part B	52	967-975	1997	TXRF; Clean room; Impactor; Quality control	Chemical Analysis
Liu, Yawen; Fan, Qinmin; Wu, Yingrong; Wei, Chenglian; Xiao, Hui	Three-dimensional microanalysis of arsenic impurity in silicon	Guangpuxue Yu Guangpu Fenxi	17(4)	96-99	1997	three dimensional microanalysis; arsenic impurity; silicon; synchrotron	Surfaces and Layers
Wegrzynek, D.; Holynska, B.	Fundamental quantification procedure for total reflection X-ray fluorescence spectra analysis and elements determination	Spectrochim. Acta Part B	52	915-921	1997	TXRF; X-ray spectra fitting	Principles and Instrumentation
Miesbauer, H.	Multielement determination in sediments, pore water and river water of Upper Austrian rivers by total-reflection X-ray fluorescence	Spectrochim. Acta Part B	52	1003-1007	1997	Multielement determination; Pore water; River water; Sediments; TXRF	Chemical Analysis
Werho, D.; Gregory, R.B.; Schauer, S.N.; Liu, X.; Carney, G.F.; Banks, J.C.; Knapp, J.A.; Doyle, B.L.; Diebold, A.C.	Heavy ion backscattering spectrometry analysis of TXRF calibration standards	Adv. X-Ray Anal.	40	37-47	1998	heavy ion backscattering spectrometry; TXRF; calibration	Chemical Analysis
Pahlke, S.; Kotz, L.; Ehmann, T.; Eichinger, P.; Huber, A.	WSPS: wafer surface preparation system. A novel modular automated method capable of the ultratrace analytical inspection of 300 MM silicon wafer surfaces	Proc. - Electrochem. Soc.	98-1	1524-1540	1998	wafer surface prepn system; silicon wafer surface analysis; TXRF	Surfaces and Layers
Yamaguchi, H.; Itoh, S.; Igarashi, S.; Naitoh, K.; Hasegawa, R.	TXRF analysis of solution samples using polyester film as a disposable sample-carrier cover	Anal. Sci.	14	909-912	1998	TXRF; solution; polyester sample carrier cover	Chemical Analysis
De Bokx, P. K.; Kidd, S. J.; Wiener, G.; Urbach, H.P.; De Gendt, S.; Mertens, P.W.; Heyns, M.M.	Grazing-emission x-ray fluorescence spectrometry: a novel tool for surface contamination analysis and thin film metrology	Proc. - Electrochem. Soc.	98-1	1511-1523	1998	grazing emission x ray fluorescence spectrometry; surface analysis;	Related Methods

Autoren	Titel	Zeitschrift	Vol	Seiten	Jahr	Keywords	Gruppe
Wu, W.L.; Wallace, W.L.	Microroughness of polymer thin films studied by total-reflection x-ray fluorescence and atomic force microscopy	J. Vac. Sci. Technol., B	16	1958-1963	1998	polymer characterization; atomic force microscopy;	Surfaces and Layers
Xie, M.Y.; von Bohlen, A.; Klockenkämper, R.; Jian, X.H.; Günther, K.	Multielement Analysis of Chinese Tea (Camellia Sinensis) by Total-Reflection X-Ray Fluorescence	Z Lebensm Unters Forsch A	207	31-38	1998	TXRF; Camellia sinensis; Selenium; Tea infusions; Tea leaves	Chemical Analysis
Ellis, A.T.; Holmes, M.; Kregsamer, P.; Potts, P.J.; Streli, C.; West, M.; Wobrauschek, P.	Atomic spectrometry update-X-ray fluorescence spectrometry	J. Anal. At. Spectrom.	13	209R-232R	1998	review; x-ray fluorescence spectrometry	Review
Savage, I.; Haswell, S. J.	Multivariate experimental methodology for the evaluation of sample preparation techniques used in simultaneous multielemental analysis using total reflection x-ray fluorescence	Anal. Chim. Acta	376	145-151	1998	multivariate methodology; sample preparation; multielemental	Chemical Analysis
Mori, Y.; Kubota, K.; Shimanoe, K.; Sakon, T.	Accuracy of Total Reflection X-ray Fluorescence Spectrometry near the Detection Limit	Anal. Sci.	14	275-280	1998		Chmical Analysis
Neidhart, B.; Knoth, J.; Schwenke, H.	The potential of TXRF as a primary method in chemical metrology	Accred Qual Assur	3	470-472	1998	TXRF; metrology	Principles and Instrumentation
Wittershagen, A.; Rostam-Khani, P.; Zickermann, V.; Zickermann, I.; Gemeinhardt, S.; Ludwig, B.; Kolbesen, B. O.	Determination of metal-cofactors in respiratory chain complexes by total-reflection x-ray fluorescence spectrometry TXRF	Fresenius' J. Anal. Chem.	361	326-328	1998	enzyme; metal; x ray fluorescence spectrometry; respiratory chain;	Chemical Analysis
Trabuc, R.; Llug, Ph.; Bienvenu, Ph.	Analyse d´eaux radioactives d´un condenseur de réacteur nucléaire par spectrométrie de fluorescence X à réflexion totale (TXRF), dans un laboratoire en zone surveilllée sans	J. Phys. IV France	8	351-358	1998	Waste water; Radioactive water; Micro-analysis	Chemical Analysis
Ortega, L.; Comin, F.; Formoso, V.; Stierle, A.	Trace element analysis on Si wafer surfaces by TXRF at ID32 ESRF undulator beamline	J. Synchrotron Radiat.	5	1064-1066	1998	trace element; silicon; surface; TXRF	Related Methods
Savage, I.; Haswell, S.J.	The development of analytical methodology for simultaneous trace elemental analysis of blood plasma samples using total reflection X-ray fluorescence spectrometry	J. Anal. At. Spectrom.	13	1119-1122	1998	Blood plasma; Matrix decomposition	Chemical Analysis

Autoren	Titel	Zeitschrift	Vol	Seiten	Jahr	Keywords	Gruppe
Lofthouse, S.D.; Greenway, G.M.; Stephen, S.C.	Comparison of inductively coupled plasma mass spectrometry with a microconcentric nebulizer and total reflection X-ray spectrometry for the analysis of small liquid volume samples	J. Anal. At. Spectrom.	13	1333-1335	1998	ICP-MS; Small volume samples; Comparison	Chemical Analysis
Streli, C.; Wobrauschek, P.; Kregsamer, P.	Synchrotronstrahlungsinduzierte Totalreflexions-Röntgenfluoreszenzanalyse	Österreichische Physikalische Gesellschaft, Mitteilungsblätter	3		1998		Review
Werho, D.; Wetteroth, T.; Schauer, S.N.; Carney, G.F.	Particulate contamination from TXRF instrumentation	Adv. X-Ray Anal.	40	48-55	1998	particulate contamination; TXRF instrumentation	Chemical Analysis
Adams, F.; Janssens, K.; Snigirev, A.	Microscopic X-ray fluorescence analysis and related methods with laboratory and synchrotron radiation sources	J. Anal. At. Spectrom.	13	319-331	1998	Microprobe; X-ray fluorescence; synchrotron radiation; air	Related Methods
Wegrzynek, D.; Holynska, B.; Ostachowicz, B.	A comparison of the performance of a fundamental parameter method for analysis of total reflection X-ray fluorescence spectra and determination of trace elements, versus an	Spectrochim. Acta Part B	53	43-48	1998	TXRF; Trace element determination; Spectra fitting;	Chemical Analysis
Wu, Yingrong; Pan, Juxiang; Zhao, Limin; Li, uangcheng; Huang, Yuying	Total reflection x-ray fluorescence experiments excited by synchrotron radiation	Guangpu Shiyanshi	15	12-15	1998	total reflection x ray fluorescence analysis; synchrotron radiation	Instrumentation
Pettersson, R.P.	A method for trace element determination of marine periphyton communities on discs of float glass (without sample preparation) using total-reflection X-ray fluorescence spectrometry	Spectrochim. Acta Part B	53	101-115	1998	Trace element analysis; Periphyton; float glass; microalgae;	Chemical Analysis
Wobrauschek, P.	Total reflection X-ray fluorescence spectrometric determination of trace elements in the femtogram region: a survey	J. Anal. At. Spectrom.	13	333-337	1998	XRF; TXRF; Energy-dispersive XRF; Trace element analysis;	Principles and Instrumentation
Wittershagen, A.; Rostam-Khani, P.; Zickermann, V.; Zickermann, I.; Gemainhardt, S.; Ludwig, B.; Kolbesen, B.O.	Determination of metal-cofactors in respiratory chain complexes by total-reflection X-ray fluorescence spectrometry (TXRF)	Fresenius' J. Anal. Chem.	361	326-328	1998	TXRF; metal-cofactor; respiratory chain	Chemical Analysis
Holynska, B.; Olko, M.; Ostachowicz, B.; Ostachowicz, J.; Wegrzynek, D.; Claes, M.; Van Grieken, R.; De Bokx, P.;	Performance of total reflection and grazing emission x-ray fluorescence spectrometry for the determination of trace metals in drinking water in relation to other analytical techniques	Fresenius' J. Anal. Chem.	362	294-298	1998	trace metal; drinking water; TXRF; grazing emission	Chemical Analysis

Autoren	Titel	Zeitschrift	Vol	Seiten	Jahr	Keywords	Gruppe
Van Hooydonk, G.; de Reu, M.; Moens, L.; Van Aelst, J.; Milis, L.	A TXRF and micro-Raman spectrometric reconstruction of palettes for destinguishing between scriptoria of related medieval manuscripts	European J. of Inorganic Chemistry	5	639-644	1998	Manuscripts; Scriptoria; Micro-Raman spectroscopy; Gold	Chemical Analysis
Stoev, K.; Knoth, J.; Schwenke, H.	Optimization of curved x-ray multilayer mirrors for total reflection x-ray fluorescence spectrometry	X-Ray Spectrom.	27	166-172	1998		Principles and Instrumentation
Haswell, S.J.; Walmsley, A.D.	Multivariate data visualisation methods based on multi-elemental analysis of wines and coffees using total reflection X-ray fluorescence analysis	J. Anal. At. Spectrom.	13	131-134	1998	multi-elemental analysis; TXRF; principal components	Chemical Analysis
Gerwinski, W.; Schmidt, D.	Automated solid-phase extraction for trace-metal analysis of seawater: sample preparation for total-reflection X-ray fluorescence measurements	Spectrochim. Acta Part B	53	1355-1364	1998	Trace metals in seawater; TXRF; Solid-phase extraction;	Chemical Analysis
Hitoshi Yamaguchi; Sinji Itoh; Shukuro Igarashi; Kunishige Naitoh; Ryosuke Hasegawa	Trace analysis of high-purity copper by total reflection X-ray fluorescence spectrometry	Fresenius J. Anal. Chem.	362	395-398	1998		Chemical Analysis
Krasnolutskii, V.P.; Blokhin, S.M.	Sensitivity of determining the concentration gradient in the analysis of thin films by X-ray spectrometry with a variable glancing angle	J. of Analytical Chemistry	53	722-724	1998	Depth profiles	Surfaces and Instrumentation
Pettersson, R.P.; Olsson, M.	A nitric acid-hydrogen peroxide digestion method for trace element analysis of milligram amounts of plankton and periphyton by total-reflection X-ray fluorescence spectrometry	J. Anal. At. Spectrom.	13	609-613	1998	TXRF; microanalysis; wet digestion; environmental	Chemical Analysis
Frank, W.; Schindler, A.; Thomas, H.J.	Depth profiling of Co/Ti - Silicide films using total reflection X-ray fluorescence (TXRF) spectrometry combined with low energy ion beam etching (IBE) for sample preparation	Fresenius' J. Anal. Chem.	361	625-627	1998	CoSi2; Combination, Surface	Surfaces and Layers
Dietrich, H.; Nissen, C.; Schmidt, O.; Patz, C.; Frentzel-Beyme, U.; Reus, U.	Dem Inhalt auf der Spur	das deutsche weinmagazin	21	12-17	1998	Wein; Multielement	Chemical Analysis
Tsuji, K.; Sato, T.; Wagatsuma, K.; Claes, M.; Van Grieken, R.	Preliminary experiment of total reflection X-ray fluorescence using two glancing X-ray beams excitation	Rev. Sci. Instrum.	70	1621-1623	1999	Synchrotron-Radiation	Principles and Instrumentation

Autoren	Titel	Zeitschrift	Vol	Seiten	Jahr	Keywords	Gruppe
Klockenkämper, R.; von Bohlen, A.	Depth profiling of a Co-implanted silicon wafer by total-reflection X-ray fluorescence analysis after repeated oxidation and HF-etching	Anal. Commun.	36	27-29	1999	Depth-profiling; implantation; etching	Surfaces and Layers
Streli, C.; Kregsamer, P.; Wobrauschek, P.; Gatterbauer, H.; Pianetta, P.; Pahlke, S.; Palmetshofer, L.; Schmeling, M.	Low Z total reflection X-ray fluorescence analysis - challenges and answers	Spectrochim. Acta Part B	54	1433-1441	1999	Total reflection X-ray fluorescence analysis, TXRF; Energy dispersive X-	Principles and Instrumentation
Tatar, E.; Mihucz, V.G.; Varga, A.; Zaray, G.; Cseh, E.	Effect of lead, nickel and vanadium contamination on organic acid transport in xylem sap of cucumber	J. Inorg. Biochem.	75	219-223	1999	heavy metal pollution; carboxylic acid translocation; cucumber;	Chemical Analysis
Rink, I.; Thewissen, H.	Application of total reflection X-ray fluorescence in angle scan mode to establish the location of arsenic contamination in silicon and silicon oxide, respectively	Spectrochim. Acta Part B	54	1427-1431	1999	TXRF; Depth profiling; Surface contamination	Surfaces and Layers
Liendo, J.A.; González, A.C.; Castelli, C.; Gómez, J.; Jiménez, J.; Marcó, L.; Sajp-Bohus, L.; Greaves, E.D.; Fletcher, N.R.; Bauman, S.	Comparison between Proton-Induced X-Ray Emission (PIXE) and Total Reflection X-Ray Fluorescence (TXRF) Spectrometry for the Elemental Analysis of Human Amniotic Fluid	X-Ray Spectrom.	28	3-8	1999	TXRF; PIXE; Human amniotic fluid	Chemical Analysis
Iltgen, K.; Zschech, E.; Ghatak-Roy, A.; Hossain, T.	Future in-fab applications of total reflection X-ray fluorescence spectrometry for the semiconductor industry	Spectrochim. Acta Part B	54	1393-1398	1999	Surface roughness; Implant dose; In-line TXRF; Semiconductors	Surfaces and Layers
Buhrer, G.	Application of vapor phase decomposition/total reflection X-ray fluorescence in the silicon semiconductor manufacturing environment	Spectrochim. Acta Part B	54	1399-1407	1999	Semiconductor; Trace metal contamination; Vapor phase	Surfaces and Layers
Fabry, L.; Pahlke, S.; Kotz, L.; Wobrauschek, P.; Streli, C.	Novel methods of TXRF analysis for silicon wafer surface inspection	Fresenius' J. Anal. Chem.	363	98-102	1999	VPD/TXRF; Silicon wafer; Synchrotron	Chemical Analysis
Sanchez, H.J.	Theoretical Calculations of Detection Limits in Total Reflection XRF Analysis	X-Ray Spectrom.	28	51-58	1999	Theoretical calculations	Principles and Instrumentation
Knoth, J.; Beaven, P.A.; Michaelsen, C.; Schneider, H.; Schwenke, H.	A tunable focusing monochromator for total reflection X-ray fluorescence spectrometers	X-Ray Spectrom.	28	110-114	1999	Curved multilayer; Ray tracing; Monochromator;	Principles and Instrumentation

Autoren	Titel	Zeitschrift	Vol	Seiten	Jahr	Keywords	Gruppe
Jark, W.; Die Fonzo, S.; Cedola, A.; Lagomarsino, S.	The application of resonantly enhanced X-ray standing waves in fluorescence and waveguide experiments	Spectrochim. Acta Part B	54	1487-1495	1999	Standing X-ray waves; Thin films; Waveguides	Principles and Instrumentation
Terada, Y.; Kondo, N.; Kataoka, M.; Izumiyama, M.; Nakai, I.; Goto, S.	Development and application of multi-purpose X-ray fluorescence analyzer using synchrotron and conventional X-ray sources	X-Ray Spectrom.	28	461-463	1999		Principles and Instrumentation
Bock, H.; Sievert, M.; Bogdan, C.L.; Kolbesen, B.O.; Wittershagen, A.	Interactions in Crystals. Biphenylene Ring Expansion by a (H3C)2Si Link from Silicone Grease As Proven by the Crystal Structures of [(Sodium+[2.2.1]cryptand)(9,9-	Organometallics	18	2387-2389	1999	crystal structure; biphenylene silafluorene radical anion; mol structure;	Chemical Analysis
Spolnik, Z.M.; Claes, M.; Van Grieken, R.E.; de Bokx, P.K.; Urbach, H.P.	Quantification in grazing-emission X-ray fluorescence spectrometry	Spectrochim. Acta Part B	54	1525-1537	1999	Grazing-emission; X-ray spectrometry; Quantification; Light elements	Related Methods
Claes; M.; Van Dyck, K.; Deelstra, H.; Van Grieken, R.	Determination of silicon in organic matrices with grazing-emission X-ray fluorescence spectrometry	Spectrochim. Acta Part B	54	1517-1524	1999	Si; Organic matrices; Grazing-emission TXRF	Related Methods
Knoth, J.; Prange, A.; Reus, U.; Schwenke, H.	A formula for the background in TXRF as a function of the incidence angle and substrate material	Spectrochim. Acta Part B	54	1513-1515	1999	Background formula in TXRF; Substrate material in TXRF; TXRF	Surfaces and Layers
Yamagami, M.; Nonoguchi, M.; Yamada, T.; Shoji, T.; Utaka, T.; Nomura, S.; Taniguchi, K.; Wakita, H.; Ikeda, S.	VPD/TXRF analysis of trace elements on a silicon wafer	X-Ray Spectrom.	28	451-455	1999	trace elements; silicon wafer; vapor phase decomposion; TXRF	Surfaces and Layers
Prange, A.; Reus, U.; Schwenke, H.; Knoth, J.	Optimization of TXRF measurements by variable incident angles	Spectrochim. Acta Part B	54	1505-1511	1999	Analytical quality assurance; Sample homogeneity; Sample carrier	Principles and Instrumentation
Sakurai, K.	Total-reflection X-ray fluorescence imaging	Spectrochim. Acta Part B	54	1497-1503	1999	Imaging; Total-reflection; X-ray fluorescence; CCD camera; Collimator;	Principles and Instrumentation
Jach; T.; Gormley, J.; Thurgate, S.	Grazing incidence X-ray photoemission spectroscopy of SiO2 on Si	Spectrochim. Acta Part B	54	1539-1544	1999	Grazing incidence; X-ray photoemission spectroscopy; XPS; Thin films; Total	Related Methods

Autoren	Titel	Zeitschrift	Vol	Seiten	Jahr	Keywords	Gruppe
van Aarle, J.; Abela, R.; Hegedüs, F.; Streli, C.; Victoria, M.; Winkler, P.; Wobrauschek, P.	Measurement of trace element concentration in a metal matrix using total reflection X-ray fluorescence spectrometry	Spectrochim. Acta Part B	54	1443-1447	1999	Total reflection X-ray fluorescence spectroscopy; Trace element	Chemical Analysis
Mori, Y.; Uemura, K.	Tutorial: Error factors of quantitative total-reflection X-ray fluorescence analysis	X-Ray Spectrom.	28	421-426	1999	Error factors; Si wafers; Surface contamination	Review
Noma, T.; Takada, K.; Iida, A.	Surface-sensitive X-ray fluorescence and diffraction analysis with grazing-exit geometry	X-Ray Spectrom.	28	433-439	1999	thin film; synchrotron radiation; structural surface information	Related Methods
Bellisola, G.; Pasti, F.; Valdes, M.; Torboli, A.	The use of total-reflection X-ray fluorescence to track the metabolism and excretion of selenium in humans	Spectrochim. Acta Part B	54	1481-1485	1999	Trace analysis; TXRF; Blood plasma; Sodium selenite; Selenium	Chemical Analysis
Marcó, L.M.; Greaves, E.D.; Alvarado, J.	Analysis of human blood serum and human brain samples by total reflection X-ray fluorescence spectrometry applying Compton peak standardization	Spectrochim. Acta Part B	54	1469-1480	1999	TXRF; Serum; Brain; Compton; Analysis	Chemical Analysis
Capote, T.; Marcó, L.M.; Alvarado, J.; Greaves, E.D.	Determination of copper, iron and zinc in spirituous beverages by total reflection X-ray fluorescence spectrometry	Spectrochim. Acta Part B	54	1463-1468	1999	Total reflection X-ray fluorescence spectrometry; Copper; Spirituous	Chemical Analysis
Stoev, K.N.; Sakurai, K.	Review on grazing incidence X-ray spectrometry and reflectometry	Spectrochim. Acta Part B	54	41-82	1999	Total reflection; Specular reflection; Diffuse scattering; Surface	Related Methods
Iljima, Y.; Miyoshi, K.	Account: Recent advances in the application of total reflection X-ray photoelectron spectroscopy in the semiconductor industry	X-Ray Spectrom.	28	427-432	1999	TRXPS; semiconductor surface;	Related Methods
Varga, A.; Garcinuno Martinez, R.M.; Záray, Gy.; Fodor, F.	Investigation of effects of cadmium, lead, nickel and vanadium contamination on the uptake and transport processes in cucumber plants by TXRF spectrometry	Spectrochim. Acta Part B	54	1455-1462	1999	Metal uptake; Transport processes; Cucumber plants;	Chemical Analysis
Szaloki, I.; Utaka, T.; Tsuji, Y.; Taniguchi, K.	Quantification of TXRF analysis	Adv. X-Ray Anal.	41	812-821	1999	Quantitation	Chemical Analysis

Autoren	Titel	Zeitschrift	Vol	Seiten	Jahr	Keywords	Gruppe
Comin, F:; Navizet, M.; Mangiagalli, P.; Apostolo, G.	An industrial SR-TXRF facility at ESRF	Nucl. Instrum. Methods B	150	538-542	1999	mapping; trace impurity; surface; silicon wafer	Surfaces and Layers
Ritschel, A.; Wobrauschek, P.; Chinea, E.; Grass, F.; Fabjan, Ch.	An electrochemical enrichment procedure for the determination of heavy metals by total-reflection X-ray fluorescence spectroscopy	Spectrochim. Acta Part B	54	1449-1454	1999	Total-reflection X-ray fluorescence spectroscopy (TXRF);	Chemical Analysis
Klockenkämper, R.; von Bohlen, A.; Becker, H.W.; Palmetshofer, L.	Comparison of shallow depth profiles of cobalt-implanted Si wafers determined by total reflection X-ray fluorescence analysis after repeated stratified etching and by Rutherford	Surf. Interface Anal.	27	1003-1007	1999	TXRF; RBS; ion implantation; Si-wafer; depth profiles	Surfaces and Layers
Comin, F.	The industrial use of synchrotron radiation for TXRF analysis of Si wafers	Proc. - Electrochem. Soc.	99-16	134-138	1999	synchrotron radiation TXRF; analysis silicon wafer	Surfaces and Layers
Viksna, A.; Znotina, V.; Boman, J.	Concentrations of some elements in and on Scots pine needles	X-Ray Spectrom.	28	275-281	1999	Scots pine needle;TXRF; GFAAS	Chemical Analysis
Tian, Y.; Liu, K.; Wu, X.; Zheng, S.	TXRF technique and quantitative analysis of mollusc teeth	Guangpuxue Yu Guangpu Fenxi	19	430-433	1999	TXRF; analysis mollusc teeth	Chemical Analysis
Kawai, J.; Sai, M.; Sugimura, T.; Hayashi, K.; Takenaka, H.; Kitajima, Y.	Total reflection X-ray photoelectron spectroscopy of a tantalu-titanium multilayer	X-Ray Spectrom.	28	519-522	1999		Related Methods
Muratsu, S.; Fukui, S.; Maeda, T.; Matsushita, T.; Hasegawa, H.; Sakurai, Y.; Shimoda, O.; Kaizaki, S.; Ninomiya, T.	Trace elemental analysis of illicit methamphetamines using total reflection x-ray fluorescence spectroscopy	J. Health Sci.	45	166-171	1999	methamphetamine; trace element detection; spectroscopy	Chemical Analysis
Barkacs, K.; Varga, A.; Gal-Solymos, K.; Zaray, Gy.	Direct determination of metal concentrations in freshwater algae by total reflection X-ray fluorescence spectrometry	J. Anal. At. Spectrom.	14	577-581	1999	total reflection X-ray fluorescence spectrometry; metal; algae; environmental	Chemical Analysis
Fernandez Ruiz, R.; Tornero, J.D.; Gonzalez, V.M.; Alonso, C.	Quantification of Pt bound to DNA using total-reflection X-ray fluorescence (TXRF)	Analyst	124	583-585	1999	Antitumor platinum; DNA; X-ray fluorescence	Chemical Analysis

Autoren	Titel	Zeitschrift	Vol	Seiten	Jahr	Keywords	Gruppe
Yamada, T.; Nisawa, A.; Shoji, T.; Utaka, T.	Design of double multilayer monochromator for TXRF optics by using ray-tracing simulation	J. Surf. Anal.	5	124-127	1999	design multilayer monochromator; TXRF; optics; ray tracing; simulation	Instrumentation
Kregsamer, P.; Streli, C.; Wobrauschek, P.; Gatterbauer, H.; Pianetta, P.; Palmetshofer, L.; Brehm, L.L.	Synchrotron Radiation-excited Glancing Incidence XRF for Depth Profile and Thin-Film Analysis of Light Elements	X-Ray Spectrom.	28	292-296	1999	Glancing incidence synchrotron radiation; light elements; depth	Related Methods
Theisen, M.; Nießner, R.	Sapphire sample carriers for silicon determination by total-reflection X-ray fluorescence analysis	Spectrochim. Acta Part B	54	1839-1848	1999	sapphire carrier; silicon detn X ray fluorescence; environmental	Chemical Analysis
Kelkó-Lévai, Á.; Varga, I.; Zih-Perényi, K.; Lásztity, A.	Determination of trace elements in pharmaceutical substances by graphite furnace atomic absorption spectrometry and total reflection X-ray fluorescence after flow injection	Spectrochim. Acta Part B	54	827-833	1999	ETAAS; TXRF; flow injection; preconcentration; impurities; drugs;	Chemical Analysis
Buscaglia, Joann	The forensic characterization of polyethylene films by elemental analysis using total-reflection x-ray fluorescence TXRF spectrometry	UMI, Order No. DA9924798		Dissertation	1999	metal; x-ray fluorescence spectrometry; forensic polyethylene	Chemical Analysis
Huber, A.; Freudenberg, F.	Fully automatic wafer surface contamination monitoring based on VPD-TXRF	Proc. - Electrochem. Soc.	99-16	221-231	1999	wafer surface contamination automatic monitoring; VPD	Surfaces and Layers
Padilla Alvarez, R.; Chinea Cano, E.; Estévez Alvarez, J.R.; Greaves, E.D.	Instrumental detection limits in total reflection X-ray fluorescence: Comparison of cut-off and monochromatic excitation devices	J. Radioanal. Nucl. Chem.	240	517-522	1999	Cut-off reflectors; monochromator; detection limit;	Principles and Instsrumentation
von Bohlen, A.	Multielement microanalysis and pattern characterisation of historical violin varnishes	J. Trace and Microprobe Techniques	17	177-187	1999	Total reflection X-ray fluorescence; violin varnish; pattern recognition;	Chemical Analysis
Tsuji, K.; Wagatsuma, K.; Nullens, R.; Van Grieken, R.E.	Grazing Exit Electron Probe Microanalysis for Surface and Particle Analysis	Anal. Chem.	71	2497–2501	1999		Related Methods
Varga, I.; Rierpl, E.; Tusai, A.	Comparison of slurry preparation and microwave digestion of freshwater algae for multi-element analysis by total reflection X-ray fluorescence spectrometry	J. Anal. At. Spectrom.	14	881.883	1999	Slurry sampling; Vapour-phase microwave digestion; algae	Chemical Analysis

Autoren	Titel	Zeitschrift	Vol	Seiten	Jahr	Keywords	Gruppe
Wehling, B.; Vandenabeele, P.; Moens, L.; Klockenkämper, R.; von Bohlen, A.; Van Hooydonk, G.; de Reu, M.	Investigation of Pigments in Medieval Manuscripts by Micro Raman-spectroscopy and Total Reflection X-ray Fluorescence Spectrometry	Mikrochim. Acta	130	253-260	1999	Micro-Raman-spectroscopy; TXRF; artists´ pigments;	Chemical Analysis
Gonzáles, M.; Tapia, L.; Alvarado, M.; Tornero, J.D.; Fernández, R.	Intracellular determination of elements in mammalian cultured cells by total-reflection X-ray fluorescence spectrometry	J. Anal. At. Spectrom.	14	885-888	1999	Mammalian cell lines; Intracellular concentrations; biology;	Chemical Analysis
Klockenkämper, R.; von Bohlen, A.	Survey of sampling techniques for solids suitable for microanalysis by total-reflection X-ray spectrometry	J. Anal. At. Spectrom.	14	571-576	1999	Solid sampling; internal standardazation, microanalysis	Review
Claes, M.; de Bokx, P.; Van Grieken, R.	Progress in Laboratory Grazing Emission X-Ray Fluorescence Spectrometry	X-Ray Spectrom.	28	224-229	1999	Grazing emission XRF; light elements; wavelength-dispersive	Related Methods
Bennun, L.; Gillette, V.H.; Greaves, E.D.	Data processing technique for mercruy determination by total-reflection X-ray fluorescence, using amalgamation with gold	Spectrochim. Acta Part B	54	1291-1301	1999	Hg; Amalgam; TXRF; Environment samples	Chemical Analysis
Theisen, M.; Niessner, R	Elemental analysis of airborne dust samples with TXRF. Comparison of oxygen-plasma ashing on sapphire carriers and acid digestion for sample preparation	Fresenius' J. Anal. Chem.	365	332-337	1999	multielement detn airborne particulate matter TXRF sample prepn; x ray	Chemical Analysis
Klockenkämper, R.; von Bohlen, A.	A new method for depth-profiling of shallow layers in silicon wafers by repeated chemical etching and total-reflection X-ray fluorescence analysis	Spectrochim. Acta Part B	54	1385-1392	1999	Depth profiling of shallow layers; Oxidation of Si; HF-etching of SiO2; Co-	Surfaces and Layers
Pérez, R.D.; Sánchez, H.J.; Rubio, M.; Pérez, C.A.	Mathematical model for evaluation of surface analysis Data by total reflection XRF	X-Ray Spectrom.	28	342-347	1999		Surfaces and Layers
Vilhunen, J.K.; von Bohlen, A.; Schmeling, M.; Rantanen, L.; Mikkonen, S.; Klockenkämper, R.; Klockow, D.	Trace element determination in Diesel particulates by total-reflection X-ray fluorescence analysis	Mikrochim. Acta	131	219-223	1999	total-reflection X-ray fluorescence; trace element analyses; Diesel fuel; Diesel	Chemical Analysis
Funahashi, M.; Matsuo, M.; Kawada, N.; Yamagami, M.; Wilson, R.	Enhanced analysis of particles and vapor phase decomposition droplets by total-reflection X-ray fluorescence	Spectrochim. Acta Part B	54	1409-1426	1999	Total-reflection X-ray fluorescence (TXRF); Vapor phase	Surfaces and Layers

Autoren	Titel	Zeitschrift	Vol	Seiten	Jahr	Keywords	Gruppe
Costa, M.M.; Barreiros, M.A.; Carvalho, M.L.; Queralt, I.	Multi-element characterization of Estuarine sediments and waters	X-Ray Spectrom.	28	410-413	1999	Sediment; water; trace elements;	Chemical Analysis
Holynska, B.; Ostachowicz, B.; Samek, L.	Speciation of heavy metals in peat with the use of total reflection X-ray fluorescence spectrometry	X-Ray Spectrom.	28	372-375	1999	Speciation; peat	Chemical Analysis
Nascimento Filho, V.F.; Poblete, V.H.; Parreira, P.S.; Matsumoto, E.; Simabuco, S.M.; Espinoza, E.P.; Navarro, A.A.	Limits of detection of a total reflection x-ray fluorescence system with double reflection module	Biological Trace Element Research	71-72	423-430	1999	Total reflection x-ray fluorescence; XRF; ED-XRF; instrumental analysis	Chemical Analysis
Comin, F.; Mangiagalli, P.; Navizet, M.; Apostolo, G.	An industrial SR-TXRF facility at ESRF	Microelectron. Eng.	45	265-268	1999	silicon wafer; metal impurity surface analysis; total x ray reflection	Chemical Analysis
Schwenke, H.; Beaven, P.A.; Knoth, J.	Applications of total reflection X-ray fluorescence spectrometry in trace element and surface analysis	Fresenius' J. Anal. Chem.	365	19-27	1999	Surface analysis; thin layer and interface analysis; contamination	Review
Yamagami, M.; Nonoguchi, M.; Yamada, T.; Shoji, T.; Utaka, T.; Mori, Y.; Nomura, S.; Taniguchi, K.; Wakita, H.; Ikeda, S.	Analysis of light elements on Si wafer by vapor-phase decomposition/total reflection x-ray fluorescence	Bunseki Kagaku	48	1005-1011	1999	silicon; vapor phase decomposition; TXRF	Surfaces and Layers
Tsuji, K., Spolnik, Z., Wagatsuma, K., Zhang, J., Van Grieken, R.	Enhancement of electron-induced X-ray intensity for single particles under grazing-exit conditions	Spectrochim. Acta Part B	54	1243-1251	1999	Electron probe microanalysis; Grazing exit; Aerosols;	Related Methods
Liou, B.W.; Lee, C.L.	Variations of X-ray spectrum in total reflection X-ray fluorescence (TXRF) analysis with respect to Si wafer crystal orientation for different incident angles	Chin. J. Phys. (Taipei)	37	623-630	1999	spectrum variation; TXRF; silicon wafer; crystal orientation	Surfaces and Layers
Fermo, P.; Cariati, F.; Pozzi, A.; Demartin, F.; Tettamanti, M.; Collina, E.; Lasagni, M.; Pitea, D.; Puglisi, O.; Russo, U.	The analytical characterization of municipal solid waste incinerator fly ash: methods and preliminary results	Fresenius' J. Anal. Chem.	365	666-673	1999	incinerator fly ash; analysis method	Chemical Analysis
Marco, L.M.; Greaves, E.D.; Alvarado, J.	Analysis of human blood serum and human brain samples by total reflection X-ray fluorescence spectrometry applying Compton peak standardization	Spectrochim. Acta Part B	54	1469-1480	1999	blood serum; brain; X-ray fluorescence spectrometry; Compton peak	Chemical Analysis

Autoren	Titel	Zeitschrift	Vol	Seiten	Jahr	Keywords	Gruppe
Werho, D.; Schauer, S.N.; Carney, G.F.	Issues with TXRF angle scans and calibration	Adv. X-Ray Anal.	41	794-803	1999	angle scan calibration; total reflection x ray fluorescence	Surfaces and Layers
Morovov, A.P.; Danilin, L.D.; Zhmailo, V.V.; Ignatiev, Yu.V.; Lakhtikov, A.E.; Nazarov, V.V.; Vasin, M.G.; Chulkov, V.V.; Funin, V.N.	Ion-exchange films for element concentration in x-ray fluorescence analysis with total reflection of the primary beam	Adv. X-Ray Anal.	41	822-828	1999	ion exchange film; gold; total reflection x-ray fluorescence	Chemical Analysis
Schwaiger, R.; Wobrauschek, P.; Streli, C.	Bending multilayers - A simple method to increase the sensitivity in TXRF	Adv. X-Ray Anal.	41	804-811	1999	bending multiplayer; TXRF; sensitivity improvement	Chemical Analysis
Gatterbauer, H.; Wobrauschek, P.; Hegedus, F.; Boni, P.; Streli, C.	Double multilayer monochromator with fixed exit geometry	Adv. X-Ray Anal.	41	379-383	1999	multilayer monochromator; fixed exit geometry	Chemical Analysis
Olsson, M.; Viksna, A.; Helmisaari, H.-S.	Multi-element analysis of fine roots of Scots pine by total reflection X-ray fluorescence spectrometry	X-Ray Spectrom.	28	335-338	1999	Fine roots; multielement analysis; Scot pine; TXRF	Chemical Analysis
Moreira Simabuco, S.; Matsumoto, E.	Synchrotron radiation total reflection for rainwater analysis	Spectrochim. Acta Part B	55	1173-1179	2000	trace elements; rain water; total reflection x-ray fluorescence analysis;	Chemical Analysis
Mori, Y.; Uemura, K.	Multi-batch Preparation of Standard Samples from a Single Doped Solution for Cross-checking in Surface Metal Analyses of Silicon Wafers	Anal. Sci.	16	987-989	2000		Surfaces and Layers
Xie, Mingyong; Wen, Huiliang	Study on element analysis of Oolong tea by total reflection X-ray fluorescence (TXRF) and hydride generation atomic absorption	Shipin Kexue (Beijing)	21	51-54	2000	Oolong tea; trace element analysis; TXRF; AAS; hydride generation	Chemical Analysis
Schmeling, M.;Russell, L.M.; Erlick, C.;Collins, D.R.; Jonsson, H.; Wang, Q.; Kregsamer, P.; Streli, C.	Aerosol particle chemical characteristics measured from aircraft in the lower troposphere during ACE-2	Tellus, Ser. B	52B	185-200	2000	particulate air pollution; lower troposphere; aerosol particle;	Chemical Analysis
Varga, A.; Zaray, Gy.; Fodor, F.	Investigation of element distributions between the symplasm and apoplasm of cucumber plants by TXRF spectrometry	Microchem. J.	67	257-264	2000	trace element distribution; symplasm; apoplasm; cucumber	Chemical Analysis

Autoren	Titel	Zeitschrift	Vol	Seiten	Jahr	Keywords	Gruppe
Greaves, E. D.	Heavy element determination in health-related organic matrix materials by total reflection x-ray fluorescence	Adv. X-Ray Anal.	43	601-609	2000	total reflection x-ray fluorescence spectroscopy heavy metal; trace	Chemical Analysis
Sobrado, M. A.; Greaves, E. D.	Leaf secretion composition of the mangrove species Avicennia germinans (L.) in relation to salinity: a case study by using total-reflection X-ray fluorescence analysis	Plant Sci.	159	1-5	2000	leaf secretion; comparison; mangrove salinity	Chemical Analysis
Pianetta, P.; Baur, K.; Singh, A.; Brennan, S.; Kerner, Jonathan; Werho, D.; Wang, J.	Application of synchrotron radiation to TXRF analysis of metal contamination on silicon wafer surfaces	Thin Solid Films	373	222-226	2000	synchrotron radiation TXRF; silicon wafer surface; metal	Surfaces and Layers
Potts, P.J.; Ellis, A.T.; Holmes, M.; Kregsamer, P.; Streli, C.; West, M.; Wobrauschek, P.	X-ray fluorescence spectrometry	J. Anal. At. Spectrom.	15	1417-1442	2000		Review
Weiss, C.; Knoth, J.; Schwenke, H.; Geisler, H.; Lerche, J.; Schulz, R.; Ullrich, H.-J.	Potential of total reflection and grazing incidence XRF for contamination and process control in semiconductor fabrication	Mikrochim. Acta	133	65-68	2000	grazing incidence XRF; process control semiconductor	Surfaces and Layers
Morovov, A. P.; Danilin, L. D.; Zhmailo, V. V.; Funin, V. N.; Ignatiev, Yu.V.; Pilipenko, N. V.; Vasin, M. G.; Nazarov, V. V.; Chulkov, V. V.	Thin film sorbents for TXRF analysis	Adv. X-Ray Anal.	42	119-125	2000	TXRF; microanalysis; heterogenic thin film; sorbent; sorbent film	Chemical Analysis
Awaji, N.; Ozaki, S.; Nishino, J.; Noguchi, S.; Yamamoto, T.; Syoji, T. Yamagami, M.; Kobayashi, A.; Hirai, Y.; Shibata, M.; Yamaguchi, K.; Kiu, K-	Wavelength-dispersive total reflection X-ray fluorescence with high-brilliance undulator radiation at Spring-8	Japanese Journal of Applied Physics, Part 2: Letters	39	L1252-L1255	2000	WD-TXRF; Ed-TXRF; Synchrotron radiation;	Principles and Instrumentation
Ebert, M.; Mair, V.; Tessadri, R.; Hoffmann, P.; Ortner, H.M.	Total-reflection X-ray fluorescence analysis of geological microsamples	Spectrochim. Acta Part B	55	205-212	2000	TXRF; analysis geol; microsample; garnet analysis	Chemical Analysis
Vandenabeele, P.; von Bohlen, A.; Moens, L.; Klockenkämper, R.; Joukes, F.; Dewispelaere, G.	Spectroscopic examinatoin of two Egyptian Masks: a combined method approach	Anal. Letters	33	3315-3332	2000	Art analysis; TXRF; Micro-Raman spectroscopy (MRS); pigment	Chemical Analysis
Egorov, V.K.; Kondratiev, O.S.; Zuev, A.P.; Egorov, E.V.	The modification of TXRF -method by use of x-ray slitless collimator	Adv. X-Ray Anal.	43	437-448	2000	TXRF; x-ray slitless collimator	Instrumentation

Autoren	Titel	Zeitschrift	Vol	Seiten	Jahr	Keywords	Gruppe
Waldschäger, U.	The analytical possibilities of a portable TXRF-spectrometer	Adv. X-Ray Anal.	43	449-454	2000	portable TXRF spectrometer; water analysis; airborne particulate	Instrumentation
Wang, J.; Balazs, M.; Pianetta, P.; Baur, K.; Brennan, S.	Investigation of trace metals analyses of dry residue on silicon wafer surfaces by TXRF and ICP-MS	Diffus. Defect Data, Pt. B	76-77	75-80	2000	trace metal analysis; dry residue; silicon wafer surface; TXRF; ICPMS	Chemical Analysis
Istratov, A.A.; Hieslmair, H.; Weber, E.R.	Iron contamination in silicon technology	Appl. Phys. A	70	489–534	2000		Review
Blockhuys, F.; Claes, M.; Van Grieken, R.; Geise, H.J.	Assessing the Molecular Weight of a Conducting Polymer by Grazing Emission XRF	Anal. Chem.	72	3366–3368	2000		Related Methods
Holynska, B.; Ostachowicz, B.; Ostachowicz, J.; Samek, L.; Wachniew, P.; adeyska, E.; Wobrauschek, P.; Streli, C.;	Time dependent characterization of ombrotrophic peat cores from Poland and Austria for studying atmospheric deposition of metals	Adv. X-Ray Anal.	43	553-559	2000	ombrotrophic peat; atmosperic deposition of metals; Poland; Austria; lead	Chemical Analysis
Wang, J.; Balazs, M. K.; Pianetta, P.; Baur, K.; Brennan, S.	Analytical techniques for trace elemental analyses on wafer surfaces for monitoring and controlling contamination	Semicond. Pure Water Chem. Conf.	19	399-412	2000	trace elemental analysis; wafer surface; TXRF; ICPMS	Chemical Analysis
Yamaguchi, H.; Itoh, S.; Igarashi, S.; Naitoh, K.; Hasegawa, R.	Determination of trace impurities in graphite and silicon carbide by total reflection x-ray fluorescence spectrometry after homogeneous liquid-liquid extraction	ISIJ Int.	40	779-782	2000	x-ray fluorescence spectrometry; graphite; silicon carbide; trace	Chemical Analysis
Streit, N.; Weingartner, E.; Zellweger, C.; Schwikowski, M.; Gaggeler, H.W.; Baltensperger, U.	Characterization of size-fractionated aerosol from the Jungfraujoch (3580 m asl) using total reflection X-ray fluorescence (TXRF)	Int. J. Environ. Anal. Chem.	76	1-16	2000	aerosol elemental analysis; impactor; total reflection X-ray fluorescence;	Chemical Analysis
Spanke, J.; von Bohlen, A.; Klockenkämper, R.; Quentmeier, A.; Klockow, D.	Total reflection X-ray fluorescence analysis of laser-deposited solid sample material	J. Anal. At. Spectrom.	15	673-679	2000	laser ablation; solid sample deposition; TXRF	Chemical Analysis
Exner, A.; Theisen, M.; Panne, U.; Niessner, R.	Combination of asmmetric flow field-flow fractionation (AF4) and total-reflection X-ray fluorescence analysis (TXRF) for determination of heavy metals assocciated with colloidal humic	Fresenius' J. Anal. Chem.	366	254-258	2000	Colloidal humic substances; flow field-flow fractionation; TXRF;	Chemical Analysis

Autoren	Titel	Zeitschrift	Vol	Seiten	Jahr	Keywords	Gruppe
Vázquez, C.; de Funes, S.F.; Casa, A.; Adelfang, P.	Application of total reflection X-ray fluorescence to studies of the geographical distribution of arsenic and other toxic trace elements in ground waters of argentine pampa plain	J. Trace Microprobe Tech.	18	73-81	2000	As in water; trace element analysis; X-ray fluorescence; toxic trace elements	Chemical Analysis
Quentmeier, A.; Kraft, R.; Kostka, S.; Klockenkämper, R.; Friedrich, C.G.	Characterization of a new type of sulphite dehydrogenase from Paracoccus pantotrophus GB17	Arch. Microbiol.	173	117-125	2000	Paracoccus denitrificans; Paracoccus pantotrophus;	Chemical Analysis
Tsuji, K.; Wagatsuma, K.; Oku, T.	Glancing-incidence and glancing-takeoff x-ray fluorescence analysis of Ni-GaAs interface reactions	X-Ray Spectrom.	29	155-160	2000	GIT-XRF; GE-XRF; GaAs; Ni-GaAs interface	Related Methods
Staat, H.; Seifert, L.; von Bohlen, A.	Detection of casting material on historical violins by infrared spectroscopy and total reflection X-ray fluorescence spectrometry	Analytical Letters	33	953-962	2000	violin varnish; TXRF; IR; casting material; artefacts	Chemical Analysis
von Bohlen, A.; Lietz, E.; Brink-Kloke, H.; Poniecki, C.	Microanalytical characteriation of Germanic non-iron metal finds at Dortmund-Oespel	J. Trace Microprobe Tech.	18	275-285	2000	X-ray microprobe; archaeology; brass; bronze; spectral analysis	Related Methods
Varga, I.; von Bohlen, A.; Zaray, Gy.; Klockenkämper, R.	Chemical speciation of metals and sulphur in air dust by sequential leaching and total reflection X-ray fluorescence analysis	J. Trace Microprobe Tech.	18	293-302	2000	TXRF; air dust; sequential leaching; microanalysis; heavy metals	Chemical Analysis
Wamwangi, D.M.; Rathore, I.V.S.; Katia, S.K.; Mangala, M.J.	Trace element analyses of pollen, bee tissue and honey by total reflection and radioisotope excited X-ray fluorescence spectrometry	Journal Trace Microprobe Technique	18	303-310	2000	Environmental samples; EDXRF; TXRF; radioisotope XRF; trace	Chemical Analysis
Varga, I.; von Bohlen, A.; Klockenkämper, R.; Zaray, Gy.	Solid state speciation of elenents in urban dust by sequential leaching and total reflection X-ray fluorescence spectrometry	Microchem. J.	67	265-269	2000	TXRF; air dust; sequential leaching; microanalysis; heavy metals	Chemical Analysis
Weber, S.; Hoffmann, P.; Ensling, J.	Characterization of iron compounds from urban and rural aerosol sources	J. Aerosol Sci.	31	987-997	2000		Chemical Analysis
Klockenkämper, R.; von Bohlen, A.; Moens, L.	Analysis of pigments and inks on oil paintings and historical manuscripts using total reflection X-ray fluorescence spectrometry	X-Ray Spectrom.	29	119-129	2000	TXRF; pigment analysis; inks; oil paintings; historical manuscripts	Review

Autoren	Titel	Zeitschrift	Vol	Seiten	Jahr	Keywords	Gruppe
Schmeling, M.; Russell, L.M.; Erlick, C.; et al.	Aerosol particle chemical characteristics measured from aircraft in the lower troposhere during ACE-2	Tellus B-Chem. Phys. Meteorol.	52	185-200	2000		Chemical Analysis
De Witte, H.; De Gendt, S.; Douglas, M.	Evaluation of time-of -flight secondary ion mass spectrometry for metal contamination monitoring on Si wafer surfaces	J. Electrochem. Soc.	147	1915-1919	2000		Related Methods
Ebert, M.; Mair, V.; Tessadri, R.; Hoffmann, P.; Ortner, H.M..	Total-reflection X-ray fluorescence analysis of geological microsamples	Spectrochim. Acta Part B	55	205-212	2000	TXRF; garnet; microsamples; EMPA	Chemical Analysis
Zanderigo, F.; Ferrari, S.; Queirolo, G. et al.	Quantitative TOF-SIMS analysis of metal contamination on silicon wafers	Mater. Sci. Engl. B-Solid State M:	73	173-177	2000		Related Methods
Kouichi Tsuji, Marc Huisman, Spolnik, Z.; Wagatsuma, K.; Mori, Y.; Van Grieken, R.; Vis, R.D.	Comparison of grazing-exit particle-induced X-ray emission with other related methods	Spectrochim. Acta Part B	55	1009-1016	2000		Related Methods
Greaves, E.D.; Marcó Parra, L.M.; Rojas, A.; Sajo-Bohus, L.	Determination of platinum levels in serum and urine samples from pediatric cancer patients by TXRF	X-Ray Spectrom.	29	349-353	2000	Platinum; cancer patients; serum; urine; TXRF	Chemical Analysis
Fink, H.; Panne, U.; Theisen, M.; Niessner, R.; Probst, T.; Lin, X.	Determination of metal additives and bromine in recycled thermoplasts from electronic waste by TXRF analysis	Fresenius' J. Anal. Chem.	368	235-239	2000	Polymers; additives; validation INAA; recycling	Chemical Analysis
Messerschmidt, J.; von Bohlen, A.; Alt, F.; Klockenkämper, R.	Separation and enrichment of palladium and gold in biological and environmental samples, adapted to the determination by total reflection X-ray fluorescence	Analyst	125	397-399	2000	preconcentration; co-precipitation, ultra-trace; palladium; gold	Chemical Analysis
Streli, C.	Development of total reflection x-ray fluorescence analysis at the Atominstitute of the Austrian Universities	X-Ray Spectrom.	29	203-211	2000	TXRF; trace elements; synchrotron radiation; low- and	Review
Rink, I. et al.	Calibration of straight total reflection X-ray fluorescence spectrometry - results of a European Round Robin test	Spectrochim. Acta Part B	56	2283-2292	2001	Round robins; iso-angle; calibration	Chemical Analysis

Autoren	Titel	Zeitschrift	Vol	Seiten	Jahr	Keywords	Gruppe
Mertens, M.; Rittmeyer, C.; Kolbesen, B.O.	Evaluation of the protein concentration in enzymes via determination of sulfur by total reflection X-ray fluorescence spectrometry - limitations of the method	Spectrochim. Acta Part B	56	2157-2164	2001	TXRF; enzymes; sulfur; protein determination	Chemical Analysis
Steinmeyer, S.; Kolbesen, B.O.	Capability and limitations of the determination of sulfur in inorganic and biological matrices by total reflection X-ray fluorescence spectrometry	Spectrochim. Acta Part B	56	2165-2173	2001	Determination of sulfur; tungsten L-radiation; inorganic/biological	Chemical Analysis
Carvalho, M.L.; Custódio, P.J.; Reus, U.; Prange, A.	Elemental analysis of human amniotic fluid and placenta by total-reflection X-ray fluorescence and energy-dispersive X-ray fluorescence: child weight and maternal age dependence	Spectrochim. Acta Part B	56	2175-2180	2001	EDXRF; biological samples; amniotic fluid, placenta; elemental analysis;	Chemical Analysis
Buoso, M.C. et al.	Assessment of serum selenium levels in 2-month-od sucking calves using total reflection X-ray fluorescence technique	Spectrochim. Acta Part B	56	2181-2186	2001	TXRF; serum selenium; sucking calves	Chemical Analysis
Marcó, L.M.; Capote, T.; Hernández, E.A.; Greaves, C.; Greaves, E.D.	Feasibility study on in situ microwave digestion prior to analysis of biological samples by total reflection X-ray fluorescence	Spectrochim. Acta Part B	56	2187-2193	2001	TXRF; direct analysis; solid sampling; microwave digestion	Chemical Analysis
Marcó, L.M.; Jiménez, E.; Hernández, E.A.; Rojas, A.; Greaves, E.D.	Determination of Zn/Cu ratio and oligoelements in serum samples by total reflection X-ray fluorescence spectrometry for cancer diagnosis	Spectrochim. Acta Part B	56	2195-2201	2001	TXRF; serum; cancer	Chemical Analysis
Miesbauer, H.; Köck, G.; Püreder, L.	Determination of trace elements in macrozoobenthos samples by total reflection X-ray fluorescence analysis	Spectrochim. Acta Part B	56	2203-2207	2001	Biomonitoring; aquatic insects; bioindicator; trace elements	Chemical Analysis
Mages, M.; Woelfl, S.; v. Tümpling, W., jun.	A method for trace element determination of single Daphnia specimens using total reflection X-ray fluorescence spectrrometry	Spectrochim. Acta Part B	56	2209-2217	2001	trace element analysis; Daphnia; bioaccumulation; contamination	Chemical Analysis
Zarkadas, Ch.; Karydas, A.G.; Paradellis, T.	Applicability of direct total reflection X-ray fluorescence analysis in the case of human blood serum samples	Spectrochim. Acta Part B	56	2219-2228	2001	Blood serum; critical sample thickness; trace elements	Chemical Analysis
Varga, I.; Nagy, M.	Investigation of polyelectrolytes by total reflection X-ray fluorescence spectrometry	Spectrochim. Acta Part B	56	2229-2234	2001	Polyelectrolyte; organic film; sample preparation; TXRF	Chemical Analysis

Autoren	Titel	Zeitschrift	Vol	Seiten	Jahr	Keywords	Gruppe
Mihucz, V.G.; Tatár, E.; Varga, A.; Záray, Gy.; Cseh, E.	Application of total-reflection X-ray fluorescence spectrometry and high-performance liquid chromatography for the chemical characterization of xylem saps of nickel	Spectrochim. Acta Part B	56	2235-2246	2001	Xylem; urea; nickel; high-performance liquid chromatography;	Chemical Analysis
Bermúdez, J.I.; Greaves, E.D.; Nemeth, P.; Sajo-Bohus, L.	Determination of technetium by total-reflection X-ray fluorescence	Spectrochim. Acta Part B	56	2247-2251	2001	Technetium; TXRF; analysis; nuclear medicine	Chemical Analysis
Vázquez, C.; Custo, G.; Boeykens, S.	Characterization of trace elements in high viscosity materiasl by total reflection X-ray spectrometry	Spectrochim. Acta Part B	56	2253-2260	2001	Polymer samples; trace element analysis; scattering radiation method;	Chemical Analysis
Brauer, H.; Wagner, A.; Boman, J.; Binh, D.V.	Use of total-reflection X-ray fluorescence in search of a biomonitor for environmental pollution in Vietnam	Spectrochim. Acta Part B	56	2147-2155	2001	Biomonitor; trace elements; Vietnam; TXRF	Chemical Analysis
Esaka, F.; Watanabe, K.; Magara, M.; Hanzawa, Y.; Usuda, S.	Screening of uranium particles by total-reflection X-ray fluorescence spectrometry for safeguards environmental sample analsis	Journal Trace Microprobe Technique	19	487-496	2001	uranium particles; environmental samples;	Chemical Analysis
Zereini, F.; Wiseman, C.; Beyer, J.M.; Artelt, S.; Urban, H.	Platinum, Lead and Cerium Concentrations of Street Particulate Matter (Frankfurt am Main, Germany)	Journal of Soils and Sediments	1	188-195	2001	Airborne particulate matter - Ce - lead (Pb) - palladium (Pd) - Platinum	Review
Burba, P.; Beer, A.-M.; Lukanov, J.	Metal distribution and binding in balneological peats and their aqueous extracts	Fresenius' J. Anal. Chem.	370	419–425	2001		Chemical Analysis
Fuertes, M.A.; Pérez, J.M.; Soto, M.; López, M.C.; Alonso, C.	Calcium-induced conformational changes in Leishmania infantum kinetoplastid membrane protein-11	J. Biol. Inorg. Chem.	6	107-117	2001	Recombinant kinetoplastid mebrane protein; calcium interaction;	Chemical Analysis
Bohuss, I.; Varga, A.; Barkács, K.; Oertel, N.; Záray, Gy.	Microanalytical determination of metals in selected organs of zebra mussels by total reflection X--ray fluorescence spectrometer	Journal Trace Microprobe Technique	19	177-182	2001	Zebra mussel; metal accumulation, biomonitoring TXRF	Chemical Analysis
Pasadakis, N.; Varotsis, N.; Kallithrakas, N.	The influence of pressure on the asphaltenes content and composition in oils	Petroleum Scince and Technology	19	1219-1227	2001	Precipitation	Chemical Analysis

Autoren	Titel	Zeitschrift	Vol	Seiten	Jahr	Keywords	Gruppe
Pahlke, S.; Fabry, L.; Kotz, L.; Mantler, C.; Ehmann, T.	Determination of ultra trace contaminants on silicon wafer surfaces using total-reflection X-ray fluorescence TXRF ´state of the art´	Spectrochim. Acta Part B	56	2261-2274	2001	VPD; VPD-TXRF; silicon wafer surface; surface metals; WSPS	Review
Esaka, F.; Watanabe, K.; Magara, M.; Hanzawa, Y.; Usuda, S.	Screening of uranium particles by total-reflection X-ray fluorescence spectrometry for safeguards environmental sample analysis	J. Trace and Microprobe Techniques	19	487-496	2001	TXRF; SIMS; uranium; particles; safeguards	Chemical Analysis
Knoth, J.; Beaven, P.; Schwenke, H.; Dobler, M.; Reus, U.	Calibration of total-reflection X-ray fluorescence using a nickel bulk sample	Spectrochim. Acta Part B	56	2275-2281	2001	Quantification; calibration; wafer contamination; TXRF	Surfaces and Layers; Principles
Suzuki, T.; Sasaki, A.; Nakai, I.	Total reflection X-ray fluorescence analysis of cisplatin platinum in human cancerous tissues obtained by biopsy	J. Trace and Microprobe Techniques	19	547-561	2001	Cisplatin; cancerous tissue;	Chemical Analysis
Ayala Jiménez, R.E.	Total reflection X-ray fluorescence spectrometers for multielement analysis: status of equipment	Spectrochim. Acta Part B	56	2331-2336	2001	TXRF; EDXRF; analytical instrumentation	Principles and Instrumentation
Vereecke, G.; et al.	Analysis of trace metals in thin silicon nitride films by total-reflection X-ray fluorescence	Spectrochim. Acta Part B	56	2321-2330	2001	Trace elements; metallic impurities; silicon nitride; thin films	Chemical Analysis
Yamada, T.; Matsuo, M.; Kohno, H.; Mori, Y.	Sensitive detection of trace copper contamination on a silicon wafer by total reflection X-ray fluorescence using W-Lß or Au-Lß excitation soruce	Spectrochim. Acta Part B	56	2307-2312	2001	Wafers; Copper; TXRF	Surfaces and Layers
Mori, A.; Uemura, K.; Yamagami, M.; Yamada, T.	A method of locating dried residue on a semiconductor wafer in vapor phase decomposition-total-reflection X-ray fluorescence spectrometry by monitoring	Spectrochim. Acta Part B	56	2293-2300	2001	Silicon wafer; vapor phase decompostion (VPD); dried residue search; internal	Surfaces and Layers
Nutsch, A.; Erdmann, V.; Zielonka, G.; Pfitzner, L.; Ryssel, H.	Trace analysis for 300 mm wafers and processes with total reflection X-ray fluorescence	Spectrochim. Acta Part B	56	2301-2306	2001	300 mm wafer; reclaim; polishing; silicon; contamination;	Surfaces and Layers
Zarkadas, Ch.; Karydas, A.G.; Paradellis, T.	Determination of uranium in human urine by total reflection X-ray fluorescence	Spectrochim. Acta Part B	56	2505-2511	2001	Uranium; urne; TXRF; chemical treatment	Chemical Analysis

Autoren	Titel	Zeitschrift	Vol	Seiten	Jahr	Keywords	Gruppe
Shin, N. S.; Chang, C. H.; Koo, Y. M.; Padmore, H.	Synchrotron radiation excited total reflection X-ray fluorescence quantitative analysis of Si wafer by absolute fluorescence intensity calculation	Mater. Lett.	49	38-42	2001	synchrotron radiation TXRF; analysis silicon	Chemical Analysis
Kilian, G.; et al.	Some aspects of the high-temperature behavior of bismuth, strontium and barium on silicon surfaces studied by total reflection X-ray fluorescence spectrometry	Spectrochim. Acta Part B	56	2313-2319	2001	Ferroelectric films; metal contamination; annealing behaviour; Elymat; minority	Surfaces and Layers
Klockenkämper, R.; Alt, F.; Brandt, R.; Jakubowski, N.; Messerschmidt, J.; von Bohlen, A.	Results of proficiency testing with regard to sediment analysis by FAAS, ICP-MS and TXRF	J. Anal. At. Spectrom.	16	658-663	2001	Sediment, Round robin, FAAS, ICP-MS	Chemical Analysis
John, A.C.; Kuhlbusch, T.A.J.; Fissan, H.; Schmidt, K.-G.	Size-fractionated sampling and chemical analysis by total-reflection X-ray fluorescence spectrometry of PMx in ambient air and emissions	Spectrochim. Acta Part B	56	2137-2146	2001	Ambient aerosols; emissions; particulate matter (Omx) sampling;	Chemical Analysis
Shin, N.a.; Chang, C.H.; Koo, Y.M.; Padmore, H.	Background spectrum of synchrotron radiation-excited total reflection x-ray fluorescence for Si wafer analysis	X-Ray Spectrom.	30	127-131	2001	Surface contamination; Si-wafer; synchrotron radiation;	Related Methods
Castineira, M.M.; Brandt, R.; von Bohlen, A.; Jakubowski, N.	Development of a procedure for the multi-element determination of trace elements in wine by ICP-MS	Fresenius' J. Anal. Chem.	370	553-558	2001	Wine; multielement; trace element; ICP-MS	Chemical Analysis
Pepponi, G.; Wobrauschek, P.; Streli, C.; Zöger, N.; Hegedüs F.	Synchrotron radiation-induced TXRF of reactor steel samples	X-Ray Spectrom.	30	267-272	2001	reactor steel; rare earth elements; polarization of synchrotron	Chemical Analysis
Fernández-Ruiz, R.; Capmany, J.	Determination of the rare-earth: Nb mass ratio in doped LiNbO3 by the TXRF technique	J. Anal. At. Spectrom.	16	867-869	2001	Rare-earth elements; Nb	Chemical Analysis
Chimidza, S.; Viksna, A.; Lindgren, E.S.	EDXRF and TXRF analysis of aerosol particles and the mobile fraction of soil in Botswana	X-Ray Spectrom.	30	301-307	2001	EDXRF; aerosol particles; soil; mobility	Chemical Analysis
Pérez, R.D.; Sánchez, H.J.; Rubio, M.	Theoretical model for the calculation of interference effects in TXRF and GEXRF	X-Ray Spectrom.	30	292-295	2001	Interference effects; stratified structures; GEXRF; calculation of X-ray propagation	Principles and Instrumentation

Autoren	Titel	Zeitschrift	Vol	Seiten	Jahr	Keywords	Gruppe
Xu, Weiming; Xu, Junqian; Wu, Nianzu; Yan, Jingfeng; Zhu, Yongfa; Huang, Yuying; He, Wei; Xie, Youchang	Study of the diffusion behaviour of MoO3 and ZnO on oxide thin films by SR-TXRF	Surf. Interface Anal	32	301-305	2001	diffusion; zinc oxide molybdenum oxide film; SR-TXRF	Surfaces and Layers
Sures, B.; Zimmermann, J.; Messerschmidt, J.; von Bohlen, A.; Alt, F.	First report on the uptake of automobile catalyst emitted Palladium by European eels (Anguilla anguilla) following experimental experimental exposure to road dust	Environmental Pollution			2001	Palladium (Pd); Platinum-group-metals (PGM); bioavailability;	Chemical Analysis
Streli, C.; Wobrauschek, P.; Beckhoff, B.; Ulm, G.; Fabry, L.; Pahlke, S.	First results of TXRF measurements of low-Z elements on Si wafer surfaces at the PTB plane grating monochromator beamline for undulator radiation at BESSY II	X-Ray Spectrom.	30	24-31	2001	wafer analysis; light elements; synchrotron;	Surfaces and Layers
Mori, Y.	Study of standard sample preparation for total reflection X-ray fluorescence spectrometry and of its application to high-accuracy analysis	Bunseki Kagaku	49	131-132	2001	standard sample preparation; TXRF; semiconductor wafer	Chemical Analysis
Falkenberg, G.; Clauss, O.; Swiderski, A.; Tschentscher, Th.	Upgrade of the x-ray fluorescence beamline at HASYLAB/DESY	X-Ray Spectrom.	30	170-173	2001	x-ray fluorescence; beamline HASYLAB DESY	Principles and Instrumentation
Pepponi, G. et al.	Synchrotron radiation total reflection X-ray fluorescence and energy dispersive X-ray fluorescence analysis on AP1™ films applied to the analysis of trace elements in metal alloys for	Spectrochim. Acta Part B	56	2063-2071	2001	Synchrotron radiation; Sample carrier; ultra thin film sample support;	Chemical Analysis
Schmeling, M.	Total-reflection X-ray fluorescence - a tool to obtain information about different air masses and air pollution	Spectrochim. Acta Part B	56	2127-2136	2001	Atmospheric aerosols; air masses; Chicago; TXRF	Chemical Analysis
Alov, N.V. et al.	Total-reflection X-ray fluorescence study of electrochemical deposition of metals on a glass-ceramic carbon electrode surface	Spectrochim. Acta Part B	56	2117-2126	2001	Analytical signal information; nucleation and growth mechanisms;	Surfaces and Layers
Griesel, S.; Reus, U.; Prange, A.	Electro-deposition as a sample preparation technique for total-reflection X-ray fluorescence analysis	Spectrochim. Acta Part B	56	2107-2115	2001	Electro-deposition; saline matrices; seawater; trace elements	Chemical Analysis
Barreiros, M.A.; et al.	Quality assurance of X-ray spectrometer for chemical analysis	Spectrochim. Acta Part B	56	2095-2106	2001	X-ray spectrometry, quality assurance; quality control; traceability	Chemical Analysis

Autoren	Titel	Zeitschrift	Vol	Seiten	Jahr	Keywords	Gruppe
Beckhoff, B. et al.	Improvement of total reflection X-ray fluorescence analysis of low Z elements on silicon wafer surfaces at the PTB monochromator beamline for undulator radiation	Spectrochim. Acta Part B	56	2073-2083	2001	Monochromator beamline; undulator radiation	Surfaces and Layers
Weber, G.; Messerschmidt, J.; von Bohlen, A.; Alt, F.	Effect of extraction pH on metal speciation in plant root extracts	Fresenius' J. Anal. Chem.	371	921-926	2001	metal species; plant roots; HPLC; TXRF; AAS	Chemical Analysis
Huang Yuying et al.	Beijing synchrotron radiation total-reflection X-ray fluorescence analysis facility and its applications on trace element study of cells	Spectrochim. Acta Part B	56	2057-2062	2001	Synchrotron radiation; trace element; cell; TXRF	Chemical Analysis
Baur, K.; Brennan, S.; Burrow, B.; Werho, D.; Pianetta, P.	Laboratory and synchrotron radiation total-reflection X-ray fluorescence: new perspectives in detection limits and data analysis	Spectrochim. Acta Part B	56	2049-2056	2001	Low Z elements; Stanford Synchrotron Radiation Laboratory	Surfaces and Layers
Ebel, H.; Streli, C.; Pepponi, G.; Wobrauschek, P.	Energy dispersion of X-ray continua in the energy range 8 keV to 16 keV by refraction on Si wafers	Spectrochim. Acta Part B	56	2045-2048	2001	Refractive monochromator; total reflection of X-rays	Principles and Instrumentation
Kubala-Kukus, A. et al.	Determination of concentration distribution of trace elements near the detection limit	Spectrochim. Acta Part B	56	2037-2044	2001	Detection limit; concentration distribution; Simulations	Chemical Analysis
Sánchez, H. J.	Detection limit calculations for the total reflection techniques of X-ray fluorescence analysis	Spectrochim. Acta Part B	56	2027-2036	2001	X-ray fluorescence; total reflection; grazing emission	Related Methods
Zheludeva, S.; Kovalchuk, M.; Novikova, N.	Total reflection X-ray fluorescence study of organic nanostructures	Spectrochim. Acta Part B	56	2019-2026	2001	TR; fluorescence; X-ray standing waves; Langmuir-Blodgett films	Surfaces and Layers
Klockenkämper, R.; von Bohlen, A.	Total-reflection moving towards nanoanalysis: a survey	Spectrochim. Acta Part B	56	2005-2018	2001	Nanoanalysis; ultramicro analysis; ultratrace analysis; surface and thin-	Review
Streli, C. et al.	Synchrotron radiation induced total reflection X-ray fluorescence of low Z elements on Si wafer surfaces at SSRL - comparison of excitation geometries and conditions	Spectrochim. Acta Part B	56	2085- 2094	2001	Low-Z elements; ultra trace levels; Si wafer surfaces; SR-TXRF; Synchrotron	Principles and Instrumentation

Autoren	Titel	Zeitschrift	Vol	Seiten	Jahr	Keywords	Gruppe
Tiwari, M.K.;Gowrishankar, B.; Raghuvanshi, V.K.; Nandedkar, R.V.; Sawhney, K.J.S.	Development of a total reflection X-ray fluorescence spectrometer for ultra-trace element analysis	Bulletin of Materials Science	25	435-441	2002	X-ray spectrometry; detection limits	Principles and Instrumentation
Mori, Y.; Uemura, K.; Iizuka, Y.	Statistics for the accumulation of multi-point mapping of TXRF for the whole-surface analysis of silicon wafers	Adv. X-ray Chem. Anal. Japan	33	155-174	2002		Surfaces and Layers
Karamcheti A.; Watt, V.H.C.; Al-Shareef, H.N.; Luo, T.Y.; Jackson, M.D.; Huff, H.R.; Steinbrüchel, C.	Characterization of Ultrathin Gate Dielectrics Formed by In-Situ Steam Generation with Nitrogen Postprocessing	Journal of Electronic Materials	31	124-128	2002	Gate dielectrics, oxynitride, in-situ steam generation (ISSG), remote	Chemical Analysis
Dogan, M.; Soylak, M.; Elci, L.; von Bohlen, A.	Application of Total Reflection X-Ray Fluorescence Spectrometry in the Textile Industry	Mikrochim. Acta	138	77-82	2002	Textile; Öko-Tex; toxic metals; TXRF	Chemical Analysis
Kurunczi, S.; Török, S.; Beal, J.W.	Investigation of adsorbed mercury distribution in silver coated filters by X-ray fluorescence	J. Radioanal. Nucl. Chem.	253	291-295	2002		Chemical Analysis
Baur, K.; Brennan, S.; Pianetta, P.	Looking at trace imipurities on silicon wafers with synchrotron radiation	Anal. Chem.		609A-616A	2002	Synchrotron radiation; silicon wafer; XANES; solid-state detector;	Review, Related Methods
Zimmermann, S.; Alt, F.; Messerschmidt, J.; von Bohlen, A.; Taraschewski, H.; Sures, B.	Biological availability of traffic-related platinum group elements (Palladium, Platinum and Rhodium) and other metals to the Zebra mussel (Dreiissena polymporpha) in water containing	Environ. Toxicol. Chem.	21	2713-2718	2002		Chemical Analysis
Mori, Y.	TXRF for Semiconductor Applications	Adv. X-ray Anal.	45	523-532	2002		Surfaces and Layers
Mori, Y.; Uemura, K.; Iizuka, Y.	Whole-surface analysis of semiconductor wafrs by accumulating short-time mapping data of total-reflection X-ray fluorescence spectrometry	Anal. Chem.	74	1104-1110	2002	mapping; contamination; wafer;	Surfaces and Layers
Klockenkämper, R.; Becker, H.W.; Bubert, H.; Jenett, H.; von Bohlen, A.	Depth profiles of a shallow implanted layer in a Si wafer determined by different methods of thin-layer analysis	Spectrochim. Acta Part B	57	1593-1599	2002	Depth profiles; Implantation; Si-wafer; Thin-layer analysis; TXRF	Surfaces and Layers

Autoren	Titel	Zeitschrift	Vol	Seiten	Jahr	Keywords	Gruppe
Klockenkämper, R.; von Bohlen, A.; Radke, M.; Knöchel, A.; Palmetshofer, L.	Analytical characterization of ion-implanted conductor paths in Si-wafers by a synchrotron microprobe	X-Ray Spectrom.	31	373-376	2002	Synchrotron microprobe; ion implantation; Si wafer; X-ray spectral	Related Methods
von Bohlen, A.; Klockenkämper, R.; Messerschmidt, J.; Alt, F.	Development and application of a micro-digestion device for elemental analysis of biological samples	Anal. Chim. Acta	471	279-284	2002	High pressure; Micro-digestion; Biological samples; Standard reference	Chemical Analysis
Matsumoto, E.; Simabuco, S.M.; Pérez, C.A.; Nascimento Filho, V.F.	Atmospheric particulate analysis by synchrotron radiation total reflection (SR-TXRF)	X-Ray Spectrom.	31	136-140	2002	Synchrotron; atmospheric particulate	Chemical Analysis
Bennun, L.; Greaves, E.D.; Blostein, J.J.	New procedure for intensity and detection limit determination in spectral trace analysis: application for trace mercury by TXRF	X-Ray Spectrom.	31	289-295	2002	theoretical calibration; trace mercury; modelling;	Chemical Analysis
Tsuji, K.; Wagatsuma, K.	Enhancement of TXRF intensity by using a reflector	X-Ray Spectrom.	31	358-362	2002	Si reflector; enhancement of X-ray intensity; background	Principles and Instrumentation
Alov, N.V.; Oskolok, K.V.	Influence of heterogeneous surface morphology on analytical signal formation in total reflection x-ray fluorescence analysis	X-Ray Spectrom.	31	235-238	2002	Excitation; surface analysis;	Principles and Instrumentation
Fernández-Ruiz, R.; Furió, M.; Cabello Galisteo, F.; Larese, C.; López Granados, M.; Mariscal, R.; Fierro, J.L.G.	Chemical analysis of used three-way catalysts by Total Reflection X-ray Fluorescence	Anal. Chem.	74	5463-5469	2002	Three-way catalyst;	Chemical Analysis
Sakurai, K.; Eba, H.; Inoue, K.; Yagi, N.	Wavelength-dispersive total-reflection X-ray fluorescence with an efficient Johansson spectrometer and an undulator X-ray source: detection of 10-16 g-level trace metals	Anal. Chem.	74	4532-4535	2002	Wavelength-dispersive; Synchrotron undulator; trace	Principles and Instrumentation
Hernández-Caraballo, E.A.; Marc-Parra, L.M.	Direct analysis of blood serum by total reflection X-ray fluorescence spectrometry and application of an artificial neural network appoach for cancer diagnosis	Spectrochim. Acta Part B	58	2205- 2213	2003	Iron; Copper; Zinc; Selenium; Cancer; Artificial neural networks (ANNs)	Chemical Analysis
Streli, C.; Pepponi, G.; Wobrauschek, P.;Beckhoff, B.; Ulm, G.; Pahlke, S.; Fabry, L.; Ehmann, Th.; Kanngießer, B.; Malzer, W.; Jark, W.	Analysis of low Z elements on Si wafer surfaces with undulator radiation induced total reflection X-ray fluorescence at the PTB beamline at BESSY II	Spectrochim. Acta Part B	58	2113- 2121	2003	SR-TXRF; Wafer surface analysis; Thin layer analysis; Raman scattering;	Principles and Instrumentation

Autoren	Titel	Zeitschrift	Vol	Seiten	Jahr	Keywords	Gruppe
Osmic, F.; Wobrauschek, P.; Streli, C.; Pahlke, S.; Fabry, L.	Si drift detector in comparison to Si(Li) detector for total reflection X-ray fluorescence analysis applications	Spectrochim. Acta Part B	58	2123- 2128	2003	Si drift detector; Si(Li) detector	Principles and Instrumentation
Mages, M.; Woelfl, S.; Óvári, M.; v. Tümpling jun, W.	The use of a protable total reflection X-ray fluorescence spectrometer for field investigation	Spectrochim. Acta Part B	58	2129- 2138	2003	Portable TXRF; Field experiments; Contamination; Elbe river; Chilean lakes;	Chemical Analysis
Pepponi, G.; Streli, C.; Wobrauschek, P.; Zamini, S.; Zöger, N.; Falkenberg, G.	Comparison of synchrotron radiation total reflection X-ray fluorescence excitation - detection geometries for samples with differing matrices	Spectrochim. Acta Part B	58	2139- 2144	2003	SR-TXRF; Excitation-detection geometry; Sample matrix	Principles and Instrumentation
Esaka, F.; Watanabe, K.; Onodera, T.; Taguchi, T.; Magara, M.; Usuda, S.	The use of Si carriers for aerosol particle collection and subsequent elemental analysis by total-reflection X-ray fluorescence spectrometry	Spectrochim. Acta Part B	58	2145-2155	2003	Aerosol; Particles; Si; Carriers	Chemical Analysis
Woelfl, S.; Mages, M.; Encina, F.	Cold plasma ashing improves the trace element detection of single Daphnia specimens by total reflection X-ray fluorescence spectrometry	Spectrochim. Acta Part B	58	2157-2168	2003	Trace element analysis; Daphnia; Zooplankton; Bioaccumulation;	Chemical Analysis
Boeykens, S.; Vázquez, C.; Temprano, N.	Macromolecules by total reflection X-ray fluorescence: marking techniques	Spectrochim. Acta Part B	58	2169- 2175	2003	Marking; Labeling; Macromolecules; Polysaccharides	Chemical Analysis
Kröpfl, K.; Záray, Gy.; Ács, É.	Investigation of lead and nickel contaminated natural biofilms	Spectrochim. Acta Part B	58	2177-2181	2003	Lead and nickel; Biofilms; Biomass production	Chemical Analysis
Alvarez, J.; Marcó, L.M.; Arroyo, J.; Greaves, E.D.; Rivas, R.	Determination of calcium, potassium, manganese; iron, copper and zinc levels in representative samples of two onion cultivars using total reflection X-ray fluorescence and	Spectrochim. Acta Part B	58	2183- 2189	2003	Ultrasound; Onion; Calcium; Potassium; Microelements	Chemical Analysis
Marques, A.F.; Queralt, I.; Carvalho, M.L.;Bordalo, M.	Total reflection X-ray fluorescence and energy-dispersive X-ray fluorescence analysis of runoff water and vegetation from abandoned mining of Pb-Zn ores	Spectrochim. Acta Part B	58	2191- 2198	2003	EDXRF; Moss; Grass, Mines	Chemical Analysis
Streli, C.; Pepponi, G.; Wobrauschek, P.; Zöger, N.; Pianetta, P.; Baur, K.; Pahlke, S.; Fabry, L.; Mantler, C.; Kanngießer, B.; Malzer, W.	Analysis of low Z elements on Si wafer surfaces with synchrotron radiation induced total reflection X-ray fluorescence at SSRL, Beamline 3-3: comparison of droplets with spin coated	Spectrochim. Acta Part B	58	2105-2112	2003	Synchrotron radiation; Si wafer; Low Z elements	Principles and Instrumentation

Autoren	Titel	Zeitschrift	Vol	Seiten	Jahr	Keywords	Gruppe
Wagner; A.; Boman, J.	Biomonitoring of trace elements in muscle and liver tissue of freshwater fish	Spectrochim. Acta Part B	58	2215- 2226	2003	Biomonitor; Freshwater fish (Clarias fucus); Trace elements;	Chemical Analysis
Mori, Y.; Uemura, K.; Matsuo, M.; Fukuda, T.; Shimizu, K.; Yamada, T.	TXRF with Simultaneous Multi-Beam Excitation by Utilizing Higher Harmonics	Adv. X-ray Chem. Anal. Japan	34	165-172	2003		Chemical Analysis
Tapia, L.; Suazo, M.; Hödar, C.; Cambiazo, V.; González, M.	Copper exposure modifies the content and distribution of trace metals in mammalian cultured cells	BioMetals	16	169–174	2003	Caco2, copper, copper homeostasis, HepG2, iron, TXRF, zinc	Chemical Analysis
Anjos, M.J.; Lopes, R.T.; de Jesus, E.F.O.; Moreira, S.; Barroso, R.C.; Castro, C.R.F.	Trace element determionation in red and white wines using total-reflection X-ray fluorescence	Spectrochim. Acta Part B	58	2227- 2232	2003	Wine; Trace elements; Synchrotron radiation	Chemical Analysis
Falkenberg, G.; Pepponi, G.; Streli, C.; Wobrauschek, P.	Comparison of conventional and total reflection excitation geometry for ffuorescence X-ray absorption spectroscopy on droplet samples	Spectrochim. Acta Part B	58	2239- 2244	2003	Total reflection; X-ray absorption fine structure spectroscopy; Pb;	Related Methods
Pepponi, G.; Beckhoff, B.; Ehmann, Th.; Ulm, G.; Streli, C.; Fabry, L.; Pahlke, S.; Wobrauschek, P.	Analysis of organic contaminants on Si wafers with TXRF-NEXAFS	Spectrochim. Acta Part B	58	2245- 2253	2003	NEXAFS; Organic contaminants on Si wafers	Related Methods
Fernandes, L.M.P.; Antognini, A.; Boucher, M.; Conde, C.A.N.; Huot, O.; Knowles, P.E.; Kottmann, F.; Ludhova, L.; Mulhauser, F.; Pohl. R.; dos	Applicatin of large-area avalanche photodiodes to X.-ray spectrometry of muonic atoms	Spectrochim. Acta Part B	58	2255-2260	2003	Lamb shift; Muonic atoms X-ray spectrometry; Avalanche	Related Methods
Tiwari, M.K.; Sawhney, K.J.S.	Applicability of a cut-off reflector for grazing incidence X-ray fluorescence analysis	Spectrochim. Acta Part B	58	1895- 1900	2003	X-ray fluorescence; Grazing incidence X-ray fluorescence; Multilayer	Related Methods
Costa, A.C.M.; Anjos; M.J.; Moreira, S.; Lopes, R.T.; de Jesus, E.F.O.	Analysis of mineral water from Brazil using total reflection X-ray fluorescence by synchrotron radiation	Spectrochim. Acta Part B	58	2199- 2204	2003	Mineral water; Trace elements; Synchrotron radiation	Chemical Analysis
Pahlke, S.	Quo Vadis total reflection X-ray fluorescence?	Spectrochim. Acta Part B	58	2025-2038	2003	TXRF; VPD; Wafer; Synchrotron; Solid state detector; Surfaces	Survey

Autoren	Titel	Zeitschrift	Vol	Seiten	Jahr	Keywords	Gruppe
Krzyżanowska, H.; von Bohlen, A.; Klockenkämper, R.	Depth profiles of shallow implanted layers by soft ion sputtering and total-reflection X-ray fluorescence	Spectrochim. Acta Part B	58	2059-2067	2003	Ion sputtering; Implanted layers; Depth profiling; TXRF	Principles and Instrumentation
von Bohlen, A.; Vandenabeele, P.; De Reu, M.; Moens, L.; Klockenkämper, R.; Dekeyzer, B.; Cardon, B.	Pigmente und Tinten in mittelalterlichen Handschriften	Restauro	2/2003	118-122	2003	Q-tip sampling; microanalysis; pigments, inks; manuscripts	Chemical Analysis
von Bohlen, A.; Brink-Kloke, H.; Althoff, C.	Element determination in medieval soil samples by total reflection X.-ray fluorescence analyis	Anal. Chim. Acta	480	317-335	2003	Medieval soil; extraction; TXRF; Dortmund	Chemical Analysis
Cariati, F.; Fermo, P.; Gilardoni, S.; Galli, A.; Milazzo, M.	A new approach for archaeological ceramics analysis using total reflection X-ray fluorescence spectrometry	Spectrochim. Acta Part B	58	177-184	2003	TXRF; ICP-AES; archaeological ceramics; provenance studies	Chemical Analysis
Tsuji, K.; Delalieux, F.	Feasibility study of thress-dimensional XRF spectrometry using μ-X-ray beams under grazing-exit conditions	Spectrochim. Acta Part B	58	2233-2238	2003	Grazing-exit XRF; Micro-XRF; Surface analysis; Depth analysis	Related Methods
Menegário, A.A.; Pellegrinotti, D.C.; Giné, M.F.; Nascimento Filho, V.F.	On-line preconcentration flow system for multi-elemental analysis by total reflection X-ray fluorescence spectrometry	Spectrochim. Acta Part B	58	543-549	2003	TXRF; On-line preconcentration; Flow system; Saliva; River water	Chemical Analysis
Alov, N.V.; Oskolok, K. V.	Formation of binary and ternary metal deposits on glass–ceramic carbon electrode surfaces: electron-probe X-ray microanalysis, total-reflection X-ray fluorescence analysis, X-ray	Spectrochim. Acta Part B	58	735-740	2003	Copper; Cadmium; Lead; Binary and ternary alloy electrodeposit;	Chemical Analysis
Kubala-Kukus, A.; Bana, D.; Braziewicz, J.; Majewska, U.; Pajek, M.	Comparative study of trace element contents in human full-term placenta and fetal membranes by total reflection X-ray fluorescence	Spectrochim. Acta Part B	58	725-734	2003	Total reflection X-ray fluorescence; Human placenta; Fetal membranes;	Chemical Analysis
Hellin, D.; Bearda, T.; Zhao, C.; Raskin,G.; Mertens, P.W.; De Gendt, S.; Heyns, M.M.; Vinckier, C.	Determination of metallic contaminants on Ge wafers using direct- and droplet sandwich etch-total reflection X-ray fluorescence spectrometry	Spectrochim. Acta Part B	58	2093- 2104	2003	Metallic contamination; Ge wafers; Droplet sandwich etch;	Surfaces and Layers
Klockenkämper, R.; Krzyżanowska, H.; von Bohlen, A.	Density-depth profiles of an As-implanted Si wafer studied by repeated planar sputter etching and total reflection x-ray fluorescence analysis	Surf. Interface Anal.	35	829-834	2003	Ion sputtering; Depth profiling; Implanted layers; Mass density; Atomic density;	Principles and Instrumentation

Autoren	Titel	Zeitschrift	Vol	Seiten	Jahr	Keywords	Gruppe
Schwenke, H.; Beaven, P.A.; Knoth, J.; Jantzen, E.	A wavelength-dispersive arrangement for wafer analysis with total reflection X-ray fluorescence spectrometry using synchrotron radiation	Spectrochim. Acta Part B	58	2039-2048	2003	Synchrotron radiation; Wavelength dispersive detection;	Principles and Instrumentation
Mori, Y.; Uemura, K.	Total-reflection X-ray fluorescence analysis for semiconductor process characterization	Spectrochim. Acta Part B	58	2085- 2092	2003	Semiconductor; Vapor phase decomposition; Reference standard	Surfaces and Layers
Yamagami, M.; Ikeshita, A.; Onizuka, Y.; Kojima, S.; Yamada, T.	Development of vapor phase decomposition-total-reflection X-ray fluorescence spectrometer	Spectrochim. Acta Part B	58	2079- 2084	2003	Vapor phase decomposition; Metal contamination; Silicon wafer;	Principles and Instrumentation
Meinschad, Th.; Streli, C.; Wobrauschek, P.; Eisenmenger-Sittner, Ch.	Construction of a windowless Si-anode X-ray tube for a more efficient excitation of low Z elements on Si-wafer surfaces in total reflection fluorescence analysis	Spectrochim. Acta Part B	58	2069- 2077	2003	Light elements; Windowless tube; Si-anode tube; Wafer surface quality	Principles and Instrumentation
Beaven, P.A.; Marmotti, M.; Kampmann, R.; Knoth, J.; Schwenke, H.	Simultaneous acquisition of X-ray spectra using a multi-wire, position-sensitive gas flow detector	Spectrochim. Acta Part B	58	2049-2057	2003	Wavelength dispersive X-ray fluorescence spectrometry;	Principles and Instrumentation
Alov, N.V.; Oskolok, K.V.	Surface morphology characterization using TXRF and SEM	(European) Microscopy and Analysis	81	5-7	2003	analytical signal formation; SEM; EPMA; heterogeneous	Surfaces and Layers
Viksna, A.; Selin Lindgren, E.; Standzenieks, P.; Jacobsson, J.	EDXRF and TXRF analysis of elemental size distributions and environmental mobility of airborne particles in the city of Riga, Latvia	X-Ray Spectrom.	33	414-420	2004	DOI: 10.1002/xrs.742	Chemical Analysis
Kubala-Kukus, A.; Kuternoga, E.; Braziewicz, J.; Pajek, M.	Log-stable concentration distributions of trace elements in biomedical samples	Spectrochim. Acta Part B	59	1711-1716	2004	X-ray fluorescence (XRF, TXRF) methods; Trace elements;	Chemical Analysis
Ardid, M.; Ferrero, J.L.; Juanes, D.; Lluch, J.L.; Roldán, C.	Comparison of total-reflection X-ray fluorescence, static and portable energy dispersive X-ray fluorescence spetrometers for art and archeometry studies	Spectrochim. Acta Part B	59	1581-1586	2004	EDXRF, TXRF; Applications in art and archeometry; Scientific techniques	Chemical Analysis
Gomes, A.C.F.; Menegário, A.A.; Pellegrinotti, D.C.; Giné, M.F.; Nascimento Filho, V.F.	A hydride generation flow system for determination of arsenic and selenium by total reflection X-ray fluorescence spectrometry	Spectrochim. Acta Part B	59	1481-1484	2004	TXRF; Hydride generation; Flow system; Preconcentration	Chemical Analysis

Autoren	Titel	Zeitschrift	Vol	Seiten	Jahr	Keywords	Gruppe
M. Ardid, J.L. Ferrero, D. Juanes, J.L. Lluch and C. Roldán	Comparison of total-reflection X-ray fluorescence, static and portable energy dispersive X-ray fluorescence spectrometers for art and archeometry studies	Spectrochim. Acta Part B	59	1581-1586	2004	EDXRF: energy dispersive X-ray fluorescence spectrometry; TXRF:	Chemical Analysis
Mori, Y.; Uemura, K.; Kohno, H.; Yamagami, M.; Yamada, T.; Shimizu, K.; Onizuka, Y.; Iizuka, Y.	Detection of unknown localized contamination on silicon wafer surface by sweeping-total reflection X-ray fluorescence analysis	Spectrochim. Acta Part B	59	1277-1282	2004	otal reflection X-ray fluorescence (TXRF) analysis; Semiconductor	Surfaces and Layers
Vázquez, C.	The capabilities of total reflection X-ray fluorescence in the polymeric analytical field	Spectrochim. Acta Part B	59	1215-1219	2004	TXRF; Polymer analysis; High viscosity dispersions;	Chemical Analysis
Awane, T.; Kimura, T.; Nishida, K.; Ishikawa, N.; Tanuma, S.	Grazing exit electron probe microanalysis of submicrometer precipitates in a copper base alloy	Spectrochim. Acta Part B	59	1235-1241	2004	X-ray; GE-EPMA analysis; Precipitate	Related Methods
Tani, K.; Iwata, N.; Mitsueda, T.; Ueha, M.; Saisho, H.; Iwasaki, H.	X-ray absorption near edge spectroscopy from reflection x-ray absorption fine structure under the grazing incidence conditions	Spectrochim. Acta Part B	59	1221-1225	2004	ReflXAFS; Reflectivity; Kramers-Kroning relations; XANES; TiSi2; Sb-	Related Methods
Awaji N, Nomura K, Doi S, Takemura M, Kamimuta Y, Takahashi, M.; Ozaki, S.; Takahashi, M.; Iihara, J.; Miyatake, K.; Yamazaki, N.; Inoue, K.; Yagi, N.;	Detection limits of trace elements for wavelength dispersive total X-ray fluorescence under high flux synchrotron radiation	Japanese Journal of Applied Physics, Part 1	43 (4A)	1644-1648	2004	TXRF; detection limits; SR; WD; SPring-8; undulator Scattering;	Principles and Instrumentation
Sparks, C.M.; Beebe, M.R.; Bennett, J.; Foran, B.; Gondran, C.; Hou, A.	Characterization of high-k gate dielectric and metal gate electrode semiconductor samples with a total reflection X-ray fluorescence spectrometer	Spectrochim. Acta Part B	59	1227-1234	2004	Total reflection X-ray fluorescence; TXRF; High-k; Hafnium; Metal gate;	Surfaces and Layers
Tanida, H.	Total-reflection X-ray absorption fine structure on liquid surface	Spectrochim. Acta Part B	59	1071-1076	2004	Total-reflection X-ray absorption fine structure; Solution surface; Monolayer	Review; Related Methods
Iijima, Y.; Tazawa, T.	Application of total reflection X-ray photoelectron spectroscopy to boron and phosphorus on Si wafer surface measurement	Spectrochim. Acta Part B	59	1273-1276	2004	Total reflection X-ray photoelectron spectroscopy; Si wafer; SiB4; P2O5;	Surfaces and Layers
Mages, M.; Woelfl, S.; Óvári, M.; v. Tümpling, W.Jr.; Encina, F.	The use of a portable total reflection X-ray fluorescence spectrometer for trace element determination in freshwater microcrustaceans (Daphnia)	Spectrochim. Acta Part B	59	1265-1272	2004	Trace element analysis; Daphnia; Zooplankton; Total reflection X-ray	Chemical Analysis

Autoren	Titel	Zeitschrift	Vol	Seiten	Jahr	Keywords	Gruppe
Carvalho, M.L.; Marques, A.F.; Lima, M.T.; Reus, U.	Trace elements distribution and post-mortem intake in human bones from Middle Age by total reflection X-ray fluorescence	Spectrochim. Acta Part B	59	1251-1257	2004	Bone; Total-reflection X-ray fluorescence; Trace elements;	Chemical Analysis
Pepponi, G.; Streli, C.; Wobrauschek, P.; Zoeger, N.; Luening, K.; Pianetta, P.; Giubertoni, D.; Barozzi, M.; Bersani, M.	Nondestructive dose determination and depth profiling of arsenic ultrashallow junctions with total reflection X-ray fluorescence analysis compared to dynamic secondary ion mass	Spectrochim. Acta Part B	59	1243-1249	2004	Ultrashallow junction; TXRF; SIMS; Absolute quantification;	Surfaces and Layers
Emoto, T.; Sato, Y.; Konishi, Y.; Ding, X.; Tsuji, K.	Development and applications of grazing exit micro X-ray fluorescence instrument using a polycapillary X-ray lens	Spectrochim. Acta Part B	59	1291-1294	2004	Grazing exit micro X-ray fluorescence; X-ray lens; Quinoa	Related Methods
Awaji, N.	Wavelength dispersive grazing incidence X-ray fluorescence of multilayer thin films	Spectrochim. Acta Part B	59	1133-1139	2004	X-ray fluorescence; X-ray reflectivity; Wavelength dispersive	Related Methods
von Bohlen, A.; Krzyzanowska, H.; Klockenkämper, R.	A broad beam ion-source used for a planar sputter-etching of shallow layers from flat samples and determination of their mass density	Nucl. Instrum. Methods B	217	158-166	2004	Shallow layers; Ion etching; Ion implantation; Depth profiling; Mass	Principles and Instrumentation
Verbi, F.M.; Arruda, S.C.C.; Rodriguez, A.P.M.; Perez, C.A.; Arruda, M.A.Z.	Metal-binding proteins scanning and determination by combining gel electrophoresis, synchrotron radiation X-ray fluorescence and atomic spectrometry	J. Biochem. Biophys. Meth.	62 (2)	97-109	2004	metal-binding proteins; metal determination; SDS-PAGE; synchrotron	Chemical Analysis
Frost, M. R.; French, M.; Harris, W.	Application of TXRF for ion implanter dose matching experiments	Appl. Surf. Sci.	231-232	734-737	2004	dose matching; SIMS; TXRF; ion implantation; metrology	Chemical Analysis
Weber, Guenther; Messerschmidt, J.; von Bohlen, A.; Kastenholz, B.; Guenther, K.	Improved separation of palladium species in biological matrices by using a combination of gel permeation chromatography and isotachophoresis	Electrophoresis	25(12)	1758-1764	2004		Chemical Analysis
Óvári, M.; Mages, M.; Woelfl, S.; von Tuempling, W.; Kröpfl, K.; Záray, Gy.	Total reflection X-ray fluorescence spectrometric determination of element inlets from mining activities at the upper Tisza catchment area, Hungary	Spectrochim. Acta Part B	59	1173-1181	2004	Total reflection X-ray fluorescence; Trace elements; Biofilms; Tisza river; Mining	Chemical Analysis
Schmeling, M.	Characterization of urban air pollution by total reflection X-ray fluorescence	Spectrochim. Acta Part B	59	1165-1171	2004	Aerosols; Pollution; Total reflection X-ray fluorescence; Elemental	Chemical Analysis

Autoren	Titel	Zeitschrift	Vol	Seiten	Jahr	Keywords	Gruppe
Schwenke, H.; Knoth, J.; Beaven, P. A.; Kiehn R.; Buhrz, J.	A laser plasma X-ray source for the analysis of wafer surfaces by grazing emission X-ray fluorescence spectrometry	Spectrochim. Acta Part B	59	1159-1164	2004	Laser plasma X-ray source; Grazing emission X-ray fluorescence	Principles and Instrumentation
Martinez, T.; Lartigue, J.; Avila-Perez, P.; Zarazua, G.; Navarrete, M.; Tejeda, S.; Ramirez, A.	Determination of trace elements in blood samples by TXRF analysis	Journal of Radioanalytical and Nuclear Chemistry	259(3)	511-514	2004		Chemical Analysis
Tiwari, M.K.; Sawhney, K.J.S.; Gowri Sankar, B.; Raghuvanshi, V.K.; Nandedkar, R.V.	A simple and precise total reflection X-ray fluorescence spectrometer: construction and its applications	Spectrochim. Acta Part B	59	1141-1147	2004	X-ray fluorescence; Total reflection X-ray fluorescence; Grazing incidence X-	Principles and Instrumentation
Mori, Y.; Uemura, K.	Development of a standard sample preparation method for total-reflection X-ray fluorescence analysis and its semiconductor applications	Bunseki Kagaku	53	61-69	2004		Chemical Analysis
Wagner, A.; Boman, J.	Biomonitoring of trace elements in Vietnamese freshwater mussels	Spectrochim. Acta Part B	59	1125-1132	2004	Biomonitoring; Freshwater mussels (Pletholophus swinhoei); Graphite	Chemical Analysis
Miller, T.C.; Sparks, C.M.; Havrilla, G.R.; Beebe, M.R.	Semiconductor applications of nanoliter droplet methodology with total reflection x-ray fluorescence analysis	Spectrochim. Acta Part B	59	1117-1124	2004	Nanoliter dried spot deposition; Total reflection X-ray fluorescence; Vapor	
Mukoyama, T.	Theory of X-ray absorption and emission spectra	Spectrochim. Acta Part B	59	1107-1115	2004	X-ray absorption; Emission spectra; Dipole matrix element	Related Methods; Review
M. Pajek, A. Kubala-Kukuś and J. Braziewicz	Censoring: a new approach for detection limits in total-reflection X-ray fluorescence	Spectrochim. Acta Part B	59	1091-1099	2004	Total-reflection X-ray fluorescence (TXRF); Trace elements; Detection	Review
Lué M. Marcó P.; Edwin A. Hernández-Caraballo	Direct analysis of biological samples by total reflection X-ray fluorescence	Spectrochim. Acta Part B	59	1077-1090	2004	Direct analysis; Total reflection X-ray fluorescence; Clinical samples	Review
Kubala-Kukuś, A.; Braziewicz, J.; Pajek, M.	Total-reflection X-ray fluorescence studies of trace elements in biomedical samples	Spectrochim. Acta Part B	59	1283-1289	2004	X-ray fluorescence; TXRF method; Trace elements; Concentration	Chemical Analysis

Autoren	Titel	Zeitschrift	Vol	Seiten	Jahr	Keywords	Gruppe
Egorov, V.K.; Egorov, E.V.	The experimental background and the model description for the waveguide-resonance propagation of X-ray radiation through a planar narrow extended slit	Spectrochim. Acta Part B	59	1049-1069	2004	X-ray external total reflection; X-ray slitless collimator; Interference field of	Review
Streli, C.; Wobrauschek, P.; Schraik, I.	Comparison of SiLi detector and silicon drift detector for the determination of low Z elements in total reflection X-ray fluorescence	Spectrochim. Acta Part B	59	1211-1213	2004	TXRF; SiLi; SDD; low energy X-rays	Principles and Instrumentation
Hellin, D.; Rip, J.; Arnauts, S.; De Gendt, S.; Mertens, P.W.; Vinckier, C.	Validation of vapor phase decomposition–droplet collection–total reflection X-ray fluorescence spectrometry for metallic contamination analysis of silicon wafers	Spectrochim. Acta Part B	59	1149-1157	2004	VPD–DC–TXRF; Recovery rate; Contamination analysis; Validation;	Chemical Analysis
Zimmermann, S.; Messerschmidt, J.; von Bohlen, A.; Sures, B.	Determination of Pt, Pd and Rh in biological samples by electrothermal atomic absorption spectrometry as compared with adsorptive cathodic stripping voltammetry and total	Anal. Chem. Acta	498	93-104	2004		Chemical Analysis
Cunha e Silva, R.M.; Almeida, E.; Valencia, E.P.E.; Nascimento Filho, V.F.	Determination of Fe, Cu and Zn in sugar-cane spirits commercialized in Southeastern Brazil by TXRF	Journal of Radioanalytical and Nuclear Chemistry	260	3 - 7	2004		Chemical Analysis
Koulouridakis, P.E.; Domazos, E.A.; Galani-Nikolakaki, S.M.; Kallithrakas-Kontos, N.G.	Low Level Lead Determination After Membrane Complexation and TXRF Analysis	Microchim. Acta	146	245–250	2004	TXRF; lead; Nafion; water analysis	Chemical Analysis
Ostachowicz, B.; Boruchowska, M.; Lankosz, M.; et al.	Application of the TXRF method to the elemental analysis of cerebrospinal fluid in amyotrophic lateral sclerosis	X-Ray Spectrom.	33 (1)	46-49	2004		Chemical Analysis
Ardid, M.; Ferrero, J.L.; Juanes, D.; Lluch, J.L.; Roldán, C.	Comparison of total-refelctin X-ray fluorescence, static and portable energy dispersive X-ray fluorescence spectrometers for art and archeometry studies	Spectrochim. Acta Part B	59	1581-1586	2004	EDXRF; Applications in art and archeometry; Scientific techniques	Chemical Analysis
Gomes, A.C.F.; Menegário, A.A.; Pellegrinotti, D.C.; Giné, M.F.; Nascimento Filho, V.F.	A hydride generation flow system for determination of arsenic and selenium by total reflection X-ray fluorescence spectrometry	Spectrochim. Acta Part B	59	1481-1484	2004	Hydride generation; Flow system; Precencentration	Chemical Analysis
Pepponi, G.; Lazzeri, P.; Coghe, N.; Bersani, M.; Gottardini, E.; Cristofolini, F.; Clauser, G.; Torboli, A.	Total reflection X-ray fluorescence analysis of pollen as an indicator for atmospheric pollution	Spectrochim. Acta Part B	59	1205-1209	2004	Pollution; Bio-indicator; Pollen; Suspension; TXRF	Chemical Analysis

Autoren	Titel	Zeitschrift	Vol	Seiten	Jahr	Keywords	Gruppe
Holynska, B.; Gilewicz-Wolter, J.; Ostachowicz, B.; Bielewski, M.; Streli, C.; Wobrauschek, P.	Study of the deterioration of sandstone due to acid rain and humid SO2 gas	X-Ray Spectrom.	33	342-348	2004		Chemical Analysis
Gomes, A.C.F.; Menegário, A.A.; Pellegrinotti, D.C.;Giné, M.F.; Nascimento Filho, V.F.	A hydride generation flow system for determination of arsenic and selenium by total reflection X-ray fluorescence spectrometry	Spectrochim. Acta Part B	59	1481-1484	2004	TXRF; Hydride generation; Flow system; Preconcentration	Chemical Analysis
Zereini, F.; Alt, F.; Messerschmidt, J.; von Bohlen, A.; Liebl, K.; Püttmann, W.	Concentration and distribution of platinum group elements (Pt, Pd, Rh) in airborne particulate matter in Frankfurt am Main, Germany	Environm. Sci. Technol.	38	1686-1692	2004		Chemical Analysis
Kallithrakas-Kontos, N.	TXRF heavy metal analysis after immobilization as PAN complexes	X-Ray Spectrom.	33	12-15	2004	preconcentration; immobilization of heavy metals;	Chemical Analysis
Egorov, V.K.; Egorov, E.V.	The experimental background and the model description for the waveguide-resonance propagation of X-ray radiation through a planar narrow extended slit	Spectrochim. Acta part B	59	1049-1069	2004	X-ray flux; Light-attenuated internal total reflection; Planar X-ray	Principles and Instrumentation
Koulouridakis, P.E.; Kallithrakas-Kontos, N.G.	Selective mercury determination after membrane complexation and total reflection X-ray fluorescence analysis	Anal. Chem.	76 (15)	4315-4319	2004	Water	Chemical Analysis
Török, S.; Osan, J.; Beckhoff, B.; Ulm, G.	Ultratrace speciation of nitrogen compounds in aerosols collected on silicon wafer surfaces by means of TXRF-NEXAFS	Powder Diffr.	19 (1)	81-86	2004	Low-Z-elements; Grating monochromator beamline; Single-	Principles and Instrumentation
Woelfl, S.; Mages, M.; Mercado, S.; et al.	Determination of trace elements in planktonic microcrustaceans using total reflection X-ray fluorescence (TXRF): First results from two Chilean lakes	Anal. Bioanal. Chem.	378 (4)	1088-1094	2004		Chemical Analysis
Mages, M.; Ovari, M.; von Tumpling, W.; et al.	Biofilms as bio-indicator for polluted waters? Total reflection X-ray fluorescence analysis of biofilms of the Tisza river (Hungary)	Anal. Bioanal. Chem.	378 (4)	1095-1101	2004		Chemical Analysis
von Bohlen, A.	Quantitative analysis of minor and trace elements in historical varnishes by total reflection X-ray fluorescence	Anal. Letters	37	491-498	2004		Chemical Analysis

Autoren	Titel	Zeitschrift	Vol	Seiten	Jahr	Keywords	Gruppe
Koch, J.; von Bohlen, A.; Hergenröder, R.; Niemax, K.	Particle size distribution and composition of aerosols produced by near-IR femto- and nanosecond laser ablation of brass	J. Anal. At. Spectrom.	19	267-272	2004	Laser ablation; Aerosol; Particle distribution;	Chemical Analysis
Marco P.; Lue M.; Hernandez-Caraballo, Edwin A.	Direct analysis of biological samples by total reflection X-ray fluorescence	Spectrochim. Acta Part B	59	1077-1090	2004	direct analysis; clinical samples; fresh water algae; mircrowave digestion	Chemical Analysis
Streli, C.; Wobrauschek, P.; Pepponi, G.; Zoeger, N.	A new total reflection X-ray fluorescence vacuum chamber with sample changer analysis using a silicon drift detector for chemical analysis	Spectrochim. Acta Part B	59	1199-1203	2004	TXRF; Vacuum chamber; SDD	Principles and Instrumentation
Ovari, M.; Mages, M.; Woelfl, S.; von Tuempling, W.; Kropfl, K.; Zaray, Gy.	Total reflection X - ray fluorescence spectrometric determination of element inlets from mining activities at the upper Tisza catchment area, Hungary	Spectrochim. Acta Part B	59	1173-1181	2004		Chemical Analysis
Hallquist, M.; Boman, J.	Analysis of organic substances and trace elements in aerosol samples using Fourier transform infra-red and total reflection X-ray fluorescence methods, initial experiments	Spectrochim. Acta Part B	59	1193-1197	2004	Fourier transform infra-red spectroscopy; Zincselenide plates;	Chemical Analysis
Awaji, N.	Performance of synchrotron radiation total reflection x-ray fluorescence for the evaluation of semiconductor materials	Rigaku Janaru	35	18-26	2004		Surfaces and Layers
Boeykens, S.; Vázquez, C.	Preliminary classification of polymers by using total-reflection X-ray fluorescence spectra	Spectrochim. Acta Part B	59	1189-1192	2004	Polymers; X-ray fluorescence; Chemometric	Chemical Analysis
Carpanese, C.; Crivelli, B.; Caniatti, M.	Study on deposition kinetics of high-K materials by X-ray fluorescence techniques	Spectrochim. Acta Part B	59	1183-1187	2004	deposition kinetics; layer thickness;	Surfaces and Layers
Hellin, D.; Onsia, B.; Delabie, A.; De Gendt, S.; Vinckier, C.	The role of TXRF in the introduction of high-k materials into IC processing	Proceedings - Electrochemical Society (2004)		199-211	2004		
Tsuji, K.; Delalieux, F.	Characterization of x-rays emerging from between reflector and sample carrier in reflector-assisted TXRF analysis	X-Ray Spectrom.	33	281-284	2004		Principles and Instrumentation

Autoren	Titel	Zeitschrift	Vol	Seiten	Jahr	Keywords	Gruppe
Costa, A.C.M.; Anjos, M.J.; Lopes, R.T.; Pérez, C.A.; Castro, C.R.F.	Multi-element analysis of sea water from Sepetiba Bay, Brazil, by total reflection x-ray fluorescence spectrometry using synchrotron radiation	X-ray Spectrom.	34	183-188	2005	trace elements; surface water; synchrotron	Chemical Analysis
Tiwari, M.K.; Naik, S.R.; Lodha, G.S.; Nandedkar, R.V.	Effect of energy dependence of primary beam divergence on the X-ray standing wave characterization of layered materials	Anal. Sci.	21	757-762	2005	X-ray standing wave (XSW); Synchrotron; Beam divergence; multilayer	Surfaces and Layers
Klockenkämper, R.; Becker, M.; von Bohlen, A.; Becker, H.W.; Krzyzanowska, H.; Palmetshofer, L.	Near-surface density of ion-implanted Si studied by Rutherford backscattering and total-reflection x-ray fluorescence	J. Appl.Phys.	98	033517-1-033517-5	2005	TXRF; RBS; implantation	Surfaces and Layers
Sanchez, H.J.; Valentinuzzi, M.C.	Experimental characterization of beam guides for TXRF	Radiat. Phys. Chem.	73 (5)	243-247	2005	X-ray fluorescence; Spectrometer; Emission	Principles and Instsrumentation
Civici, N.; Demko, O.; Clark, R.J.H.	Identification of pigments used on late 17th century Albanian icons by total reflection X-ray fluorescence and Raman microscopy	J Cult. Herit.	6 (2)	157-164	2005	Albanian icons; constantin leromonachou; pigment analysis;	Chemical Analysis
Verbi, F.M.; Arruda, S.C.C.; Rodriguez, A.P.M.; Pérez, C.A.; Arruda, M.A.Z.	Metal-binding proteins scanning and determination by combining gel electrophoresis, synchrotron radiation X-ray fluorescence and atomic spectrometry	J. Biochem. Biophys. Methods	62	97–109	2005	Metal-binding proteins; Metal determination; SDS-PAGE; Synchrotron	Chemical Analysis
Tiwari, M.K.; Modi, M.H.; Lodha, G.S.; Sinha, A.K.; Sawhney, K.J.S.; Nandedkar, R.V.	Non-destructive surface characterization of float glass: X-ray reflectivity and grazing incidence X-ray fluorescence analysis	J. Non-Cryst. Sol.	351	2341-2347	2005	oxidation state; depth profiles; tin; multilayer; penetration;	Related Methods
Zucchi, O.L.A.D.; Moreira, S.; de Jesus, E.F.O.; Neto, H.S.; Salvador, M.J.	Characterization of Hypoglycemiant Plants by Total Reflection X-ray Fluorescence Spectrometry	Biological Trace Element Research	103	277-290	2005	Hypoglycemiant plants; medicinal plants; diabetes mellitus; syncrotron	Related Methods
El-Hami, K.; Kuwajima, S.; Micheletto, R.; Matsushige, K.	Carbon Nanotube/P(VDF-TrFE) Nano-Composite Characterization by Total Reflection X-Ray Fluorescence	J. Appl. Spectrosc.	72	771-774	2005	nano-composite, carbon nanotubes, total x-ray fluorescence, single-	Chemical Analysis
Hellin, D.; Delabie, A.; Puurunen, R.L.; Beaven, P.; Conard, T.;, Brijs, B.; De Gendt, S.; Vinckier, C.	Grazing incidence-X-ray fluorescence spectrometry for the compositional analysis of nanometer-thin high-kappa dielectric HfO2 layers	Anal. Sci.	21	845-850	2005	Surface; Growth; Films	Surfaces and Layers

Autoren	Titel	Zeitschrift	Vol	Seiten	Jahr	Keywords	Gruppe
Varga, I.; Szebeni, A.; Szoboszlai, N. et al.	Determination of trace elements in human liver biopsy samples by ICP-MS and TXRF: hepatic steatosis and nickel accumulation	Analytical and Bioanalytical Chemistry	383	476-482	2005	X-Ray-fluorescence; Bioanalytical samples; Multielement	Chemical Analysis
Kurunczi, S.; Sakurai, K.	Natural water specimen preparation for TXRF analysis using a Johansson wavelength-dispersive spectrometer	X-Ray Spectrom.	34 (1)	56-58	2005		Chemical Analysis
Fernández-Ruiy, R.; Bermúdez, V.	Determination of the Ta and Nb ratio in LiNb1-xTaxO3 by total reflection X-ray fluorescence spectrometry	Spectrochim. Acta Part B	60	231-235	2005	TXRF; Lithium niobate tantalate; XRD; Lattice parameter	Chemical Analysis
Carvalho, M.L.; Ascensao, L.; Magalhaes, T.; et al.	EDXRF and TXRF application to cadmium toxicity in Acer pseudoplatanus L. cells: cytological features and cation interactions	X-Ray Spectrom.	34	406-410	2005		Chemical Analysis
Peschel, B.U.; Fittschen, U.E.A.; Pepponi, G.; et al.	Direct analysis of Al2O3 powders by total reflection X-ray fluorescence spectrometry	Anal. Bioanal. Chem.	382	1958-1964	2005		Chemical Analysis
Matsuoka, Y.; Hosokawa, Y.; Hino, M. et al.	Study of the sampling method of blood samples for total-reflection x-ray fluorescence	Bunseki Kagaku	54	749-753	2005	TXRF; sampling methods; whole blood; destruction of the red blood cells	Chemical Analysis
von Bohlen, A.; Klockenkämper, R.	Parasitic ion-implantation produced by a Kaufman-type ion source used for planar etching of surfaces	Anal. Bioanal. Chem.	382	1975-1980	2005		Chemical Analysis
Stosnach, H.	Environmental trace-element analysis using a benchtop total reflection X-ray, fluorescence spectrometer	Anal. Sci.	21	873-876	2005	benchtop; TXRF;	Chemical Analysis
Hellin, D.; Rip, J.; Geens, V.; Delande, T.; Conard, T.; De Gendt, S.; Vinckier, C.	Remediation for TXRF saturation effects on microdroplet residues from preconcentration methods on semiconductor wafers	J. Anal. At. Spectrom.	20	652-658	2005	X-ray-fluorescence; Vapor-phase decomposition; Silicon-Wafers;	Chemical Analysis
Hatzistavros, V.; Koulouridakis, P.; Kallithrakas-Kontos, N.	Complexing membrane for Uranium detection by total reflection X-ray fluorescence	Anal. Sci,	21	823-826	2005	PVC membrane; complexing; uranium	Chemical Analysis

Autoren	Titel	Zeitschrift	Vol	Seiten	Jahr	Keywords	Gruppe
Lindner, H.; Koch, J.; Niemax, K.	Production of Ultrafine Particles by Nanosecond Laser Sampling Using Orthogonal Prepulse Laser Breakdown	Anal. Chem.	77	7528–7533	2005		Chemical Analysis
Mori, Y.	Summary of ISO/TC201 Standard: XIX ISO 17331:2004 - Surface chemical analysis - Chemical methods for the collection of elements from the surface of silicon-wafer working	Surf. Interface Anal.	37	522-523	2005	reference material; chemical preconcentration; VPD; vapour-phase	Surfaces and Layers
Hellin, D.; Geens, V.; Teerlinck, I.; Van Steenbergen, J.; Rip, J.; Laureyn, W.; Raskin, G.; Mertens, P.W.; De Gendt, S.; Vinckier, C.	Vapor phase decomposition-droplet collection-total reflection X-ray fluorescence spectrometry for metallic contamination analysis on Ge wafers	Spectrochim. Acta Part B	60	209-213	2005	Vapor phase decomposition-droplet collection; Metallic	Chemical Analysis
Mori, Y.; Uemura, K.; Kohno, H.; Yamagami, M.; Shimizu, K.; Onizuka, Y.; Iizuka, Y.	Rapid Entire-Surface Mapping of Metal Contaminations on Silicon Wafers by Sweeping-Total Reflection X-Ray Fluorescence Spectroscopy (Sweeping-TXRF)	Adv. X-ray Chem. Anal. Japan	36	275-284	2005		Surfaces and Layers
Sanchez, H.J.; Valentinuzzi, M.C.	Numerical simulations of photon transport inside a beam guide	X-Ray Spectrom.	34	164–168	2005		Principles and Instrumentation
Streli, C.; Pepponi, G.; Wobrauschek, P.; Jokubonis, C.; Falkenberg, G.; Zaray, G.	A new SR-TXRF vacuum chamber for ultra-trace analysis at HASYLAB, Beamline L	X-Ray Spectrom.	34	451-455	2005	X-Ray fluorescence; Radiation total-reflection; Synchrotron-	Principles and Instrumentation
Bichinho, K.M.; Pires, G.P.; Stedile, F.C.; dos Santos, J.H.Z.; Wolf, C.R.	Determination of catalyst metal residues in polymers by X-ray fluorescence	Spectrochim. Acta Part B	60	500-604	2005	Metal; Polymer; Rutherford backscattering spectrometry; XRF;	Chemical Analysis
Varga, I.	Assessment of the contamination problems resulting from the use of stainless steel needles in liver biopsies by total reflection X-ray fluorescence and inductively coupled plasma	Spectrochim. Acta Part B	61	1201-1204	2006	Liver biopsy;Steatosis; Nickel; ICP-MS	Chemical Analysis
de Vives, A.E.S.; Moreira, S.; Boscolo Breinza, S.M.; Silva Medeiros, J.G.; Tomazello Filho, M.; Domingues Zucchi, O.L.A.; do Nascimento Filho,	Monitoring of the environmental pollution by trace element analysis in tree-rings using synchrotron radiation total reflection X-ray fluorescence	Spectrochim. Acta Part B	61	1170-1174	2006	Heavy metal; Environmental contamination; Tree-ring	Chemical Analysis
Misra, N.L.; Dhara, S.; Singh Mudher; K.D.	Uranium determination in seawater by total reflection X-ray fluorescence spectrometry	Spectrochim. Acta Part B	61	1166-1169	2006	Trace element; Solvent extraction; Seawater; Nuclear reactor	Chemical Analysis

Autoren	Titel	Zeitschrift	Vol	Seiten	Jahr	Keywords	Gruppe
Woelfl; S.; Mages, M.; Òvari, M.; Geller; W.	Determination of heavy metals in macrozoobenthos from the rivers Tisza and Szamos by total reflection X-ray fluorescence spectrometry	Spectrochim. Acta Part B	61	1153-1157	2006	Trace element analysis; Heavy metals; Zoobenthos; Bioaccumulation	Chemical Analysis
Sparks, C.M.; Gondran, C.H.; Havrilla, G.J.; Hastings, E.P.	Automated nanoliter solution deposition for total reflection X-ray fluorescence analysis of semiconductor samples	Spectrochim. Acta Part B	61	1091-1097	2006	Vapor phase decomposition; Nanoliter dried spot deposition	Principles and Instrumentation
Serpa, R.F.B.; de Jesus, E.F.O.; Anjos, M.J.; do Carmo, M.G.T.; Moreira, S.; Rocha, M.S.; Martinez, A.M.B.; Lopes, R.T.	Elemental concentration analysis in brain structures from young, adult and old Wistar rats by total reflection X-ray fluorescence with synchrotron radiation	Spectrochim. Acta Part B	61	1205-1209	2006	Brain; Trace elements; Aging; SR-TXRF	Chemical Analysis
Custo, G.; Litter, M.I.; Rodríguez, D.; Vázquez, C.	Total reflection X-ray fluorescence trace mercury determination by trapping complexation: Application in advanced oxidation technologies	Spectrochim. Acta Part B	61	1119-1123	2006	Heterogeneous photocatalysis; Mercury; EDTA; APDC	Chemical Analysis
Stosnach, H.	On-site analysis of heavy metal contaminated areas by means of total reflection X-ray fluorescence analysis (TXRF)	Spectrochim. Acta Part B	61	1141-1145	2006	On-site analysis; Environmental	Chemical Analysis
Boeykens, S.; Caracciolo, N.; D'Angel, M.V.; Vázquez, C.	Metal ions diffusion through polymeric matrices: A total reflection X-ray fluorescence study	Spectrochim. Acta Part B	61	1236-1239	2006	Polymer analysis; Ionic diffusion; Scleroglucan; Polyoxyethylene	Chemical Analysis
Waldschläger; U.	Recent and future developments in low power total reflection X-ray fluorescence spectroscopy	Spectrochim. Acta Part B	61	1115-1118	2006	Low power; Instrumenrt development	Principles and Instrumentation
Serpa, R.F.B.; de Jesus, E.F.O.; Anjos, M.J.; Lopes, R.T.; do Carmo, M.G.T.; Rocha, M.S.; Rodrigues, L.C.; Moreira, S.; Martinez, A.M.B.	Cognitive impairment related changes in the elemental concentration in the brain of old rat	Spectrochim. Acta Part B	61	1219-1223	2006	Brain; Trace element; Learning; Memory; SR-TXRF	Chemical Analysis
Rostam-Khani, P.; Philipsen, J.; Jansen, E.; Eberhard, H.; Vullings, P.	Quantitative analysis of surface contaminants on silicon wafers by means of TOF-SIMS	Appl. Surf. Sci.	252 (19)	7255-7257	2006	trace metals, TOF-SIMS, VPD, ICP-MS, quantification, RSF	Chemical Analysis
Moreira, S.; Vives, A.E.S.; Zucchi, O.L.A.D.; de Jesus, E.F.O.; Nascimento, V..F; Brienza, S.M.B.	Analysis of beers from Brazil with synchrotron radiation total reflection X-ray fluorescence	J. Radioanal. Nucl. Chem.	270 (1)	167-171	2006	ABSORPTION SPECTROMETRY; TRACE-ELEMENTS	Chemical Analysis

Autoren	Titel	Zeitschrift	Vol	Seiten	Jahr	Keywords	Gruppe
Egorov, V.K.; Egorov, E.V.	Nanophotonics and nanometrology with planar X-ray waveguide-resonator	Appl. Surf. Sci.	253 (1)	138-144	2006	interference field of X-ray standing wave, total reflection X-ray fluorescence	Principles and Instrumentation
Tsuji, K.; Kawamata, M.; Nishida, Y.; Nakano, K.; Sasaki, K.	Micro total reflection x-ray fluorescence (mu-TXRF) analysis	X-Ray Spectrom.	35 (6)	375-378	2006	surface, micro-distribution	Principles and Instrumentation
Majewska, U.; Banas, D.; Braziewicz, J.; Kubala-Kukus, A.; Pajek, M.; Wudarczyk, J.	Improvement of a TXRF setup to obtain detection limit in the low ppb range	X-Ray Spectrom.	35 (6)	323-328	2006	Sample carrier; reflector, selenium; tissue, copper, zinc	Principles and Instrumentation
Roka, A.; Varga, I.; Inzelt, G.	Electrodeposition and dissolution of yttrium-hexacyanoferrate layers	Electrochim. Acta	51 (28)	6243-6250	2006	yttrium-hexacyanoferrate, electrodeposition, electrodissolution,	Chemical Analysis
Granados, A.L.; Galisteo, F.C.; Mariscal, R.; Alifanti, A.; Gurbani, A.; Fierro, J.L.G.; Fernandez-Ruiz, R.	Modification of a three-way catalyst washcoat by aging: A study along the longitudinal axis	Appl. Surf. Sci.	252 (24)	8442-8450	2006	vehicle-aged TWC deactivation, CePO4 formation, washcoat sintering, Pb	Chenical Analysis
de la Fuente, J.L.G.; Martinez-Huerta, M.V.; Rojas, S.; Terreros, P.; Fierro, J.L.G.; Pena, M.A.	Methanol electrooxidation on PtRu nanoparticles supported on functionalised carbon black	Catal. Today	116 (3)	422-432	2006	Pt-Ru catalysts, direct methanol fuel cells, carbon	Chenical Analysis
Okhrimovskyy, A.; Saito, K.; Tsuji, K.	Theoretical characterization of reflector-assisted TXRF analysis	e-J. Surf. Sci. Nanotech. Vol.	4	579-583	2006	X-ray scattering, diffraction, and reflection; Cobalt; Silicon; Computer	Principles and Instrumentation
Valentinuzzi, M.C.; Sánchez, H.J.; Abraham, J.	Total reflection X-ray fluorescence analysis of river waters in its stream across the city of Cordoba, in Argentina	Spectrochim. Acta Part B	61	1175-1179	2006	Water contamination; Beam guides	Chemical Analysis
Zarazua, G.; Ávila-Pérez, P.; Tejeda, S.; Barcelo-Quintal, I.; Martínez, T.	Analysis of total and dissolved heavy metals in surface water of a Mexican polluted river by Total Reflection X-ray Fluorescence Spectrometry	Spectrochim. Acta Part B	61	1180-1184	2006	Water; Pollution; Heavy metals	Chemical Analysis
Civici, N.	Non-destructive identification of inorganic pigments used in 16-17th century Albanian icons by total reflection X-ray fluorescence analysis	J. Cult. Herit.	7 (4)	339-343	2006	Albanian icons, Onufri Qiprioti, inorganic pigments, pigment analysis,	Chemical Analysis

Autoren	Titel	Zeitschrift	Vol	Seiten	Jahr	Keywords	Gruppe
de la Fuente, J.L.G.; Martinez-Huerta, M.V.; Rojas, S.; Terreros, P.; Fierro, J.LG.; Pena, M.A.	Methanol electrooxidation on PtRu nanoparticles supported on functionalised carbon black	Catal. Today	116	422-432	2006	Pt-Ru catalysts, direct methanol fuel cells, carbon; Surface chemistry;	Chemical Analysis
Koulouridakis, P.E.; Kallithrakas-Kontos, N.G.; Gekas, V.C.	Seawater mercury analysis at PPB levels	Instrumentation Science & Technology	34	425-433	2006	TXRF, mercury, membrane, seawater, water analysis, Lead	Chemical Analysis
Moreira, S.; Vives, A.E.S.; Nascimento, V.F.; Zucchi, O.L.A.D.; Brienza, S.M.B.	Evaluation of element availability in bottom sediments by synchrotron total reflection X-ray fluorescence analysis (SR-TXRF)	J. Radioanal. Nucl. Chem.	270	87-91	2006		Chemical Analysis
Woelfl, S.; Mages, M.; Encina, F.; Bravo, F.	Trace metals in microcrustaceans and Brazilian waterweed from a contaminated Chilean wetland using total reflection X-ray fluorescence spectrometry	Microchimica Acta	145	261-268	2006	bioaccumulation, cyclopods, TXRF, Egeria densa, heavy metal uptake;	Chemical Analysis
Mokobia, C.E.; Adebiyi, F.M.; Akpan, I; Ofise, F.S.; Tchokossa, P.	Radioassay of prominent Nigerian fossil fuels using gamma and TXRF spectroscopy	Fuel	85	1811-1814	2006	radioassay, Nigerian fossil fuels, gamma, TXRF	Chemical Analysis
Moreira, S; Ficaris, M; Vives, A.E.S.; Nascimento, V.F.; Zucchi, O.L.A.D.; Barroso, R.C.; de Jesus, E.F.O.	Heavy metals in groundwater using synchrotron radiation total reflection X-ray analysis	Instrum. Sci. Technol.	34 (5)	567-585	2006	heavy metals, environmental contamination, groundwater	Chemical Analysis
Owoade, O.K.; Olise, F.S.; Olaniyi, H.B.; Wegrzynek, D.	Model estimated uncertainties in the calibration of a total reflection x-ray fluorescence spectrometer using single-element standards	X-Ray Spectrom.	35 (4)	249-252	2006	uncertainty	Chemical Analysis
Osan, J.; Torok, S.; Beckhoff, B.; Ulm, G.; Hwang, H.; Ro, C.U.; Abete, C.; Fuoco, R.	Nitrogen and sulfur compounds in coastal Antarctic fine aerosol particles - an insight using non-destructive X-ray microanalytical methods	Atmos. Environ.	40 (25)	4691-4702	2006	Antarctica, aerosols, non-destructive X-ray methods, TXRF, NEXAFS, low-Z	Chemical Analysis
Aretaki, I.N.; Koulouridakis, P.; Kallithrakas-Kontos, N.	Total reflection X-ray fluorescence mercury analysis after immobilization on quartz surfaces	Anal. Chim. Acta	562	252-257	2006	TXRF, mercury, membrane, seawater, water analysis, Lead	Chemical Analysis
Hellin, D.; De Gendt, S.; Valckx. N.; Mertens, P.W.; Vinckier, C.	Trends in total reflection X-ray fluorescence spectrometry for metallic contamination control in semiconductor nanotechnology	Spectrochim. Acta Part B	61	496-514	2006	TXRF; Multi-element detection; Preconcentration technique; Wafer	Surfaces and Layers

Autoren	Titel	Zeitschrift	Vol	Seiten	Jahr	Keywords	Gruppe
Vives, A.E.S.; Moreira, S.; Brienza, S.M.B.; Zucchi, O.L.A.; Nascimento, V.F.	Synchrotron radiation total reflection X-ray fluorescence (SR-TXRF) for evaluation of food contamination	J. Radioanal. Nucl. Chem.	270	147-153	2006	Metals, food	Chemical Analysis
Streli, C.	Recent advances in TXRF	Appl. Spectrosc. Rev.	41	473-489	2006	EDXRF, X-ray fluorescence spectrometry, trace element analysis,	Review
Samek, L; Ostachowicz, B; Worobiec, A; Spolnik, Z; Van Grieken, R.	Speciation of selected metals in aerosol samples by TXRF after sequential leaching	X-Ray Spectrom.	35 (4)	226-231	2006	Trace metals; Urban; Extraction	Chemical Analysis
Shimazaki, A.; Miyazaki, K.; Matsumura, T.; Ito, S.	Analysis of low metallic contamination on silicon wafer surfaces by vapor-phase treatment and total reflection X-ray fluorescence analysis	Jpn. J. Appl. Phys. Part 1	45 (12)	9037-9043	2006	metallic contamination, metallic impurity, silicon wafer, vapor-	Surfaces and layers
Novikava, N.N.; Zheludeva, S.I.; Stepina, N.D.; Tolstikhina, A.L.; Gaynutdinov, R.V.; Haase, W.; Erko, A.I.; Knyazev, A.A.; Galyametdinov,	Arrangement of trace metal contaminations in thin films of liquid crystals studied by X-ray standing wave technique	Spectrochim. Acta Part B	61	1229-1235	2006	Total external reflection; Metal ions; Langmuir-Blodgett films;	Surfaces and Layers
Mages, M.; von Tümpling jun., W.; van der Veen, A.; Baborowski, M.	Element determination in natural biofilms of mine drainage water by total reflection X-ray fluorescence spectrometry	Spectrochim. Acta Part B	61	1146-1152	2006	Heavy metals; Element determinaiton; Element	Chemical Analysis
Adebiyi, F.M.; Asubiojo, O.I.; Ajayi, T.R.	Multielement analysis of Nigerian bitumen by TXRF spectrometry and the physical constants characterization of its hydrocarbon component	FUEL	85 (3)	396-400	2006	oil sand; bitumen; hydrocarbon; TXRF; physical constant	Chemical Analysis
Tsuji, K.; Hanaoka, Y.; Hibara, A.; Tokeshi, M.; Kitamori, T.	Total reflection X-ray fluorescence analysis with chemical microchip	Spectrochim. Acta Part B	61	389-392	2006	TXRF; Chemical microchip; Microchannel	Principles and Instrumentation
Esaka, F.; Esaka, K.T.; Magara, M.; Sakurai, S.; Usuda, S.; Watanabe, K.	Single particle transfer for quantitative analysis with total-reflection X-ray fluorescence spectrometry	Nucl. Instrum. Methods Phys. Res. Sect. B	251	218-222	2006	individual particles, quantitative analysis, SEM, manipulator; size; air	Principles and Instrumentation
Streli, C.; Pepponi, G.; Wobrauschek, P.; Jokubonis, C.; Falkenberg, G.; Zaray, G.; Broekaert, J.A.C.; Fittschen, U.; Peschel, B.	Recent results of synchrotron radiation induced total reflection X-ray fluorescence analysis at HASYLAB, beamline L	Spectrochim. Acta Part B	61	1129-1134	2006	Synchrotron radiation; XANES; Aerosol	Chemical Analysis

Autoren	Titel	Zeitschrift	Vol	Seiten	Jahr	Keywords	Gruppe
Pahlke, S.; Meirer, F.; Wobrauschek, P.; Streli, C.; Westphal, G.P.; Mantler, C.	Adaptation of a commercial total reflection X-ray fluorescence system for wafer surface analysis equipped with a new generation of silicon drift detector	Spectrochim. Acta Part B	61	1110-1114	2006	Silicon wafer surface analysis; SDD; Ultra trace element detection	Principles and Instrumentation
Hoefler, H.; Streli, C.; Wobrauschek, P.; Óvári, M.; Záray, G.	Analysis of low Z elements in various environmental samples with total reflection X-ray fluorescence (TXRF) spectrometry	Spectrochim. Acta Part B	61	1135-1140	2006	Low Z elements; Self absorption; Biofilms	Chemical Analysis
Gruber, X.; Kregsamer, P.; Wobrauschek, P.; Streli, C.	Total-reflection X-ray fluorescence analysis of Austrian wine	Spectrochim. Acta Part B	61	1214-1218	2006	Wine analyysis; Trace element analysis	Chemical Analysis
Griesel, S.; Mundry, R.; A. Kakuschke, A.; Fonfara, S.; Siebert, U.; Prange, A.	Mineral elements and essential trace elements in blood of seals of the North Sea measured by total-reflection X-ray fluorescence analysis	Spectrochim. Acta Part B	61	1158-1165	2006	Blood; Marine mammals; North Sea; Health; Biomonitoring tool	Chemical Analysis
Nishiwaki, Y.; Shimoyama, M.; Nakanishi, T.; Ninomiya, T.; Nakai, I.	Application of total reflection X-ray fluorescence spectrometry to small glass fragments	Anal. Sci.	22	1297-1300	2006	Plasma-mass-spectrometry; AES; ICP-MS; Samples; Sheet;	Chemical Analysis
Korotkikh, E.M.	Total reflection x-ray fluorescence spectrometer with parallel primary beam	X-Ray Spectrom.	35	116-119	2006		Principles and Instrumentation
Nakano, K.; Tanaka, K.; Ding, X.; Tsuji, K.	Development of a new total reflection Xhyphenray fluorescence instrument using polycapillary Xhyphenray lens	Spectrochim. Acta Part B	61	1105-1109	2006		Principles and Instrumentation
Mihucz, V.G.; Móricz, Á.M.; Kröpfl, K.; Szikora, S.; Tatár, E.; Lué Merú Marcó Parra and Záray, G.	Development of off-line layer chromatographic and total reflection X-ray fluorescence spectrometric methods for arsenic speciation	Spectrochim. Acta Part B	61	1124-1128	2006	Arsenic; Speciation; TLC; OPLC; Plant	Chemical Analysis
Hühnerfuß, K.; von Bohlen, A.; Kurth, D.	Characterization of pigments and colors used in ancient Egyptian boat models	Spectrochim. Acta Part B	61	1224-1228	2006	Egyptology; TXRF; Historical pigments; Burial boat models	Chemical Analysis
Fernandez-Ruiz, R.; Galisteo, F.C.; Larese, C.; Granados, M.L.; Mariscal, R.; Fierro, J.L.G.	TXRF analysis of aged three way catalysts	Analyst	131	590-594	2006	X-Ray-Fluorescence; Induced breakdown spectrometrya;	Chemical Analysis

Autoren	Titel	Zeitschrift	Vol	Seiten	Jahr	Keywords	Gruppe
Koleleni, Y.I.A.; Kondoro, J.W.A.	X-ray fluorescence spectrometry in Dar es Salaam	X-Ray Spectrom.	35 (1)	40-41	2006		Chemical Analysis
Nagata, N.; Peralta-Zamora, P.G.; Poppi, R.J.; Perez, C.A.; Bueno, M.I.M.S.	Multivariate calibrations for the SR-TXRF determination of trace concentrations of lead and arsenic in the presence of bromine	X-Ray Spectrom.	35 (1)	79-84	2006	Synchrotron radiation; Lead; Arsenic; Bromine	Principles and Instumentation
Adebiyi, F.M.; Asubiojo, O.I.; Ajayi, T.R.	Multielement analysis of Nigerian bitumen by TXRF spectrometry and the physical constants characterization of its hydrocarbon component	Fuel	85 (3)	396-400	2006	oil sand, bitumen, hydrocarbon, TXRF, physical constant	Chemical Analysis
Ostachowicz, B.; Lankosz, M.; Tomik, B.; Adamek, D.; Wobrauschek, P.; Streli, C.; Kregsamer, P.	Analysis of some chosen elements of cerebrospinal fluid and serum in amyotrophic lateral sclerosis patients by total reflection X-ray fluorescence	Spectrochim. Acta Part B	61	1210-1213	2006	Amyotrophic lateral sclerosis; Body fluids analysis	Chemical Analysis
Klockenkämper, R.	Challenges of total reflection X-ray fluorescence for surface- and thin-layer analysis	Spectrochim. Acta Part B	61	1082-1090	2006	TXRF; GI´-XRF; VPD; Implantation layers; Wafer contamination;	Review
Fittschen, U.E.A.; Hauschild, S.; Amberger, M.A.; Lammel, G.; Streli, C.; Förster, S.; Wobrauschek, P.; Jokubonis, C.; Pepponi, G.;	A new technique for the deposition of standard solutions in total reflection X-ray fluorescence spectrometry (TXRF) using pico-droplets generated by inkjet printers and its applicability	Spectrochim. Acta Part B	61	1098-1104	2006	Calibration; Pico-droplet; Inkjet printer; SR-TXRF; Aerosol analysis	Principles and Instrumentation
Magalhaes, T.; von Bohlen, A.; Carvalho, M.L.; Becker, M.	Trace elements in human cancerous and healthy tissues from the same individual: A comparative study by TXRF and EDXRF	Spectrochim. Acta Part B	61	1185-1193	2006	Carcinoma; Uterus carcinoma; Breast carcinoma; Colon carcinoma;	Chemical Analysis
Greaves, E.D.; Angeli-Greaves, M.; Jaehde, U.; Drescher, A.; von Bohlen, A.	Rapid determination of platinum plasma concentrations of chemotherapy patients using total reflection X-ray fluorescence	Spectrochim. Acta Part B	61	1194-1200	2006	Cancer; Chemotherapy; Platinum; Analysis	Chemical Analysis
Meirer, F.; Pepponi, G.; Streli, C.; Wobrauschek, P.; Mihucz, V.G.; Zaray, G.; Czech, V.; Broekaert, J.A.C.; Fittschen, U.E.A.; Falkenberg,	Application of synchrotron-radiation-induced TXRF-XANES for arsenic speciation in cucumber (Cucumis sativus L.) xylem sap	X-Ray Spectrom.	36	408-412	2007		Related Methods
Borges, C.V.D.; Veiga, A.P.B.; Barroso, G.D.S.; de Jesus, E.F.; Serpa, R.F.B.; Moreira, S.; Salles-Costa, R.	Association among serum concentration of minerals, anthropometric indices and diarrhea in low-income children in the metropolitan region of Rio de Janeiro, Brazil	Revista de Nutricao - Brazilian Journal of Nutrition	20	159-169	2007		Chemical Analysis

Autoren	Titel	Zeitschrift	Vol	Seiten	Jahr	Keywords	Gruppe
Enrich, C.; Boeykens, S.; Caracciolo, N.; Custo, G.; Vázquez, C.	Honey characterization by total reflection x-ray fluorescence: evaluation of environmental quality and risk for the human health X-Ray Spectrometry	X-Ray Spectrom.	36	215-220	2007		Chemical Analysis
Khuder, A.; Bakir, M.A.; Karjou, J.; Sawan, M.Kh.	XRF and TXRF techniques for multi-element determination of trace elements in whole blood and human hair samples	Journal of Radioanalytical and Nuclear Chemistry	273	435-442	2007		Chemical Analysis
Avila-Pérez, P.; Zarazúa, G.; Tejeda, S.; Barceló-Quintal, I.; Díaz-Delgado, C.; Carreño-León, C.	Evaluation of distribution and bioavailability of Cr, Mn, Fe, Cu, Zn and Pb in the waters of the upper course of the Lerma River	X-Ray Spectrom.	36	361-368	2007		Chemical Analysis
Antipina, M.N.; Dobner, B.; Konovalov, O.V.; Shapovalov, V.L.; Brezesinski, G.	Investigation of the protonation state of novel cationic lipids designed for gene transfection	J. Phys. Chem. B	111	13845-13850	2007		Chemical Analysis
Wobrauschek, P.	Total reflection x-ray fluorescence analysis - a review	X-Ray Spectrom.	36	289-300	2007		Review
Varga, I.	Iodine determination in dietary supplement products by TXRF and ICP-AES spectrometry	Microchem J.	85	127-131	2007	iodine, seaweed, kelp, dietary supplement, TXRF spectrometry	Chenical Analysis
Goltz, D.M.; Charleton, K.; Cloutis, E.; Grinberg, P.; Collins, C.	Identification of darkened pigments in cultural objects by graphite furnace atomic absorption spectroscopy and inductively coupled plasma-mass spectrometry	J. Anal. At. Spectrom.	22 (2)	140-146	2007	induced breakdown spectroscopy; Raman microscopy; painted artworks;	Related Methods
Kunimura, S.; Kawai, J.	Portable Total Reflection X-ray Fluorescence Spectrometer for Nanogram Cr Detection Limit	Anal. Chem.	79	2593–2595	2007		Principles and Instrumentation
Hatzistavros, V.S.; Koulouridakis, P.E.; Aretaki, I.I.; Kallithrakas-Kontos, N.G.	Bromate determination in water after membrane complexation and total reflection X-ray fluorescence analysis	Anal. Chem.	79 (7)	2827-2832	2007	Drinking-water; ion chormatography; haloacetic acids; by-products, Cr(VI)	Chemical Analysis
Karjou, J.	Matrix effect on the detection limit and accuracy in total reflection X-ray fluorescence analysis of trace elements in environmental and biological samples	Spectrochim. Acta Part B	62	177-181	2007	TXRF, detection limit, reference material, direct analysis; metallic	Chemical Analysis

Autoren	Titel	Zeitschrift	Vol	Seiten	Jahr	Keywords	Gruppe
Osan, J.; Torok, S.; Alfoldy, B.; Alsecz, A.; Falkenberg, G.; Baik, S.Y.; Van Grieken, R.	Comparison of sediment pollution in the rivers of the Hungarian Upper Tisza Region using non-destructive analytical techniques	Spectrochim. Acta Part B	62	123-136	2007	water, transboundary pollution, XRF, EPMA, XANES,	Chemical Analysis
Montero Alvarez, A.; Estévez Alvarez, J.R.; Padilla Alvarez, R.	Heavy metal analysis of rainwaters: A comparison of TXRF and ASV analytical capabilities	Journal of Radioanalytical and Nuclear Chemistry	273	427-433	2007		Chemical Analysis
Hoffmann, P.; Baake, O.; Beckhoff, B.; Ensinger, W.; Fainer, N.; Klein, A.; Kosinova, M.; Pollakowski, B.; Trunova, V.; Ulm, G.; Weser, J.	Chemical bonding in carbonitride nanolayers	Nucl. Instrum. Methods Phys. Res. Sect. A	575	78-84	2007	chemical bonding, boron carbonitrides, silicon carbonitrides, X-ray fluorescence	Chemical Analysis
Dhara, S.; Misra, N.L.; Mudher, K.D.S.; Aggarwal, S.K.	Bulk determination of uranium and thorium in presence of each other by Total Reflection X-ray Fluorescence spectrometry	Spectrochim. Acta Part B	62	82-85	2007	Total Reflection X-ray Fluorescence, bulk determination, nuclear fuel, nuclear	Chemical Analysis
Beckhoff, B.; Fliegauf, R.; Kolbe, M.; Müller, M.; Weser, J.; Ulm, G.	Reference-free total reflection X-ray fluorescence analysis of semiconductor surfaces with synchrotron radiation	Anal. Chem.	79 (20)	7873-7882	2007	low-Z-elements; SiI wafer surfaces; photoelectric absorption-	Principles and Instrumentation
Granados, M.L.; Galisteo, F.C.; Lambrou, P. S.; Alifanti, M.; Mariscal, R.; Gurbani, A.; Sanz, J.; Sobrados, I.; Efstathiou, A.M.; Fierro, J.L.G.	Nucleation of isolated PO4 units on CeO2 driven by high temperatures and the effect on its oxygen storage and release properties	Top. Catal.	42-43	443-447	2007	CeO2; TWC deactivation; monazite; TXRF; XPS; P-31 NMR; X-	Chemical Analysis
Carvalho, M.L.; Magalhães, T.; Becker, M.; von Bohlen, A.	Trace elements in human cancerous and healthy tissues: A comparative study by EDXRF, TXRF, synchrotron radiation and PIXE	Spectrochim. Acta Part B	62	1004–1011	2007	Human cancerous tissues; Total-reflection X-ray fluorescence;	Chemical Analysis
Alsecz,A.; Osán, J.; Kurunczi, S.; Alföldy, B.; Várhegyi, A.; Török, S.	Analytical performance of differnt X-ray spectroscopic techniques for the environmental monitoring of the recultivated uranium mine site	Spectrochim. Acta Part B	62	769-776	2007	Mine tailing; Micro-XRF; EPMA; TXRF	Chemical Analysis
P. Piccirilli, P.; Caracciolo, N.; Enrich, C.; Boeykens, S.; Vázquez, C.; Rosen, M.	Water-polysaccharide macromolecules: competitive interaction on glass microspheres	X-Ray Spectrom.	36	211-214	2007	polymer adsorption; glass surface;	Chemical Analysis
Stehen, C.; Nutsch, A.; Pichler, P.; Ryssel, H.	Characterization of the impurity profile at the SiO2/Si interface using a combinatiton of total reflection X-ray fluorescence spectrometry and successive etching of silicon	Spectrochim. Acta Part B	62	481-484	2007	Segregation; Concentration profile; Interface; Silicon; Arsenic	Chemical Analysis

Autoren	Titel	Zeitschrift	Vol	Seiten	Jahr	Keywords	Gruppe
Fernández-Ruiz, R.; García-Heras, M.	Study of archaeological ceramics by total-reflectionX-ray fluorescence spectrometry: Semi-quantitative aproach	Spectrochim. Acta Part B	62	1123-1129	2007	INAA; archaeological ceramics; size fraction;	Chemical analysis
Kubala-Kukus, A.; Banas, D.; Braziewicz, J.; Gózdz, S.; Majewska, U.; Pajek, M.	Analysis of elemental concentration censored distributions in breast malignant and breast benign neoplasm tissues	Spectrochim. Acta Part B	62	695-701	2007	X-ray fluorescence (XRF, TXRF) methods; Trace elements; Random	Chemical Analysis
Pimentel, P.M.; Anjos, M.J.; Melo, D.M.A.; Melo, M.A.E.; Goncalves, L.M.; Silva, C.N.; Lopes, R.T.	Multi-elemental analysis of produced water by synchrotron radiation total reflection X-ray fluorescence	Talanta	74	1231-1235	2008		Chemical Analysis
Martinez, T.; Lartigue, J.; Zarazua, G.; Avila-Perez, P.; Navarrete, M.; Tejeda, S.	Application of the Total Reflection X-ray Fluorescence technique to trace elements determination in tobacco	Spectrochim. Acta Part B	63	1469-1472	2008	Tobacco; trace elements	Chemical analysis
Granados, M.L.; Gurbani, A.; Mariscal, R.; Fierro, J.L.G.	Deterioration of the oxygen storage and release properties of CeZrO4 by incorporation of calcium	J. Catalysis	256	172-182	2008		Chemical Analysis
Golmar, F.; Navarro, A.M.M.; Torres, C.E.R.; Sanchez, F.H.; Saccone, F.D.; Claro, P.C.D.; Benitez, G.A.; Schilardi, P.L.	Extrinsic origin of ferromagnetism in single crystalline LaAlO3 substrates and oxide films	Appl. Phys. Lett.	92	262503	2008		Chemical Analysis
Martinez-Huerta, M.V.; Rodriguez, J.L.; Tsiouvaras, N.; Pena, M.A.; Fierro, J.L.G.; Pastor, E.	Novel synthesis method of CO-Tolerant PtRu-MoOx nanoparticles: Structural characteristics and performance for methanol electrooxidation	Chemistry of Materials	20	4249-4259	2008		Chemical Analysis
Terra, B.F.; Araujo, F.G.; Calza, C.F.; Lopes, R.T.; Teixeira, T.P.	Heavy metal in tissues of three fish species from different trophic levels in a Tropical Brazilian River	Water Air and Soil Pollution	187	275-284	2008		Chemical Analysis
Menezes, H.; Murakami, H.; Kinashi, T.; Sparks, C.	Trace Metal Analysis on Hafnium Silicate Deposited Si Wafer by Total Reflection X-ray Fluorescence	Spectrochim. Acta Part B	63	1355-1358	2008	Trace metal analysis; Ir tube anode; high-k; hafnium silicate	Surfaces and Layers
Urdaneta, C.; Marcó Parra, L.M.; Matute, S.; Garaboto, M.A.; Barros, H.; Vázquez, C.	Evaluation of vermicompost as bioadsorbent substrate of Pb, Ni, V and Cr for waste waters remediation using Total Reflection X-Ray Fluorescence	Spectrochim. Acta Part B	63	1455-1460	2008	Vermicompost; vanadium; lead; nickel; chormium; bioadsorption	Chemical Analysis

Autoren	Titel	Zeitschrift	Vol	Seiten	Jahr	Keywords	Gruppe
Askun, H.; Gulbakan, B.; Celikbicak, O.; Uzun, C.; Guven, G.; Salih, B.	Preconcentration and matrix elimination for the determination of Pb(II), Cd(II), Ni(II), and Co(II) by 8-hydroxyquinoline	J. Appl. Polymer Sci.	107	2714-2722	2008		Chemical Analysis
Groma, V.; Osan, J.; Torok, S.; Meirer, F.; Streli, C.; Wobrauscbek, P.; Falkenberg, G.	Trace element analysis of airport related aerosols using SR-TXRF	IDOJARAS	112	83-97	2008	aerosols; trace elements; SR	Chemical Analysis
Kunimura, S.; Watanabe, D.; Kawai, J	Analysis of trace elements in soft drink, environmental water, and leaching solution of toy by using portable total reflection x-ray fluorescence spectrometer	Bunseki Kagaku	57	135-139	2008	trace elements; portable spectrometer;	Chemical Analysis
Wagner, A.; Boman, J.; Gatari, M.J.	Elemental analysis of size-fractionated particulate matter sampled in Göteborg, Sweden	Spectrochim. Acta Part B	63	1426-1431	2008	Aerosol particle; Göteborg; PIXE cascade impactor; trace element	Chemical Analysis
Tiwari, M.K.; Bhalerao, G.M.; Bhalerao, G.M.; Babu, M.; Sinha, A.K.; Mukherjee, C.	Investigation of metal nanoparticles on a Si surface using an x-ray standing wave field	J. Appl. Phys.	103	054311	2008	nanoparticles; XSW;	Related Methods
Adebiyi, F.M.; Asubiojo, O.I.; Ajayi, T.R.	Characterization of nigerian oil sands by TXRF spectrometry	Petroleum Science and Technology	26	29-39	2008		Chemical Analysis
Dhara, S.; Misra, N.L.; Aggarwal, S.K:	Determination of sulphur in uranium matrix by total reflection X-ray fluorescence spectrometry	Spectrochim. Acta Part B	63	1395-1398	2008	Trace element; sulphur; uranium; solvent extraction	Chemical Analysis
Stas, J.; Khuder, A.; Karjou, J.	Direct determination of uranium and co-extracted elements in the organic phases (D(2)EHPA/TOPO, TBP, TDA) in kerosene by TXRF technique	Applied Radiation and Isotopes	66	450-456	2008	uranium; kerosene;	Chemical Analysis
Budri, T.	Utilization of TXRF analytical technique in order to improve front-end semiconductor processing	Appl. Surf. Sci.	254	4768-4773	2008		Chemical Analysis
Vazquez, C.; Maier, M.S.; Parera, S.D.; Yacobaccio, H.; Sola, P.	Combining TXRF, FT-IR and GC-MS information for identification of inorganic and organic components in black pigments of rock art from Alero Hornillos 2 (Jujuy,	Anal. Bioanal. Chem.	391	1381-1387	2008	black pigments;	Chemical Analysis

Autoren	Titel	Zeitschrift	Vol	Seiten	Jahr	Keywords	Gruppe
Streli, C.; Wobrauschek, P.; Meirer, F.; Pepponi, G.	Synchrotron radiation induced TXRF	J. Anal. At. Spectrom.	23	792-798	2008	Synchrotron;	Review
Khuder, A.; Bakir, M.A.; Hasan, R.; Mohammad, A.	Determination of nickel, copper, zinc and lead in human scalp hair in Syrian occupationally exposed workers by total reflection X-ray fluorescence	Environmental Monitoring and Assessment	143	67-74	2008	hair; occupational exposure;	Chemical Analysis
Smichowski, P.; Gomez, D.; Frazzoli, C.; Caroji, S.	Traffic-related elements in airborne particulate matter	Appl. Spectrosc. Rev.	43	22-48	2008		Review
Fittschen, U.E.A.; Meirer, F.; Streli, C.; Wobrauschek, P.; Thiele, J.; Falkenberg, G.; Pepponi, G.	Characterization of atmospheric aerosols using SR-TXRF and Fe K-edge TXRF-XANES	Spectrochim. Acta Part B	63	1489-1498	2008	SR-TXRF; TXRF-XANES; aerosol analysis; iron	Chemical Analysis
Vázquez, C.; Albornoz, A.; Hajduk, A.; Elkin, D.; Custo, G.; Obrustky, A.	Total reflection X ray fluorescence and archaeometry: Application in the Argentinean cultural heritage	Spectrochim. Acta Part B	63	1415-1419	2008	Archaeometry; micro-analytical technique; X-ray fluroescence	Chemical Analysis
Zheludeva, S.; Novikova, N.; Stepina, N.; Yurieva, E.; Konovalov, O.	Molecular organization in protein-lipid film on the water surface studied by x-ray standing wave measurements under total external reflection	Spectrochim. Acta Part B	63	1399-1403	2008	X-ray fluorescence; total external reflection; resonance	Surfaces and Layers
Wobrauschek, P.; Streli, C.; Kregsamer, P.; Meirer, F.; Jokubonis, C.; Markowicz, A.; Wegrzynek, D.; Chinea-Cano, E.	Total Reflection X-Ray Fluorescence attachment module modified for analysis in vacuum	Spectrochim. Acta Part B	63	1404-1407	2008	Vacuum; trace-element analysis	Principles and Instrumentation
Danel, A.; Nolot, E.; Veillerot, M.; Olivier, S.; Decorps, T.; Calvo-Muñoz, M.-L.; Hartmann, J.-M.; Lhostis, S.; Kohno, H.; Yamagami, M.; Geoffroy, C.	Thin film characterization by total reflection X-ray fluorescence	Spectrochim. Acta Part B	63	1365-1369	2008	Silicon wafer; thin film; composition analysis	Surfaces and Layers
Danel, A.; Cabuil, N.; Lardin, T.; Despois, D.; Veillerot, M.; Geoffroy, C.; Yamagami, M.; Kohno, H.	Comparison of Direct-TXRF, Sweeping-TXRF and Vapor Phase Decomposition-TXRF applied to the characterization of metallic contamination on semiconductor wafers	Spectrochim. Acta Part B	63	1375-1381	2008	Silicon wafer; metallic contamintion	Surfaces and Layers
Borde, Y.; Danel, A.; Roche, A.; Veillerot, M.	Sweeping Total Reflexion X-Ray Fluorescence optimisation to monitor the metallic contamination into IC manufacturing	Spectrochim. Acta Part B	63	1370-1374	2008	Silicon wafer; metalic contamination	Surfaces and Layers

Autoren	Titel	Zeitschrift	Vol	Seiten	Jahr	Keywords	Gruppe
Moreira, S.; Fazza, E.V.	Evaluation of water and sediment of the Graminha and Águas da Serra Streams in the city of Limeira (Sp-Brazil) by Synchrotron Radiation total reflection X-ray fluorescence	Spectrochim. Acta Part B	63	1432-1442	2008	Heavy metals; water quality; sediment; galvanization industry; synchrotron	Chemical Analysis
Misra, N.L.; Dhara, S.; Adya, V.C. Godbole, S.V.; Singh Mudher, K.D.; Aggarwal, S.K.	Trace element determination in thorium oxide using total reflection X-ray fluorescence spectrometry	Spectrochim. Acta Part B	63	81-85	2008	Trace elements; Nuclear fuel; Thorium oxide	Chemical Analysis
Woelfl, S.; Mages, M.; Torres, P.	Trace metal concentrations in single specimens of the intestinal broad flatworm (Diphyllobothrium latum), compared to their fish host (Oncorhynchus mykiss) measured by total	Spectrochim. Acta Part B	63	1450-1454	2008	Trace element analysis; fish parasite; bioaccumulation:	Chemical analysis
Fernández-Ruiza, R.; Garcia-Heras, M.	Analysis of archaeological ceramics by total-reflection X-ray fluorescence: Quantitative approaches	Spectrochim. Acta Part B	63	975-979	2008	TXRF; INAA; Archaeological ceramics; Archaeometry;	Chemical Analysis
Hönicke, P.; Beckhoff, B.; Kolbe, M.; List, S.; Conard, T.; Struyff, H.	Depth-profiling of vertical sidewall nanolayers on structured wafers by grazing incidence X-ray fluorescence	Spectrochim. Acta Part B	63	1359-1364	2008	GIXRF; synchrotron radiation; sidewall characterization: patterned wafer	Surfaces and Layers
Fernández-Ruiz, R.; Costo, R.; Morales, M.P.; Bomatí-Miguel, O.; Veintemillas-Verdaguer, S.	Total-reflection X-ray fluorescence: An alternative tool for the analysis of magnetic ferrofluids	Spectrochim. Acta Part B	63	1387-1394	2008	Medical image; iron ferrofluids contrast agent; AD-TXRF; nanoparticles	Chemical Analysis
Sánchez, H.J.; Valentinuzzi, M.C.; Grenón, M.; Abraham, J.	Total Reflection X-ray Fluorescence Analysis of Oral Fluids of Women Affected by Osteoporosis and Osteopenia	Spectrochim. Acta Part B	63	1485-1488	2008	Osteoporosis; beam-guides	Chemical Analysis
Krämer, M.; Kuzushita, K.; Maeo, S.; Utaka, T.; Taniguchi, K.	Design of a doubly-curved crystal to improve X-ray fluorescence analysis of aerosol particles	Spectrochim. Acta Part B	63	1408-1414	2008	Doubly-curved crystal; X-ray fluorescence analysis; aerosol	Related Methods
Mages, M.; Bandow, N.; Küster, E.; Brack, W.; von Tümpling, W.	Zinc and Cadmium accumulation in single zebrafish (Danio rerio) embryos – A total reflection X-ray fluorescence spectrometry application	Spectrochim. Acta Part B	63	1443-1449	2008	Element accumulation; ion exchange resin; fish embryos; TXRF	Chemical Analysis
Wellenreuther, G.; Fittschen, U.E.A.; Achard, M.E.S.; Faust, A.; Kreplin, X.; Meyer-Klaucke, W.	Optimizing total reflection X-ray fluorescence for direct trace element quantification in proteins I: Influence of sample homogeneity and reflector type	Spectrochim. Acta Part B	63	1461-1468	2008	Metalloprotein; metal quantification; µXRF; trace elements	Chemical Analysis

Autoren	Titel	Zeitschrift	Vol	Seiten	Jahr	Keywords	Gruppe
Sekowski, M.; Steen, C.; Nutsch, A.; Birnbaum, E.; Burenkov, A.; Pichler, P.	Total reflection X-ray fluorescence as a sensitive analysis method for the investigation of sputtering processes	Spectrochim. Acta Part B	63	1382-1386	2008	Sputtering; germanium; grazing ion incidence	Surfaces and Layers
Cibin, G.; Marcelli, A.; Maggi, V.; Sala, M.; Marino, F.; Delmonte, B.; Albani, S.; Pignotti, S.	First combined Total X-ray Reflection Fluorescence and Grazing Incidence X-ray Absorption Spectroscopy characterization of aeolian dust archived in Antarctica and Alpine	Spectrochim. Acta Part B	63	1503-1510	2008	XAS; GI-XAS; aerosol; ice core	Chemical Analysis
Martinez, T.; Zarazua, G.; Avila-Perez, P.; Juarez, F.; Cabrera, L.; Martinez, G.	Characterization by Total Reflection X-ray Fluorescence Spectrometry of filtrated water into the cave under the Sun Pyramid in Teotihuacan City	Spectrochim. Acta Part B	63	1420-1425	2008	Water; dissolved metal	Chemical Analysis
Szoboszlai, N.; Réti, A.; Budai, B.; Szabó, Z.; Kralovánszky, J.; Záray, G.	Direct elemental analysis of cancer cell lines by total reflection X-ray fluorescence	Spectrochim. Acta Part B	63	1480-1484	2008	Direct analysis; vapour-phase digestion; copper; iron; zinc	Chemical Analysis
Fittschen, U.E.A.; Bings, N.H.; Hauschild, S.; Förster, S.; Kiera, A.F.; Karavani, E.; Frömsdorf, A.; Thiele, J.	Characteristics of Picoliter Droplet Dried Residues as Standards for Direct Analysis Techniques	Anal. Chem.	80	1967-1977	2008	Picodroplets; SR-MXRF; LA-ICP-MS	Chemical Analysis
Magalhães, T.; Becker, M.; Carvalho, M.L.; von Bohlen, A.	Study of Br, Zn, Cu and Fe concentrations in healthy and cancer breast tissues by TXRF	Spectrochim. Acta Part B	63	1473-1479	2008	Breast cancer; trace elements; bromine; trihalomethanes	Chemical Analysis
Kunimura, S.; Kawaia, J.	Handy waveguide TXRF spectrometer for nanogram sensitivity	Powder Diffraction	23	146-149	2008	waveguide; portable TXRF;	Chemical Analysis
Ravanel, X.; Trouiller, C.; Juhel, M.; Wyon, C.; Kwakman, L.F.Tz.; Leonard, D.	Quantitative static Time-of-Flight Secondary Ion Mass Spectrometry analysis of anionic minority species in microelectronic substrates	Appl. Surf. Sci.	255	1415-1418	2008		Chemical Analysis
Sparks, C.M.; Lanee, S.; Beebe, M.; Page, M.	Photovoltaic substrates and hafnium based gate dielectrics characterized with total reflection X-ray fluorescence	Spectrochim. Acta Part B	63	1351-1354	2008	Photovoltaic; hafnium silicate dielectric	Surfaces and Layers
Fernández-Ruiz, R.	Uncertainty in the Multielemental Quantification by Total-Reflection X-ray Fluorescence: Theoretical and Empirical Approximation	Anal. Chem.	80	8372–8381	2008	uncertainty; modelling	Chemical Analysis

Autoren	Titel	Zeitschrift	Vol	Seiten	Jahr	Keywords	Gruppe
Meirer, F.; Pepponi, G.; Streli, C.; Wobrauschek, P.; Kregsamer, P.; Zoeger, N.; Falkenberg, G.	Parameter study of self-absorption effects in Total Reflection X-ray Fluorescence-X-ray Absorption Near Edge Structure analysis of arsenic	Spectrochim. Acta Part B	63	1496-1502	2008	Xanes; self-absorption; arsenic	Chemical Analysis
Egorov, V.K.; Egorov, E.V.; Afanas'ev, M.S.	Comparative Analysis of TXRF-Spectroscopy Efficiency under the Testing Target Excitation by Fluxes Formed by the Slit-Cut System and Waveguide-Resonator	J. Surf. Investigaton- X-Ray Synchrotron and Neutron Techniques	2	904-912	2008		Principles and Instrumentation
Necemer, M.; Kump, P.; Scancar, J.; Jadmovic, R.; Simcic, J.; Pelicon, P.; Budnar, M.; Jeran, Z.; Pongrac, P.; Regvar, M.; Vogel-Mikus, K.	Application of X-ray fluorescence analytical techniques in phytoremediation and plant biology studies	Spectrochim. Acta Part B	63	1240-1247	2008		Chemical Analysis
Tiwari, M.K.; Lodha, G.S.; Sawhney, K.J.S.; Gowrisankar, B.; Singh, A.K.; Bhalerao, G.M.; Sinha, A.K.; Das, A.;	Progress in total reflection X-ray fluorescence spectrometry at Raja Ramanna Centre for Advanced Technology	Current Science	95	603-609	2008		Review
Meirer, F.; Streli, C.; Pepponi, G.; Wobrauschek, P.; Zaitz, M.A.; Horntrich, C.; Falkenberg, G.	Feasibility study of SR-TXRF-XANES analysis for iron contaminations on a silicon wafer surface	Surf. Interf. Anal.	40	1571-1576	2008		Related Methods
Civici, N.; Anastasiou, M.; Zorba, T.; Paraskevopoulos, K. M.; Dilo, T.; Stamati, F.; Arapi, M.	Studying wall paintings in Berati Castle (Albania): Comparative examination of materials and techniques in XIVth and XVIth century churches	J. Cultural Heritage	9	207-213	2008		Chemical Analysis
Villoria, J.A.; Alvarez-Galvan, M.C.; Navarro, R.M.; Briceno, Y.; Alvarez, F.G.; Rosa, F.; Fierro, J.L.G.	Zirconia-supported LaCoO3 Catalysts for hydrogen production by oxidative reforming of diesel: Optimization of preparation conditions	Catalysis Today	138	135-140	2008		Chemical Analysis
Fister, T.T.; Fong, D.D.; Eastman, J.A.; Baldo, P.M.; Highland, M.J.; Fuoss, P.H.; Balasubramaniam, K.R.; Meador, J.C.; Salvador, P.A.	In situ characterization of strontium surface segregation in epitaxial La0.7Sr0.3MnO3 thin films as a function of oxygen partial pressure	Appl. Phys. Lett.	93	151904	2008		Surfaces and Layers
West, M.; Ellis, A.T.; Kregsamer, P.; Potts, P.J.; Streli, C.; Vanhoof, C.; Wobrauschek, P.	Atomic spectrometry update. X-ray fluorescence spectrometry	J. Anal. At. Spectrom.	23	1409-1437	2008		Review
Staniszewski, B.; Freimann, P.	A solid phase extraction procedure for the simultaneous determination of total inorganic arsenic and trace metals in seawater: Sample preparation for total-reflection	Spectrochim. Acta Part B	63	1333-1337	2008	arsenic; trace elements; seawater;	Chemical Analysis

Autoren	Titel	Zeitschrift	Vol	Seiten	Jahr	Keywords	Gruppe
Fresno, F.; Tudela, D.; Coronado, J.M.; Soria, J.	Synthesis of Ti1-xSnxO2 nanosized photocatalysts in reverse microemulsions	Catalysis Today	143	230-236	2009	Photocatalysis; Titania; Sn; Doped; Microemulsion; Trichloroethylene	
Espinoza-Quinones, F.R.; Módenes, A.N.; Thomé, L.P.; Palácio, S.M.; Trigueros, D.E.G.; Oliveira, A.P.; Szymanski, N.	Study of the bioaccumulation kinetic of lead by living aquatic macrophyte Salvinia auriculata	Chemical Engineering Journal	150	316–322	2009	alvinia auriculata; Lead; Phytoaccumulation; SR-TXRF technique;	Chemical Analysis
Pessanha, S.; Carvalho, M.L.; Manso, M.; Guilherme, A.; Marques, A.F.; Perez, C.A.	Hg diffusion in books of XVIII and XIX centuries by synchrotron microprobe	Spectrochim. Acta Part B	64	805-807	2009	Paper; X-ray-fluorescence; EDXRF spectrometry;	Chemical Analysis
Bennun, L.; Greaves, E.D.; Barros, H.; Diaz-Valdes, J.	A method for thickness determination of thin films of amalgamable metals by total-reflection X-ray fluorescence	Nucl. Instrum. Methods Phys. Res. Sect. B	267	2532-2537	2009	Thin film; Determination; TXRF; Mercury; Gold	Chemical Analysis
von Bohlen, A.	Total reflection X-ray fluorescence and grazing incidence X-ray spectrometry — Tools for micro- and surface analysis. A review	Spectrochim. Acta Part B	64	821-832	2009	Total reflection X-ray spectrometry; TXRF; X-ray standing waves; XSW;	Review
Amberger, M. A.; Broekaert, J.A.C.	Direct multielement determination of trace elements in boron carbide powders by total reflection X-ray fluorescence spectrometry and analysis of the powders by ICP atomic emission	J. Anal. At. Spectrom.	24	1517-1523	2009	Fresh-water algae; Absorption-spectrometry; SIilicon-carbide;	Chemical Analysis
Baake,O.; Fainer, N.I.; Hoffmann, P.; Kosinova, M.L.; Rumyantsev, Yu.M.;Trunova, V.A.; Klein, A.; Ensinger, W.; Pollakowski, B.;	Chemical characterization of SiCxNy nanolayers by FTIR-and Raman spectroscopy, XPS and TXRF-NEXAFS	Nucl. Instrum. Meth. A	603	174–177	2009	Silicon carbonitride; Chemical bonding; Thin film; TXRF-NEXAFS	Related Methods
Necemer, M.; Kosir, I.J.; Kump, P.; Kropf, U.; Jamnik, M.; Bertoncelj, J.; Ogrinc, N.; Golob, T.	Application of Total Reflection X-ray Spectrometry in Combination with Chemometric Methods for Determination of the Botanical Origin of Slovenian Honey	J. Agric. Food Chem.	57	4409–4414	2009	Slovenian honey; botanical origin; TXRF; PCA; RDA; chemometry	Chemical Analysis
Sabatini, S.E.; Juárez, A.B.; Eppis, M.R.; Bianchi, L.; Luquet, C.M.; Ríos de Molina, M.C.	Oxidative stress and antioxidant defenses in two green microalgae exposed to copper	Ecotoxicology and Environmental Safety	72	1200-1206	2009	Scenedesmus vacuolatus; Chlorella kessleri; Copper content; Oxidative	Chemical Analysis
Stosnach, H.; Mages, M.	Analysis of nutrition-relevant trace elements in human blood and serum by means of total reflection X-ray fluorescence (TXRF) spectroscopy	Spectrochim. Acta Part B	64	354-356	2009	TXRF; Blood; Serum; Nutrition; Trace elements	Chemical Analysis

Autoren	Titel	Zeitschrift	Vol	Seiten	Jahr	Keywords	Gruppe
Kunimura, S.; Watanabe, D.; Kawai, J.	Optimization of a glancing angle for simultaneous trace elemental analysis by using a portable total reflection X-ray fluorescence spectromete	Spectrochim. Acta Part B	64	288 - 290	2009	Portable spectrometer; Total reflection X-ray fluorescence;	Principles and Instrumentation
Aretaki, I.-N.I.; Kallithrakas-Kontos, N.G.	Total reflection X-ray fluorescence selenium analysis after reduction and quartz reflector adsorption	J. Anal. At. Spectrom.	24	979–982	2009	Selenium; colloid; quartz reflector	Chemical Analysis
von Bohlen, A.; Krämer. M.; Sternemann, C.; Paulus, M.	The influence of X-ray coherence length on TXRF and XSW and the characterization of nanoparticles observed under grazing incidence of X-rays	J. Anal. At. Spectrom.	24	792–800	2009	nanoparticle; coherence length; grazing incidence; X-ray standing waves	Principles and Instrumentation
Khuder, A.; Sawan, M.Kh.; Karjou, J.; Razouk, A.K.	Determination of trace elements in Syrian medicinal plants and their infusions by energy dispersive X-ray fluorescence and total reflection X-ray fluorescence	Spectrochim. Acta Part B	64	721-725	2009	medical plants; infusions	Chemical Analysis
Ovari, M.; Streli, C.; Wobrauschek, P., Zaray, G.	Determination of carbon in natural freshwater biofilms with total reflection X-ray fluorescence spectrometry	Spectrochim. Acta Part B	64	802-804	2009	Low Z determination; Biofilm; Carbon; Trace- element	Chemical Analysis
Espinoza-Quinones, F.R.; Modenes, A.N.; Costa, I.L.; Palacio, S.M.; Szymanski, N.; Trigueros, D.E.G.; Kroumov, A.D.; Silva, E.A.	Kinetics of Lead Bioaccumulation from a Hydroponic Medium by Aquatic Macrophytes Pistia stratiotes	Water air and soil pollution	203	29-37	2009	Pistia stratiotes; Lead; Phytoaccumulation; Non-structural	Chemical Analysis
Lee, J.S.; Lim, H.B.	Thickness monitoring of sub-nanometer scale La2O3 films using total X-ray reflection fluorescence spectrometry	J. Anal. At. Spectrom.	24	1681–1683	2009	semiconductor; La2O3 films;	Surfaces and Layers
Fernandez-Ruiz, R.; Ocon, P.; Montiel, M.	First approximation to the analysis of Ru and Se in carbon nanoparticles as a new voltaic pile system by TXRF	J. Anal. At. Spectrom.	24	785–791	2009	nanoparticle; ruthenium, selenium; particle size distribution;	Chemical Analysis
Yang, J.; Zhao, D.D.; Xu, Q.; Ding, X.L.	Development and application of glancing incident X-ray fluorescence spectrometry using parallel polycapillary X-ray lens	Appl. Surf. Sci.	255	6439-6442	2009	TXRF; Parallel polycapillary X-ray lens; Film analysis	Related Methods
Wang, X.; Mihailova, B.; Klocke, A.; Fittschen, U.E.A.; Heidrich, S.; Hill, M.; Stosch, R.; Giittler, B.; Broekaert, J.A.C.; Bismayer, U.	Side effects of a non-peroxide-based home bleaching agent on dental enamel	J. Biomedical Materials Research Part A	88	195-204	2009	dental enamel; bleaching; ATR-IR and Raman spectroscopy; Ca	Chemical Analysis

Autoren	Titel	Zeitschrift	Vol	Seiten	Jahr	Keywords	Gruppe
Kunimura, S.; Kawai, J.	An X-ray refractive lens comprising two sections cut from a gramophone record for a portable total reflection X-ray fluorescence spectrometer	Spectrochim. Acta Part B	64	771-774	2009	Refractive lens; Gramophone record; Portable spectrometer; water	Principles and Instrumentation
Colombi, P.; Bontempi, E.; Depero, L.E.; Azuma, Y.; Fujimoto, T.	X-ray reflectivity and total reflection x-ray fluorescence study of surface oxide evolution in a GaAs/AlAs multilayer system	J. Appl. Phys.	105	014307	2009	GaAs; AlAs; multilayer; Baake	Surfaces and Layers
Fernández-Ruiz, R.	Three empirical cases of the deposition morphology influence in the analytical quality of direct solid suspension measurements by total-reflection X-ray fluorescence	Spectrochim. Acta Part B	64	672-678	2009	uncertainty; homogeneity; direct solid analysis; nanoparticles	Chemical Analysis
Balazsi, C.; Bishop, A.; Yang, J.H.C.; Balazsi, K.; Weber, F.; Gouma, P.I.	Biopolymer-Hydroxyapatite Scaffolds for Advanced Prosthetics	Composite Interfaces	16	191-200	2009	Eggshell; Hydroxyapaptite; Biocompatibility; Biomedical	Chemical Analysis
Yang, J.; Tsuji, K.; Lin, X.Y.; Han, D.Y.; Ding, X.L.	A micro X-ray fluorescence analysis method using polycapillary X-ray optics and grazing exit geometry	Thin Solid Films	517	3357-3361	2009	Grazing exit X-ray fluorescence (GE-XRF); Film analysis;	Related Methods
Macedo-Miranda, M.G.; Zarazua, G.; Mejia-Zarate, E.; Avila-Perez, P.; Barrientos-Becerra, B.; Tejeda, S.	Simultaneous determination of elemental content in water samples by total reflection X-ray fluorescence and atomic absorption spectrometry	J. Radioanal. Nucl. Chem.	280	427-430	2009	water; AAS;	Chemical Analysis
Nagatani, H.; Tanida, H.; Watanabe, I.; Sagara, T.	Extended X-ray Absorption Fine Structure of Copper(II) Complexes at the Air-Water Interface by a Polarized Total- Reflection X-ray Absorption Technique	Anal. Sci.	25	475-480	2009	Copper complexes; interface air-water; EXAFS; polarized X-rays	Related Methods
Bozek, S.; Bielecki, J.; Baszak, J.; Doruch, H.; Hajduk, R.; Lekki, J.; Stachura, Z.; Kwiatek, W.M.	X-ray microprobe – A new facility for cell irradiations in Kraków	Nucl. Instr. and Meth. B	267	2273–2276	2009	X-ray beams; X-ray microscopes; X-ray mirrors	Principles and Instrumentation
Szoboszlai, N.; Polgári, Z.; Mihucz, V.G.; Záray, G.	Recent trends in total reflection X-ray fluorescence spectrometry for biological applications	Anal. Chim. Acta	633	1-18	2009	Biological samples; Environmental; Human; Clinical; Elemental	Review
Baake, O.; Hoffmann, P.S.; Klein, A.; Pollakowski, B.; Beckhoff, B.; Ensinger, W.; Kosinova, M.; Fainer, N.; Sulyaeva, V.S.;Trunovaca, V.	Chemical characterization of SiCxNy nanolayers by FTIR-and Raman spectroscopy, XPS and TXRF-NEXAFS	X-Ray Spectrom.	38	68–73	2009	Silicon carbonitride; Chemical bonding; Thin film; TXRF-NEXAFS	Related Methods

Autoren	Titel	Zeitschrift	Vol	Seiten	Jahr	Keywords	Gruppe
Kallithrakas-Kontos, N.; Koulouridakis, P.; Hatzistavros, V.; Aretaki, I. N.	Chromium speciation by TXRF analysis	X-Ray Spectrom.	38	152–156	2009	chromium speciation; selective membrane collection; quartz	Chemical Analysis
Pinheiro, T.; Barreiros, A.; Alves, L.C.; Neres, M.; Fleming, R.; Silva, J.N.; Filipe, P.; Silva, R.	Changes of iron concentrations in skin and plasma of patients with hemochromatosis along therapy	J. Radioanal. Nucl. Chem.	281	161-164	2009	Iron; Human disorders; Nuclear microprobe	Chemical Analysis
Kakuschke, A.; Griesel, S.; Fonfara, S.; Rosenberger, T.; Prange, A.	Concentrations of Selected Essential and Non-essential Elements in Blood of Harbor Seal (Phoca vitulina) Pups of the German North Sea	Biol. Trace Element Research	127	28-36	2009		Chemical Analysis
Lattuada, R.M.; Menezes, C.T.B; Pavei, P.T.; Peralba, M.C.R.; Dos Santos, J.H.Z.	Determination of metals by total reflection X-ray fluorescence and evaluation of toxicity of a river impacted by coal mining in the south of Brazil	Journal of Hazardous Materials	163	531-537	2009	Acid mine drainage; Coal mining effluent; Heavy metal; Total reflection X-ray	Chemical Analysis
A. Danel, A.; Sage, S.; Barnes, J.P.; Peters, D.; Spicer, R.; Bryant, R.; Newcomb, R.	Imaging of contamination on wafers using a scanning surface potential difference measurement technique	Microelectronic Engineering	86	186–191	2009	SPDI; Kelvin probe; Wafer contamination	Surfaces and Layers
Piacenti da Silva, M.; Zucchi, O.L.A.S.; Ribeiro-Silva, A.; Poletti, M.E.	Discriminant analysis of trace elements in normal, benign and malignant breast tissues measured by total reflection X-ray fluorescence	Spectrochim. Acta Part B	64	587- 592	2009	Breast cancer; trace elements; disriminant analysis	Chemical Analysis
Horntrich, C.; Meirer, F.; Streli, C.; Kregsamer, P.; Pepponi, G.; Zoeger, N.; Wobrauschek, P.	Influence of the sample morphology on total reflection X-ray fluorescence analysis	Powder diffraction	24	140 -144	2009	TXRF; absorption effects; quantification; wafer	Chemical Analysis
Borgese, L.; Zacco, A.; Bontempi, E.; Colombi, P.; Bertuzzi, P.; Ferretti, E.; S Tenini, S.; Depero, L.E.	Total reflection of x-ray fluorescence (TXRF): a mature technique for environmental chemical nanoscale metrology	Meas. Sci. Technol.	20	084027 (7pp)	2009	bioindicators, total reflection x-ray fluorescence, TXRF, environmental	Chemical Analysis
Meirer, F.; Pepponi, G.; Streli, C.; Wobrauschek, P.; Zoeger, N.	Grazing exit versus grazing incidence geometry for x-ray absorption near edge structure analysis of arsenic traces	J. Appl. Phys.	105	074906	2009	arsenic, XANES, X-ray absorption, X-ray fluorescence analysis, X-ray optics	Related Methods
Juvonen, R.; Parviainen, A.; Loukola-Ruskeeniemi, K.	Evaluation of a total reflection X-ray fluorescence spectrometer in the determination of arsenic and trace metals in environmental samples	Geochemistry: Exploration, Environment, Analysis	9	173-178	2009	TXRF; arsenic; trace metals; mine tailings; surface water; acid mine	Chemical Analysis

Autoren	Titel	Zeitschrift	Vol	Seiten	Jahr	Keywords	Gruppe
Misra, N.L.;Varga, I.; Dhara, S.; Aggarwal, S.K.	A novel approach for chlorine determination in acidic medium by total reflection x-ray fluorescence	X-Ray Spectrom.	38	182–185	2009	TXRF; chlorine; trace determinations; silver; cadmium	Chemical Analysis
Kallithrakas-Kontos, N.; Hatzistavros, V.	TXRF cation analysis by anionicmembrane collection	X-Ray Spectrom.	38	229–233	2009	PVC membrane; complexing; water	Chemical Analysis
Dhara, S.; Misra, N.L.; Aggarwal, S.K.; Venugopal, V.	Energy dispersive X-ray fluorescence determination of cadmium in uranium matrix using Cd Kα line excited by continuum	Spectrochim. Acta Part B	65	461–465	2010	EDXRF; Cadmium; Uranium; Nuclear reactor; Trace element	Related Methods
Ingerle, D.; Meirer, F.; Zoeger, N.; Pepponi, G.; Giubertoni, D.; Steinhauser, G.; Wobrauschek, P.; Streli, C.	A new spectrometer for grazing incidence X-ray fluorescence for the characterization of Arsenic implants and Hf based high-k layers	Spectrochim. Acta Part B	65	429–433	2010	GIXRF; Depth profiling; Thin layer characterization;	Principles and Instrumentation
Marguí, E.; Kregsamer, P.; Hidalgo, M.; Tapias, J.; Queralt, I.; Streli, C.	Analytical approaches for Hg determination in wastewater samples bymeans of total reflection X-ray fluorescence spectrometry	Talanta	82	821–827	2010	Hg; TXRF; Wastewater samples	Chemical Analysis
Bautista, P.; Mohedano, A.F.; Menéndez, N.; Casas, J.A.; Rodriguez, J.J.	Catalytic wet peroxide oxidation of cosmetic wastewaters with Fe-bearing catalysts	Catalysis Today	151	148-152	2010	AOPs; Catalytic wet peroxide oxidation; Cosmetic wastewaters;	Chemical Analysis
Espinoza-Quinones, F.R.; Modenes, A.N.; Palacio, S.M.; Szymanski, N.; Welter, R.A.; Rizzutto, M.A.; Borba, C.E.; Kroumov, A.D.	Evaluation of trace element levels in muscles, liver and gonad of fish species from Sao Francisco River of the Parana Brazilian state by using SR-TXRF technique	Appl. Radiat. Isot.	68	2202-2207	2010	Cr; fish; trace elements: SR-TXRF	Chemical Analysis
Chan, M.; Paley, L.; Yu, R.A., et al.	Method Development and Factorial Study Using Total Reflection X-Ray Fluorescence (TXRF) as a Tool to Distinguish Okanagan Grapes	Pharmaceutical Biology	48	28-28	2010		Principles and Instrumentation
Kunimura, S.; Kawai, J.	Polychromatic excitation improves detection limits in total reflection X-ray fluorescence analysis compared with monochromatic excitation	Analyst	135	1909–1911	2010	Monochromator; Detection limit	Principles and Instrumentation
Pinheiro, D.O.; Zucchi, T.D.; Zucchi, O.L.A.D.; Nascimento Filho, V.F.; Almeida, E.; Cônsoli, F.L.	Inorganic elements in the fat bodies of Diatraea saccharalis (Lepidoptera: Crambidae) larvae parasitized by Cotesia flavipes (Hymenoptera: Braconidae)	Comparative Biochemistry and Physiology	156	273–278	2010	Inorganic elements; X-ray fluorescence; Host–parasitoid interactions;	Chemical Analysis

Autoren	Titel	Zeitschrift	Vol	Seiten	Jahr	Keywords	Gruppe
Meirer, F.; Singh, A.; Pepponi, G.; Streli, C.; Homma, T.; Pianetta, P.	Synchrotron radiation-induced total reflection X-ray fluorescence analysis	TRAC-Trends in Analytical Chemistry	29	479-496	2010	Angle-dependent measurement; GI-XRF; Glancing incident; SR-TXRF;	Survey
Marguí, E.; Floor, G.H.; Hidalgo, M.; Kregsamer, P.; Román-Ross, G.; Streli, C.; Queralt, I.	Analytical Possibilities of Total Reflection X-ray Spectrometry (TXRF) for Trace Selenium Determination in Soils	Anal. Chem.	82	7744–7751	2010	Se; Soil; Detection limit	Chemical Analysis
Radoslavov, G.; Jordanova, R.; Teofanova, D.; Georgieva, K.; Hristov, P.; Salomone-Stagni, M.; Liebau, E.; Bankov, I.	A Novel Secretory Poly-Cysteine and Histidine-Tailed Metalloprotein (Ts-PCHTP) from Trichinella spiralis	PLoS ONE	5	e13343	2010	nematode; metalloproteine	Chemical Analysis
Janik, P.; Tylko, G.; Ostachowicz, B.; Turnau, K.	Elemental Composition of Physarum compressum Alb. et Schw. Sporocarps and Their Structures Cultivated on Rabbit Dung and Agar Substrates	Microscopy Research and Technique	73	1134–1142	2010	X-ray microanalysis; SEM; TXRF; slime mold cultivation; substrate	Chemical Analysis
Tsiouvaras, N.; Pena, M.A.; Fierro, J.L.G.; Pastor, E.; Martínez-Huerta, M.V.	The effect of the Mo precursor on the nanostructure and activity of PtRuMo electrocatalysts for proton exchange membrane fuel cells	Catalysis Today	158	12–21	2010	PEMFC; DMFC; Electrocatalysts; Anode; PtRuMo; DEMS	Chemical Analysis
Marguí, E.; Tapias, J.C.; Casas, A.; Hidalgo, M.; Queralt, I.	Analysis of inlet and outlet industrial wastewater effluents by means of benchtop total reflection X-ray fluorescence spectrometry	Chemosphere	80	263–270	2010	Waste waters; Heavy metals; Benchtop instrumentation	Chemical Analysis
Boman, J.; Wagner, A.; Gatari, M.J.	Trace elements in PM2.5 in Gothenburg, Sweden	Spectrochim. Acta Part B	65	478–482	2010	Carcinogenic; Respirable particles; Anthropogenic; Aerosol particles	Chemical Analysis
Yonehara, T.; Yamaguchi, M.; Tsuji, K.	X-ray fluorescence imaging with polycapillary X-ray optics	Spectrochim. Acta Part B	65	441-444	2010	X-ray fluorescence; Elemental imaging; Polycapillary X-ray optics;	Related Methods
Espinoza-Quinones, F.R.; Modenes, A.N.; Palacio, S.M.; Szymanski, N.; Welter, R.A.; Rizzutto, M.A.; Borba, C.E.; Kroumov, A.D.	Evaluation of trace element levels in muscles, liver and gonad of fish species from Sao Francisco River of the Parana Brazilian state by using SR-TXRF technique	Applied Radiation and Isotopes	68	2202–2207	2010	SR-TXRF technique Trace element Fish	Chemical analysis
Kayser, Y.; Banaś, D.; Cao, W.; Dousse, J.-Cl.; Hoszowska, J.; Jagodziński, P.; Kavčič, M.; Kubala-Kukuś, A.; Nowak, S.; Pajek, M.;	Depth profiles of Al impurities implanted in Si wafers determined by means of the high-resolution grazing emission X-ray fluorescence technique	Spectrochim. Acta Part B	65	445–449	2010	Grazing emission X-ray fluorescence (GEXRF); Depth profiling;	Related Methods

Autoren	Titel	Zeitschrift	Vol	Seiten	Jahr	Keywords	Gruppe
Sánchez, H.J.;Pérez, C.A.	Study of copper surface oxidation by grazing angle X-ray excitation	Spectrochim. Acta Part B	65	466–470	2010	Depth profiling; Stratified media	Surfaces and Layers
Sánchez, H.J.; Perez, R.D.; Carvalho, M.L.; Rubio, M.	Total reflection X-ray fluorescence analysis using polycapillaries. A comparison with conventional setups	Nucl. Instrum. Meth. B	268	3478–3481	2010	TXRF; Polycapillary; Trace analysis	Principles and Instrumentation
Borgese, L.; Zacco, A.; Bontempi, E.; Pellegatta, M.; Vigna, L.; Patrini, L.; Riboldi, L.; Rubino, F.M.; Depero, L.E.	Use of total reflection X-ray fluorescence (TXRF) for the evaluation of heavy metal poisoning due to the improper use of a traditional ayurvedic drug	J. Pharm. Biomed. Anal.	52	787-790	2010	heavy metal; hair; ayurvedic remedy	Chemical Analysis
Tiwari, M.K.; Sawhney, K.J.S.; Lodha, G.S.	Multilayer mirror as a substrate for total reflection X-ray fluorescence spectrometry	Spectrochim. Acta Part B	65	434–440	2010	X-ray fluorescence; X-ray standing wave; Particulate matter and trace	Principles and Instrumentation
Amberger, M.A.; Höltig,M.; Broekaert, J.A.C.	Direct determination of trace elements in boron nitride powders by slurry sampling total reflection X-ray fluorescence spectrometry	Spectrochim. Acta Part B	65	152–157	2010	Boron nitride; Total reflection X-ray fluorescence spectrometry; Slurry	Chemical Analysis
Espinoza-Quinones, F.R.; Palacio, S.M.; Modenes, A.N.; Szymanski, N.; Zacarkim, C.E.; Zenatti, D.C.; Fornari, M.M.T.; Rizzutto, M.A.;Tabacniks, M.;	Water quality assessment of Toledo River and determination of metal concentrations by using SR-TXRF technique	J. Radioanal. Nucl. Chem.	283	465-470	2010	Trace elements; SR-TXRF technique; Physical-chemical parameters;	Chemical Analysis
Dhara, S.; Misra, N.L.; Maind, S.D.; Kumar, S.A.; Chattopadhyay, N.; Aggarwal, S.K.	Forensic application of total reflection X-ray fluorescence spectrometry for elemental characterization of ink samples	Spectrochim. Acta Part B	65	167-170	2010	TXRF; ICP-MS; Forensic; Ink; Rare earths	Chemical Analysis
Tarsoly, G.; Óvári, M.; Záray, Gy.	Determination of fluorine by total reflection X-ray fluorescence spectrometry	Spectrochim. Acta Part B	65	287–290	2010	Fluorine; Detection limit; Linearity range; Interference effects	Chemical Analysis
Bontempi, E.; Zacco, A.; Benedetti, D.; Borgese, L.; Colombi, P.; Stosnach, H.; Finzi, G.; Apostoli, P.; Buttini, P.; Depero, L.E.	Total reflection X-ray fluorescence (TXRF) for direct analysis of aerosol particle samples	Environmental Technology	31	467-477	2010	heavy metals; air particulate matters; nanomaterials; direct analysis	Chemical Analysis
Kropf, U.; Korošec, M.; Bertoncelj, J.; Ogrinc, N.; Nečemer, M.; Kump, P.; Golob, T.	Determination of the geographical origin of Slovenian black locust, lime and chestnut honey	Food Chemistry	121	839–846	2010	Geographical origin; Elements; IRMS; d13C; d15N;	Chemical Analysis

Autoren	Titel	Zeitschrift	Vol	Seiten	Jahr	Keywords	Gruppe
Sekowski, M.; Burenkov, A.; Ryssel, H.	2D Angular distributions of ion sputtered germanium atoms under grazing incidence	Microelectronic Engineering	87	1497–1499	2010	Ion sputtering; Angular distributions; Germanium;	Related Methods
Fernández-Ruiz, R.; Andrés, R.; de Jesús, E.; Terreros, P.	Optimization of the quantitative direct solid total-reflection X-ray fluorescence analysis of glass microspheres functionalized with Zr organometallic compounds	Spectrochim. Acta Part B	65	450–456	2010	Uncertainty; Homogeneity; Direct solid analysis; Nanoparticle	Chemical Analysis
Barros, H.; Marcó Parra, L.-M.; Bennun, L.; Greaves, E.D.	Determination of arsenic in water samples by Total Reflection X-Ray Fluorescence using pre-concentration with alumina	Spectrochim. Acta Part B	65	489-492	2010	Arsenic; Alumina; Toxicity; Public health problem	Chemical Analysis
Tejeda, S.; Zarazúa, G.; Ávila-Pérez, P.; Carapia-Morales, L.; Martínez, T.	Total reflection X-ray fluorescence spectrometric determination of elements in water hyacinth from the Lerma River	Spectrochim. Acta Part B	65	483–488	2010	Water pollution; Metals; Water hyacinth	Chemical Analysis
Martinez, T.; Lartigue, J.; Zarazua, G.; Avila-Perez, P.; Navarrete, M.; Tejeda, S.	Total reflection X-ray fluorescence analysis of trace-elements in candies marketed in Mexico	Spectrochim. Acta Part B	65	499-503	2010	Candies Trace elements	Chemical Analysis
Pessanha, S.; Carvalho, M.L.; Becker, M.; von Bohlen, A.	Quantitative determination on heavy metals in different stages of wine production by Total Reflection X-ray Fluorescence and Energy Dispersive X-ray Fluorescence: Comparison on	Spectrochim. Acta Part B	65	504-507	2010	Wine; EDXRF; copper	Chemical Analysis
von Bohlen, A.; Brücher, M.; Holland, B.; Wagner, R.; Hergenröder, R.	X-ray standing waves and scanning electron microscopy — Energy dispersive X-ray emission spectroscopy study of gold nanoparticles	Spectrochim. Acta Part B	65		2010	Nanoparticles; X-ray interference; XSW; Synchrotron radiation	Principles and Instrumentation
Wagner, A.; Mages, M.	Total-Reflection X-ray fluorescence analysis of elements in size-fractionated particulate matter sampled on polycarbonate filters — Composition and sources of aerosol particles in Göteborg,	Spectrochim. Acta Part B	65	471–477	2010	Elemental analysis; Aerosol particles; Cold plasma ashing (CPA);	Chemical Analysis
Magalhães, T.; Carvalho, M.L.; von Bohlen, A.; Becker, M.	Study on trace elements behaviour in cancerous and healthy tissues of colon, breast and stomach: TXRF applications	Spectrochim. Acta Part B	65	493-498	2010	Breast cancer; Stomach cancer; Colon cancer; Trace elements	Chemical Analysis
Bennun, L.; Sanhueza, V.	A Procedure for the Improvement in the Determination of a TXRF Spectrometer Sensitivity Curve	Anal. Sci.	26	331-335	2010		Principles and Instrumentation

Autoren	Titel	Zeitschrift	Vol	Seiten	Jahr	Keywords	Gruppe
Misra, N.L.; Dhara, S.; Óvári, M.; Záray, Gy.; Aggarwal, S.K.; Varga, I.	Determination of low atomic number elements at trace levels in uranium matrix using vacuum chamber total reflection X-ray fluorescence	Spectrochim. Acta Part B	65	457–460	2010	Low Z elements; Uranium; Vacuum chamber total reflection X-ray	Chemical Analysis
Sabatini, S.E.; Rocchetta, I.; Nahabedian, D.E.; Luquet, C.M.; Eppis, M.R.; Bianchi, L.; Rios de Molina, M.D.C.	Oxidative stress and histological alterations produced by dietary copper in the fresh water bivalve Diplodon chilensis	Comparative biochemistry and physiology. Toxicology &	154	391-398	2011		Chemical analysis
Telgmann, L.; Holtkamp, M.; Künnemeyer, J.; Gelhard, C.; Hartmann, M.; Klose, A.; Sperling, M.; Karst, U.	Simple and rapid quantification of gadolinium in urine and blood plasma samples by means of total reflection X-ray fluorescence (TXRF)	Metallomics	3	1035-1040	2011	Gd, MRI patients; blood; urine	Chemical analysis
Kühn, A.; Scharf, O.; Ordavo, I.; Riesemeier, H.; Reinholz, U.; Radtke, M.; Berger, A.; Ostermann, M.; Panne, U.	Pushing the limits for fast spatially resolved elemental distribution patterns	J. Anal. At. Spectrom.	26	1986–1989	2011	polycapillary optics; pn-CCD chip; Synchrotron;	Principles and Instrumentation
Alov, N.V.	Total Reflection X-ray Fluorescence Analysis: Physical Foundations and Analytical Application (A Review)	INORGANIC MATERIALS	47	1487-1499	2011	chemical analysis; thin-layer analyis; trace-elements; surface-analysis;	Review
Kunimura, S.; Ohmori, H.	A portable total reflection X-ray fluorescence spectrometer with a diamond-like carbon coated X-ray reflector	The Analyst	137	312-314	2011	diamond-like carbon; sample holder; portable TXRF;	Chemical analysis
Sandu, I.C.A.; de Sa, M.H.; Pereira, M.C.	Ancient 'gilded' art objects from European cultural heritage: a review on different scales of characterization	Surf. Interface Anal.	43	1134–1151	2011	gilded surface; art object; EDXRF	Review
Wannaz, E.D.; Carreras, H.A.; Abril, G.A.; Pignata, M.L.	Maximum values of Ni2+, Cu2+, Pb2+ and Zn2+ in the biomonitor Tillandsia capillaris (Bromeliaceae): Relationship with cell membrane	Environmental and Experimental Botany	74	296–301	2011	Epiphytic vascular; Metal accumulation; Lipid peroxidation; MDA	Chemical analysis
Polgári, Z.; Szoboszlai, N.; Óvári, M.; Záray, G.	Possibilities and limitations of the total reflection X-ray fluorescence spectrometry for the determination of low Z elements in biological samples	Microchemical Journal	99	339–343	2011	TXRF; Low Z elements; Microwave assisted digestion; Direct	Chemical analysis
Delabie, A.; Sioncke, S.; Rip, J.; Van Elshocht, S.; Caymax, M.; Pourtois, G.; Pierloot, K.	Mechanisms for the Trimethylaluminum Reaction in Aluminum Oxide Atomic Layer Deposition on Sulfur Passivated Germanium	J. Phys. Chem. C	115	17523–17532	2011	Atomic Layer Depostion; S passivated Ge; TMA;	Surfaces and Layers

Autoren	Titel	Zeitschrift	Vol	Seiten	Jahr	Keywords	Gruppe
Sartore, L.; Barbaglio, M.; Borgese, L.; Bontempi, E.	Polymer-grafted QCM chemical sensor and application to heavy metal ions real time detection	Sensors and Actuators B	155	538–544	2011	Polymer grafted quartz crystal; microbalance; Multifunctional	Chemical analysis
Camejo, M.I.; Abdala, L.; Vivas-Acevedo, G.; Lozano-Hernández, R.; Angeli-Greaves, M.; Greaves, E.D.	Selenium, Copper and Zinc in Seminal Plasma of Men with Varicocele, Relationship with Seminal Parameters	Biol. Trace Elem. Res.	143	1247-1254	2011	Varicocele; Selenium; Copper; Zinc; Sperm concentration;	Chemical analysis
Espinoza-Quiñones, F.R.; Módenes, A.N.; Palácio, S.M.; Lorenz, E.K.; Oliveira, A.P.	Analysis of metal concentration levels in water, sediment and fish tissues from Toledo municipal lake by applying SR-TXRF technique	Water Science & Technology	63	1506–1512	2011	fish tissue; metal concentration; sediment; SR-TXRF technique; water	Chemical analysis
Carneiro, C.D.; Marsico, E.T.; de Jesus, E.F.O.; Ribeiro, R.D.R.; Barbosa, R.D.	Trace elements in fish and oysters from Sepetiba Bay (Rio de Janeiro - Brazil) determined by total reflection X-ray fluorescence using synchrotron radiation	Chemistry and Ecology	27	1-8	2011	trace elements; fish; oysters; heavy metals; contamination;	Chemical analysis
Marcó Parra, L.M.	Determination of total As in onion plants growing in contaminated substrates by total reflection X-ray fluorescence	Journal of Radioanalytical and Nuclear Chemistry	287	479-484	2011	Onion arsenic; TXRF; HGAAS	Chemical Analysis
Tavares, G.A.; Almeida, E.; de Oliveira, J.G.G.; Bendassolli, J.A.; Nascimento Filho, V.F.	Elemental content in deionized water by total-reflection X-ray fluorescence spectrometry	Journal of Radioanalytical and Nuclear Chemistry	287	377-381	2011	TXRF; Deionized water; Water quality	Chemical analysis
Fernández-Ruiz, R.; Malki, M.; Morato, A.I.; Marin, I.	Study of bioaccumulation kinetics of chromium(VI) in Acinetobacter beijerinckii type bacterium by Total Reflection X-Ray Fluorescence	J. Anal. At. Spectrom.	26	511–516	2011	Chromium(VI); Acinetobacter beijerincki; bioaccumulation;	Chemical analysis
Cinosi, A.; Andriollo, N.; Pepponi, G.; Monticelli, D.	A novel total reflection X-ray fluorescence procedure for the direct determination of trace elements in petrochemical products	Anal. Bioanal. Chem.	399	927–933	2011	Inductively coupled plasma optical emission pectroscopy; Trace	Chemical analysis
Groh, L.; Hums, C.; Bläsing, J.; Krost, A.; Dadgar, A.	Characterization of AlGaInN layers using X-ray diffraction and fluorescence	Phys. Status Solidi B	248	622–626	2011	AlGaInN; quaternary layers; X-ray diffraction; X-ray fluorescence	Chemical analysis
Borgese, L.; Zacco, A.; Pal, S.; Bontempi, E.; Lucchini, R.; Zimmerman, N.; Depero, L.E.	A new non-destructive method for chemical analysis of particulate matter filters: The case of manganese air pollution in Vallecamonica (Italy)	Talanta	84	192–198	2011	Air particulate matter; Filter; Manganese	Chemical analysis

Autoren	Titel	Zeitschrift	Vol	Seiten	Jahr	Keywords	Gruppe
Koh, S.F.; Lim, W.L.; Tou, T.Y.	Enhanced Detection of Copper Impurity in Silicon Wafer by Dynamic Secondary Ion Mass Spectrometry	Electrochem. Solid-State Lett.	14	H110-H113	2011	copper, diffusion, elemental semiconductors, impurities,	Chemical analysis
Kadenkin, A.; Amberger, M.; Fittschen, U.E.A.; Broekaert, J.A.C.	Micro-homogeneity studies of boron carbide powders	Microchim Acta	173	183–188	2011	Boron carbide; Micro-homogeneity; ICP–OES; Impaction	Chemical analysis
Polgári, Zs.; Meirer, F.; Sasamori, S.; Ingerle, D.; Pepponi, G.; Streli, C.; Rickers, K.; Réti, A.; Budai, B.; Szoboszlai, N.; Záray, G.	Iron speciation in human cancer cells by K-edge total reflection X-ray fluorescence–X-ray absorption near edge structure analysis	Spectrochimica Acta Part B	66	274–279	2011	XANES TXRF; Iron; Cancer cell	Related Methods
Horntrich, C.; Smolek, S.; Maderitsch, A.; Simon, R.; Kregsamer, P.; Streli, C.	Investigation of element distribution and homogeneity of TXRF samples using SR-micro-XRF to validate the use of an internal standard and improve external standard quantification	Anal. Bioanal. Chem	400	2649-2654	2011	Internal standard; External standard; SR-mu-XRF; Homogeneity; wafer	Chemical analysis
Ferlito, E.P.; Alnabulsi, S.; Mello, D.	A different approach in sample preparation method for metallic contamination study by ToF-SIMS and TXRF	Appl. Surf. Sci.	257	9925–9930	2011	ToF-SIMS; Cobalt contamination	Chemical analysis
Hatzistavros, V.S.; Kallithrakas-Kontos, N.G.	Determination of Trace Perchlorate Concentrations by Anion-Selective Membranes and Total Reflection X-ray	Anal. Chem.	83	3386–3391	2011	perchlorate; anion-selective membranes; drinking water	Chemical analysis
Takahashi, M.; Higashi, Y.; Ozaki, S.; Kobayashi, H.	Chemical States of Copper Contaminants on SiO2 Surfaces and Their Removal by ppm-order HCN Aqueous Solutions	J. Electrochem. Soc.	158	H825-H829	2011	EXAFS, fluorescence, silicon compounds, surface cleaning, surface	Chemical Analysis
Polgári, Z.; Ajtony, Z.; Kregsamer, P.; Streli, C.; Mihucz, V.G.; Réti, A.; Budai, B.; Kralovánszky, J.; Szoboszlai N.; Záray, G.	Microanalytical method development for Fe, Cu and Zn determination in colorectal cancer cells	Talanta	85	1959–1965	2011	Iron, Copper; Zinc; HT-29; GF-AAS	Chemical analysis
Galstyan, V.; Comini, E.; Faglia, G.; Vomiero, A.; Borgese, L.; Bontempi, E.; Sberveglieri, G.	Fabrication and investigation of gas sensing properties of Nb-doped TiO(2) nanotubular arrays.	Nanotechnology	23	235706	2012	Titania; GIXRD; gas sensing; nanotubes	Chemical Analysis
Cataldo, F.	Multielement analysis of a municipal landfill leachate with total reflection X-ray fluorescence (TXRF). A comparison with ICP-OES analytical results	J. Radioanal. Nucl. Chem.	126	293-119	2012	Landfill leachate; groundwater; ICP-OES; Multielement analysis	Chemical Analysis

Autoren	Titel	Zeitschrift	Vol	Seiten	Jahr	Keywords	Gruppe
Hoffmann, P.S.; Baake, O.; Kosinova, M.L.; Beckhoff, B.; Klein, A.; Pollakowski, B.; Trunova, V.A.; Sulyaeva, V.S.; Kuznetsov, F.A.;	Chemical bonds and elemental compositions of BCxNy layers produced by chemical vapor deposition with trimethylamine borane, triethylamine borane, or trimethylborazine	X-Ray Spectrom.	41	240–246	2012	XPS; SR-TXRF-NEXAFS; SEM-EDX; CVD; thin layers	Chemical Analysis
Justen, G.C.; Espinoza-Quiñones, F.R.; Módenes, A.N.; Bergamasco, R.	Elements concentration analysis in groundwater from the North Serra Geral aquifer in Santa Helena-Brazil using SR-TXRF spectrometer	Water Science & Technology	66	1029–1035	2012	Brazilian aquifer; cluster analysis; groundwater; major elements; SR-TXRF	Chemical Analysis
Antoine, J.M.R.; Hoo Fung, L.A.; Grant, C.N.; Dennis, H.T.; Lalor, G.C.	Dietary intake of minerals and trace elements in rice on the Jamaican market	Journal of Food Composition and Analysis	26	111–121	2012	Rice; Trace elements; Dietary intake; Food analysis; Jamaica;	Chemical Analysis
Castell, R.; Greaves, E.D.; Abdala, L.; Barros, H.	TXRF and ICP-OES analysis of liquid-phase laser-ablated (LP-LA) nanoparticles of cryolite-alumina solutions	Appl. Phys. B	109	47–53	2012	Plasma-mass spectro-metry; Diamond nanocrystals;	Chemical Analysis
Imashuku, S.; Tee, D.P.; Kawai, J.	Improvement of total reflection X-ray fluorescence spectrometer sensitivity by flowing nitrogen gas	Spectrochimica Acta Part B	73	75–78	2012	Nitrogen gas Ar Kα line; Cd Lα line	Principles and Instrumentation
Holtkamp, M.; Wehe, C.A.; Blaske, F.; Holtschulte, C.; Sperling, M.; Karst, U.	Nitrogen purged TXRF for the quantification of silver and palladium	J. Anal. At. Spectrom.	27	1799–1802	2012	X-Ray fluorescence; Platinum-group elemennts; Risk-assessment; Blood-	Principles and Instrumentation
Marks, M.A.W.; Wenzel, T.; Martin J.; Whitehouse, M.J.; Loose, M.; Zack,T.; Barth, M.; Worgard, L.; Krasz, V.; Eby, G.N.; Stosnach, H.; Gregor Markl, G.	The volatile inventory (F, Cl, Br, S, C) of magmatic apatite: An integrated analytical approach	Chemical Geology	291	241–255	2012	Apatite; Halogens; Bromine; SIMS; TXRF	Chemical Analysis
Guimaraes D.; Carvalho M.L.; Becker M.; von Bohlen, A.; Geraldes, V.; Rocha, I.; Santos, J.P.	Lead concentration in feces and urine of exposed rats by x-ray fluorescence and electrothermal atomic absorption spectrometry	X-Ray Spectrom.	41	80-86	2012	lead; urine; feces; rats; AAS	Chemical Analysis
Schmeling, M.; Burnett, D.S.; Jurewicz, A.J.G.; Veryovkin, I.V.	Steps toward accurate large-area analyses of Genesis solar wind samples: evaluation of surface cleaning methods using total reflection X-ray fluorescence spectrometry	Powder Diffraction	27	75-78	2012	genesis solar samples	Chemical Analysis
Horntrich, C.; Kregsamer, P.; Prost, J.; Stadlbauer, F.; Wobrauschek, P.; Streli, C.	Production of the ideal sample shape for Total Reflection X-ray Fluorescence analysis	Spectrochimica Acta Part B	73	31-34	2012	Absorption; Saturation effect; External standard; Wafers	Chemical Analysis

Autoren	Titel	Zeitschrift	Vol	Seiten	Jahr	Keywords	Gruppe
Savoly, Z.; Nagy, P.; Havancsak, K.; Zaray, G.	Microanalytical investigation of nematodes	Microchemical Journal	105	83-87	2012	ductively coupled plasma mass spectrometry; Elemental	Chemical Analysis
Kunimura, S.; Ohmori, H.	A portable total reflection X-ray fluorescence spectrometer with a diamond-like carbon coated X-ray reflector	The Analyst	137	312-314	2012		Principles and Instrumentation
Cinosi, A.; Andriollo, N.; Tibaldi, F.; Monticelli, D.	Atmospheric pressure vapour phase decomposition:A proof of principle	Talanta	101	148-150	2012	Trace elements; Vapour phase decomposition; Heavy	Chemical Analysis
Antosz, F.J.; Xiang, Y.; Diaz, A.R.; Jensen, A.J.	The use of total reflectance X-ray fluorescence (TXRF) for the determination of metals in the pharmaceutical industry	Journal of Pharmaceutical and Biomedical Analysis	62	17–22	2012	Pharmaceutical; Active pharmaceutical ingredient (API);	Chemical Analysis
Domingo, I.; Garcia-Borja, P.; Roldan, C.	Identification, processing and use of red pigments (hematite and cinnabar) in the Valencian early Neolithic (Spain)	Archaeometry	54	868-892	2012	SEM-EDX; XRD; FTIR; GC; EDXRF; Early Neolithic; Spain; Hematite;	Chemical Analysis
Kijewski, H.; Beck, J.; Reus, U.	Krankheit und Tod des Violin-Virtuosen Nicolo Paganini--Interpretation auf Basis neuer Haaruntersuchungen.	Archiv fur Kriminologie	229	11-24	2012	mercury, ICP-MS, hair	Chemical Analysis
Shaw, B.J.; Semin, D.J.; Rider, M.E.; Beebe, M.R.	Applicability of total reflection X-ray fluorescence (TXRF) as a screening platform for pharmaceutical inorganic impurity analysis	Journal of Pharmaceutical and Biomedical Analysis	63	151–159	2012	Inductively coupled plasma-mass spectrometry (ICP-MS); Trace metal	Chemical Analysis
Horntrich, C.; Kregsamer, P.; Smolek, S.; Maderitsch, A.; Wobrauschek, P.; Simon, R.; Nutsch, A.; Knoerr, M.; Streli, C.	Influence of the excitation energy on absorption effects in Total Reflection X-ray Fluorescence analysis	J. Anal. At. Spectrom.	27	340-345	2012		Chemical Analysis
Chen, W.; Han, X.F.; Lu, J.G.; Liu, W.W.; Tian, Y.H.; Wu, X.R.	Determination of 16 Elements in the Different Pine Pollen by TXRF	Spectroscopy and Spectral Analysis	32	2250-2253	2012	Pine pollen; Element analysis; Microwave digestion	Chemical Analysis
Meyer, A.; Grotefend, S.; Gross, A.; Wätzig, H.; Ott; I.	Total reflection X-ray fluorescence spectrometry as a tool for the quantification of gold and platinum metallodrugs: Determination of recovery rates and precision	Journal of Pharmaceutical and Biomedical Analysis	70	713– 717	2012	Metallodrugs; Precision; Recovery; Au; Pt	Chemical Analysis

Autoren	Titel	Zeitschrift	Vol	Seiten	Jahr	Keywords	Gruppe
de Almeida, E.; do Nascimento Filho, V.F.; Menegário, A.A.	Paper-based diffusive gradients in thin films technique coupled to energy dispersive X-ray fluorescence spectrometry for the determination of labile Mn, Co, Ni, Cu, Zn and Pb in river water	Spectrochim.Acta Part B	71-72	70–74	2012	fresh water; paper-based DGT; EDXRF; SR-TXRF	Chemical Analysis
Bat, K.B.; Vidrih, R.; Necemer, M.; Vodopivec, B.M.; Mulic, I.; Kump, P.; Ogrinc, N.	Characterization of Slovenian apples with respect to their botanical and geographical origin and agricultural production practice	Food Technol. Biotechnol.	50	107–116	2012	apples; stable isotopes; botanical origin; eographical origin;	Chemical Analysis
Borgese, L.; Salmistraro, M.; Gianoncelli, A.; Zacco, A.; Lucchini, R.; Zimmerman, N.; Pisani, L. Siviero, G.; Depero, L.E.;	Airborne particulate matter (PM) filter analysis and modeling by total reflection X-ray fluorescence (TXRF) and X-ray standing wave (XSW)	Talanta	89	99–104	2012	XSW; Airbone particulate matter (PM) filter; Chemical analysis	Chemical Analysis
Silva, N.; Senanayake, H.; Waduge, V.	Elevated levels of whole blood nickel in a group of Sri Lankan women with endometriosis: a case control study	Bio Med Central	6	13	2013	Endometriosis; Metalloestrogens; Nickel	Chemical Analysis
Sparks, C.M.; Fittschen, U.E.A.; Havrilla, G.J.	Investigation of total reflection X-ray fluorescence calibration with picoliter deposition arrays	Microelectronic Engineering	102	98-102	2013		Chemical Analysis